Embedded LPDDR3 SDRAM

EDF8164A3PK, EDFA164A2PK

Features

- Ultra-low-voltage core and I/O power supplies
- Frequency range
  - 800/933 MHz (data rate: 1600/1866 Mb/s/pin)
- 8*n* prefetch DDR architecture
- 8 internal banks for concurrent operation
- Multiplexed, double data rate, command/address inputs; commands entered on each CK_t/CK_c edge
- Bidirectional/differential data strobe per byte of data (DQS_t/DQS_c)
- Programmable READ and WRITE latencies (RL/WL)
- Burst length: 8
- Per-bank refresh for concurrent operation
- Auto temperature-compensated self refresh (ATCSR) by built-in temperature sensor
- Partial-array self refresh (PASR)
- Deep power-down mode (DPD)
- Selectable output drive strength (DS)
- Clock-stop capability
- Lead-free (RoHS-compliant) and halogen-free packaging

Options

- $V_{DD1}/V_{DD2}/V_{DDCA}/V_{DDQ}$: 1.8V/1.2V/1.2V/1.2V
- Array configuration
  - 128 Meg x 64 (DDP)
  - 256 Meg x 64 (QDP)
- Packaging
  - 12mm x 12mm, 216-ball PoP FBGA package
- Operating temperature range
  - From –30°C to +85°C

Table 1: Configuration Addressing

Architecture	128 Meg x 64	256 Meg x 64
Density per package	8Gb	16Gb
Die per package	2	4
Ranks (CS_n) per channel	1	2
Die per channel	1	2
Configuration	16 Meg x 32 x 8 banks x 2 channel	16 Meg x 32 x 8 banks x 2 rank x 2 channel
Row addressing	16K A[13:0]	16K A[13:0]
Column addressing (same for each die)	1K A[9:0]	1K A[9:0]

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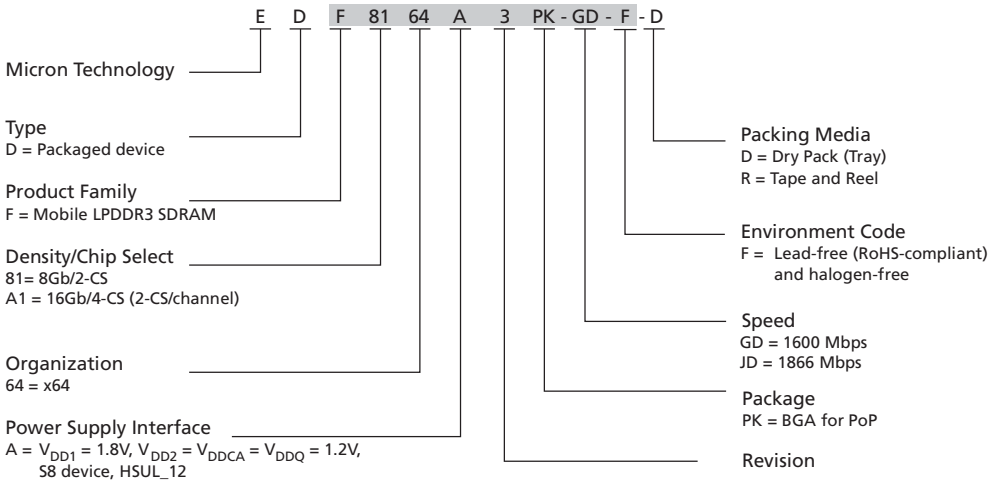
Table 2: Key Timing Parameters

Speed Grade	Clock Rate (MHz)	Data Rate (Mb/s/pin)	WRITE Latency (Set A/B)	READ Latency
GD	800	1600	6/9	12
JD	933	1866	8/11	14

Table 3: Part Number Description

Part Number	Total Density	Configuration	Ranks	Channels	Package Size	Ball Pitch
EDF8164A3PK-GD-F-D EDF8164A3PK-GD-F-R EDF8164A3PK-JD-F-D EDF8164A3PK-JD-F-R	8Gb	128 Meg x 64	1	2	12mm x 12mm (0.70mm MAX height)	0.40mm
EDFA164A2PK-GD-F-D EDFA164A2PK-GD-F-R EDFA164A2PK-JD-F-D EDFA164A2PK-JD-F-R	16Gb	256 Meg x 64	2	2	12mm x 12mm (0.80mm MAX height)	0.40mm

Figure 1: Marketing Part Number Chart



Note: 1. The characters highlighted in gray indicate the physical part marking found on the device.

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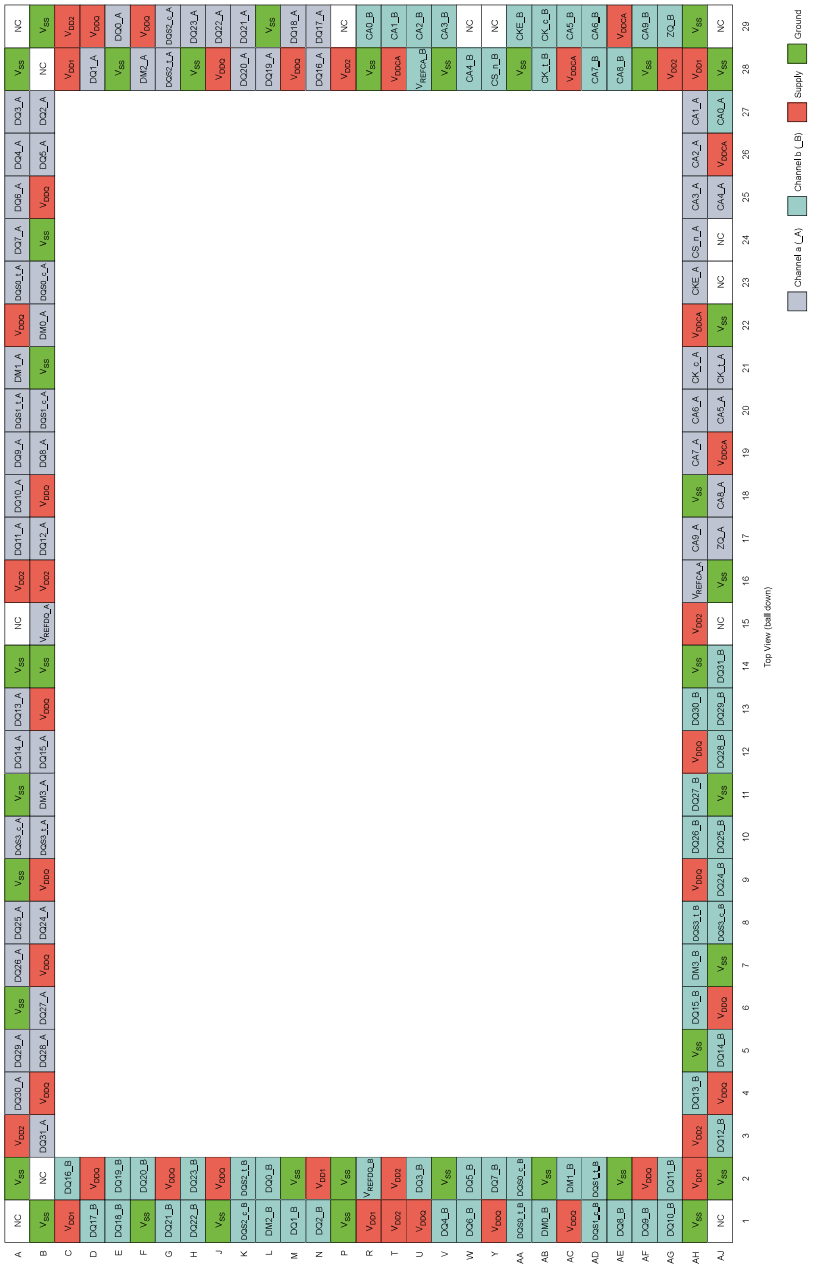
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Ball Assignments

Figure 2: 216-Ball FBGA – 2 x 4Gb Die



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Ball Assignments

Figure 3: 216-Ball FBGA – 4 x 4Gb Die



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Ball Descriptions

The ball/pad description table below is a comprehensive list of signals for the device family. All signals listed may not be supported on this device. See ball assignments for information specific to this device.

Table 4: Ball/Pad Descriptions

Symbol	Type	Description
CA[9:0]_A, CA[9:0]_B	Input	**Command/address inputs:** Provide the command and address inputs according to the command truth table. A separate CA[9:0] is provided for each channel (A and B).
CK_t_B, CK_t_A CK_c_B, CK_c_A	Input	**Clock:** Differential clock inputs. All CA inputs are sampled on both rising and falling edges of CK. CS and CKE inputs are sampled at the rising edge of CK. AC timings are referenced to clock. A separate CK_t/CK_c is provided for each channel (A and B).
CKE[1:0]_A, CKE[1:0]_B	Input	**Clock enable:** CKE HIGH activates and CKE LOW deactivates the internal clock signals, input buffers, and output drivers. Power-saving modes are entered and exited via CKE transitions. CKE is considered part of the command code. CKE is sampled on the rising edge of CK. A separate CKE is provided for each channel (A and B).
CS[1:0]_n_A, CS[1:0]_n_B	Input	**Chip select:** Considered part of the command code and is sampled on the rising edge of CK. A separate CS_n is provided for each channel (A and B).
DM[3:0]_B, DM[3:0]_A	Input	**Input data mask:** Input mask signal for write data. Although DM balls are input-only, the DM loading is designed to match that of DQ and DQS balls. DM[3:0] is DM for each of the four data bytes, respectively. A separate DM[3:0] is provided for each channel (A and B).
ODT_B, ODT_A	Input	**On-die termination:** Enables and disables termination on the DRAM DQ bus according to the specified mode register settings. For packages that do not support ODT, the ODT signal may be grounded internally. A separate ODT provided for each channel (A and B).
DQ[31:0]_B, DQ[31:0]_A	I/O	**Data input/output:** Bidirectional data bus. A separate DQ[11:0] is provided for each channel (A and B).
DQS[3:0]_t_B, DQS[3:0]_t_A, DQS[3:0]_c_B, DQS[3:0]_c_A	I/O	**Data strobe:** Bidirectional (used for read and write data) and complementary (DQS_t and DQS_c). It is edge-aligned output with read data and centered input with write data. DQS[3:0]_t/DQS[3:0]_c is DQS for each of the four data bytes, respectively. A separate DQS[3:0]_t and DQS[3:0]_c is provided for each channel (A and B).
V_{DDQ}	Supply	**DQ power supply:** Isolated on the die for improved noise immunity.
V_{SSQ}	Supply	**DQ ground:** Isolated on the die for improved noise immunity.
V_{DDCA}	Supply	**Command/address power supply:** Command/address power supply.
V_{SSCA}	Supply	**Command/address ground:** Isolated on the die for improved noise immunity.
V_{DD1}	Supply	**Core power:** Supply 1.
V_{DD2}	Supply	**Core power:** Supply 2.
V_{SS}	Supply	**Common ground.**
V_{REFCA}_B, V_{REFCA}_A V_{REFDQ}_B, V_{REFDQ}_A	Supply	**Reference voltage:** V_{REFCA} is reference for command/address input buffers, V_{REFDQ} is reference for DQ input buffers. A separate V_{REFCA} and V_{REFDQ} provided for each channel (A and B).
ZQ_B, ZQ_A	Reference	**External reference ball for output drive calibration:** This ball is tied to an external 240Ω resistor (RZQ), which is tied to V_{SSQ}. A separate ZQ is provided for each channel (A and B).

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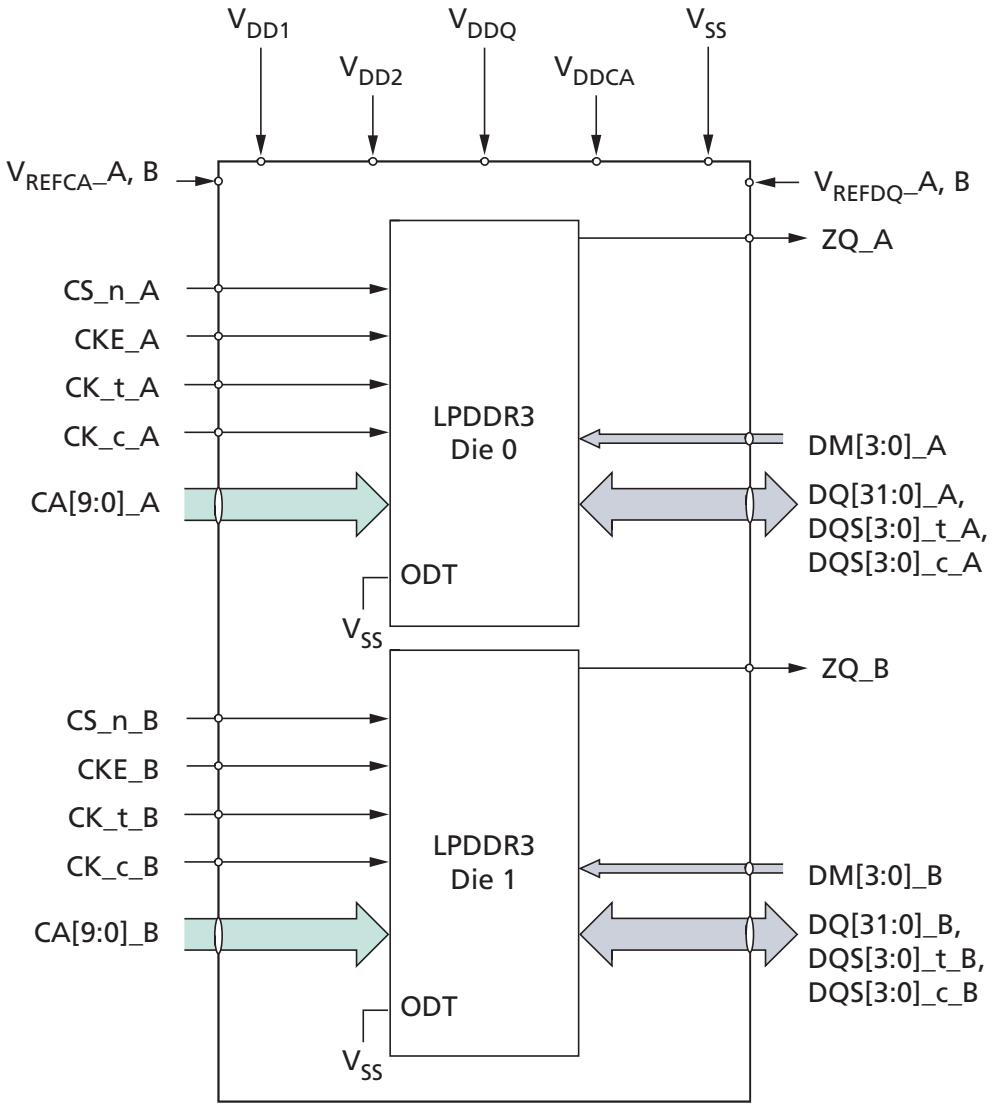
Table 4: Ball/Pad Descriptions (Continued)

Symbol	Type	Description
DNU	–	**Do not use:** Must be grounded or left floating.
NC	–	**No connect:** Not internally connected.
(NC)	–	**No connect:** Balls indicated as (NC) are no connects; however, they could be connected together internally.

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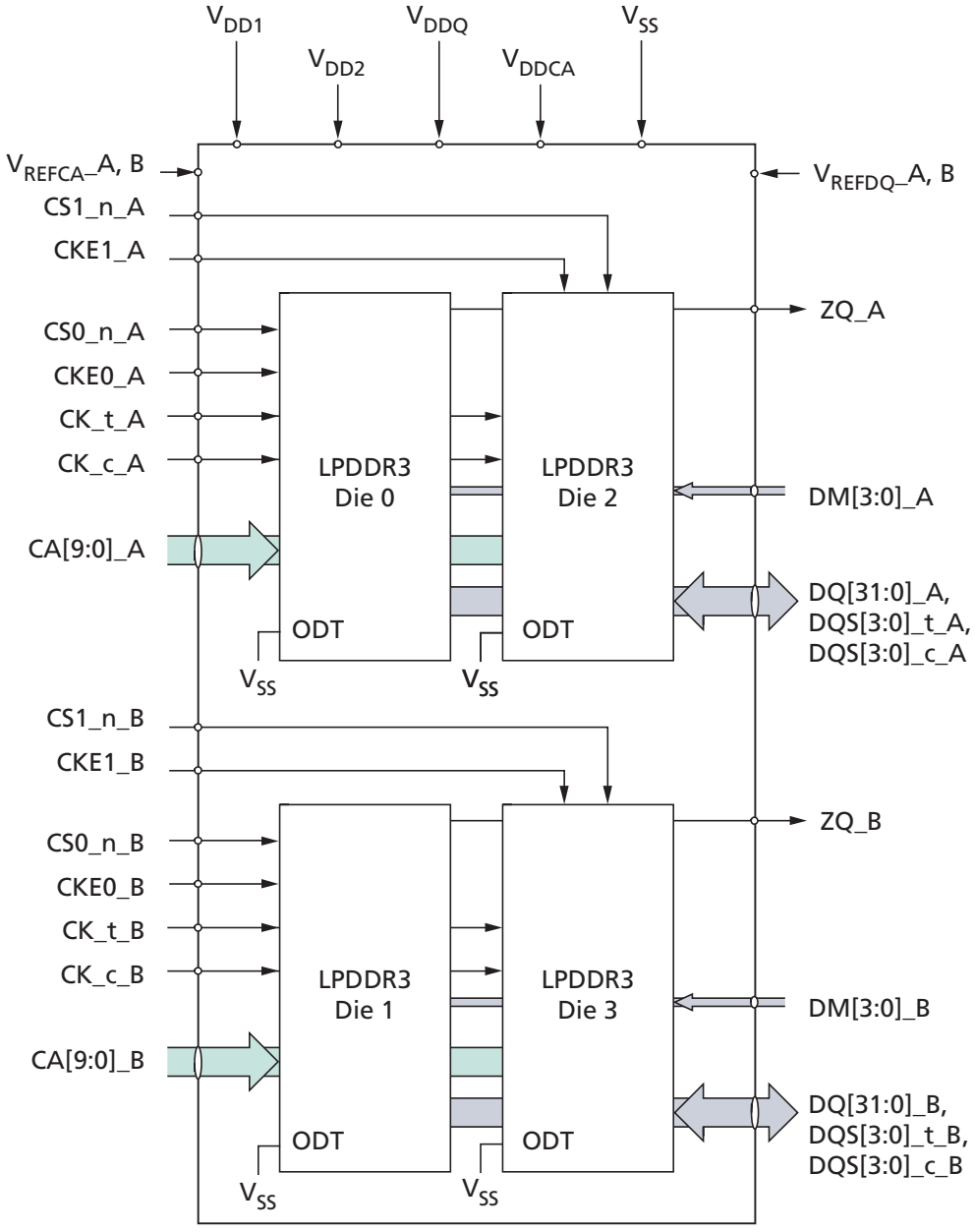
Package Block Diagrams

Figure 4: Dual-Die, Dual-Channel Package Block Diagram



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Figure 5: Quad-Die, Dual-Channel Package Block Diagram

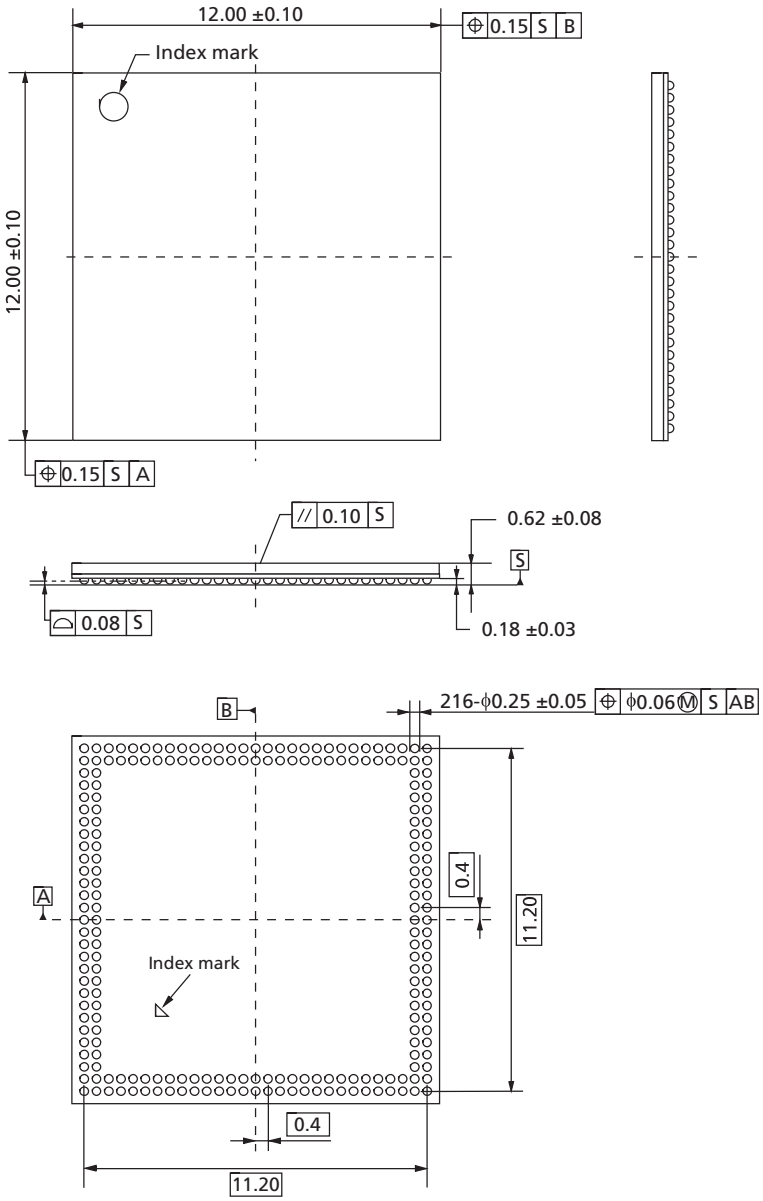


Note: 1. The ODT input is connected to rank 0. The ODT input to rank 1 is connected to V_{SS} in the package.

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Package Dimensions

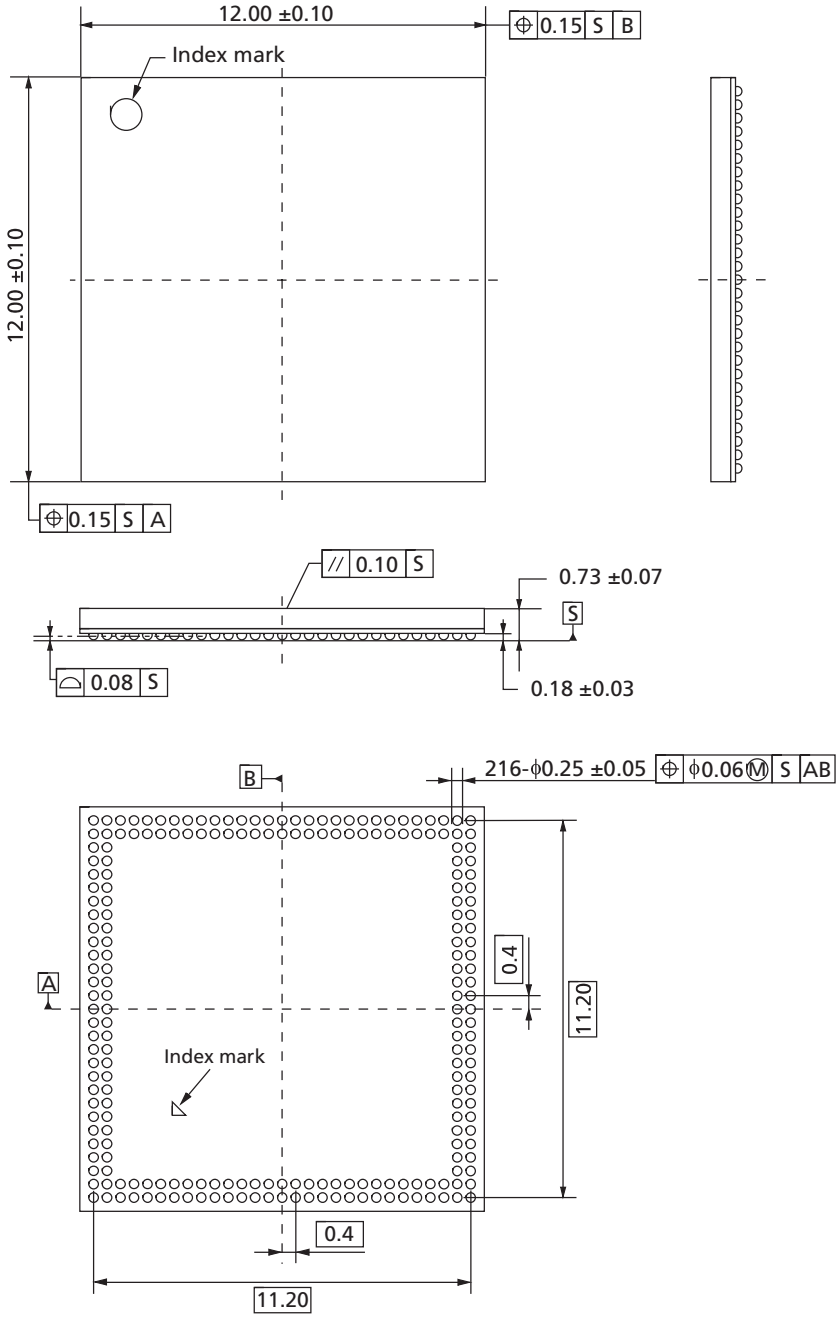
Figure 6: 216-Ball FBGA (12mm x 12mm) – EDF8164A3PK



Notes:
1. Package drawing: ECA-TS2-0498-01.
2. All dimensions are in millimeters.

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Figure 7: 216-Ball FBGA (12mm x 12mm) – EDFA164A2PK



Notes: 1. Package drawing: ECA-TS2-0499-01.
2. All dimensions are in millimeters.

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MR0, MR5–MR8 Readout

Table 5: Mode Register Contents

Mode Register	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
MR0	OP6 = 1b indicates support for WL set B OP7 = 1b indicates that the option for RL3 is supported OP6 and OP7 =1b for this package							
MR5	Manufacturer ID = 0000 0011b							
MR6	Revision ID1 = 0000 0010b: Revision C							
MR7	Revision ID2 = (RFU)							
MR8	**I/O Width**		**Density**				**Type**	
	00b: x32		0110b: 4Gb				11b: S8	

Note: 1. The contents of MR0 and MR5–MR8 will reflect the manufacturer ID, die revision, and interface configurations for each die for each package.

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I_{DD} Specifications – Dual Die, Dual Channel

Table 6: I_{DD} Specifications

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V; T_C = –30°C to +85°C

Symbol	Supply	Speed		Unit	Parameter/Condition
		1600	1333		
I_{DD01}	V_{DD1}	12	12	mA	All devices in operating one bank active-precharge ^tCK = ^tCK(avg) MIN; ^tRC = ^tRC (MIN); CKE is HIGH; CS_n is HIGH between valid commands; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD02}	V_{DD2}	60	60		
$I_{DD0,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD2P1}	V_{DD1}	0.8	0.8	mA	All devices in idle power-down standby current ^tCK = ^tCK(avg) MIN; CKE is LOW; CS_n is HIGH; All banks are idle; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD2P2}	V_{DD2}	1.8	1.8		
$I_{DD2P,in}$	V_{DDCA} + V_{DDQ}	0.2	0.2		
I_{DD2PS1}	V_{DD1}	0.8	0.8	mA	All devices in idle power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is LOW; CS_n is HIGH; All banks are idle; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD2PS2}	V_{DD2}	1.8	1.8		
$I_{DD2PS,in}$	V_{DDCA} + V_{DDQ}	0.2	0.2		
I_{DD2N1}	V_{DD1}	0.8	0.8	mA	All devices in idle non power-down standby current ^tCK = ^tCK(avg) MIN; CKE is HIGH; CS_n is HIGH; All banks are idle; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD2N2}	V_{DD2}	23	22		
$I_{DD2N,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD2NS1}	V_{DD1}	0.8	0.8	mA	All devices in idle non power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is HIGH; CS_n is HIGH; All banks are idle; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD2NS2}	V_{DD2}	19	19		
$I_{DD2NS,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD3P1}	V_{DD1}	1.4	1.4	mA	All devices in active power-down standby current ^tCK = ^tCK(avg) MIN; CKE is LOW; CS_n is HIGH; One bank is active; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD3P2}	V_{DD2}	10	10		
$I_{DD3P,in}$	V_{DDCA} + V_{DDQ}	0.2	0.2		
I_{DD3PS1}	V_{DD1}	1.4	1.4	mA	All devices in active power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is LOW; CS_n is HIGH; One bank is active; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD3PS2}	V_{DD2}	10	10		
$I_{DD3PS,in}$	V_{DDCA} + V_{DDQ}	0.2	0.2		
I_{DD3N1}	V_{DD1}	2.0	2.0	mA	All devices in active non power-down standby current ^tCK = ^tCK(avg) MIN; CKE is HIGH; CS_n is HIGH; One bank is active; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD3N2}	V_{DD2}	25	24		
$I_{DD3N,in}$	V_{DDCA} + V_{DDQ}	12	12		

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Table 6: I_{DD} Specifications (Continued)

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V; T_C = –30°C to +85°C

Symbol	Supply	Speed		Unit	Parameter/Condition
		1600	1333		
I_{DD3NS1}	V_{DD1}	2.0	2.0	mA	All devices in active non power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is HIGH; CS_n is HIGH; One bank is active; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD3NS2}	V_{DD2}	21	21		
$I_{DD3NS,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD4R1}	V_{DD1}	4.0	4.0	mA	All devices in operating burst read ^tCK = ^tCK(avg) MIN; CS_n is HIGH between valid commands; One bank is active; BL = 8; RL = RL (MIN); CA bus inputs are SWITCHING; 50% data change occurs at each burst transfer
I_{DD4R2}	V_{DD2}	400	350		
$I_{DD4R,in}$	V_{DDCA}	12	12		
I_{DD4W1}	V_{DD1}	4.0	4.0	mA	All devices in operating burst write ^tCK = ^tCK(avg) MIN; CS_n is HIGH between valid commands; One bank is active; BL = 8; WL = WL (MIN); CA bus inputs are SWITCHING; 50% data change occurs at each burst transfer
I_{DD4W2}	V_{DD2}	380	330		
$I_{DD4W,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD51}	V_{DD1}	40	40	mA	All devices in all bank auto-refresh ^tCK = ^tCK(avg) MIN; CKE is HIGH between valid commands; ^tRC = ^tRFCab (MIN); Burst refresh; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD52}	V_{DD2}	200	200		
$I_{DD5,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD5AB1}	V_{DD1}	4.0	4.0	mA	All devices in all bank auto-refresh ^tCK = ^tCK(avg) MIN; CKE is HIGH between valid commands; ^tRC = ^tREFI; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD5AB2}	V_{DD2}	24	23		
$I_{DD5AB,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD5PB1}	V_{DD1}	4.0	4.0	mA	All devices in per bank auto-refresh ^tCK = ^tCK(avg) MIN; CKE is HIGH between valid commands; ^tRC = ^tREFIpb; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD5PB2}	V_{DD2}	24	23		
$I_{DD5PB,in}$	V_{DDCA} + V_{DDQ}	12	12		
I_{DD81}	V_{DD1}	32	32	µA	All devices in deep power-down CK_t = LOW, CK _c = HIGH; CKE is LOW; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD82}	V_{DD2}	12	12		
$I_{DD8,in}$	V_{DDCA} + V_{DDQ}	24	24		

Notes:
1. Published I_{DD} values are the maximum of the distribution of the arithmetic mean.
2. I_{DD} current specifications are tested after the device is properly initialized.

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Table 7: I_{DD6} Partial-Array Self Refresh Current at 45°C

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V

PASR	Supply	Value	Unit	Parameter/Condition
Full array	V_{DD1}	400	µA	**All devices in self-refresh** CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are STABLE; Data bus inputs are STABLE
	V_{DD2}	1600		
	V_{DDCA} + V_{DDQ}	20		
1/2 array	V_{DD1}	320		
	V_{DD2}	1000		
	V_{DDCA} + V_{DDQ}	20		
1/4 array	V_{DD1}	260		
	V_{DD2}	600		
	V_{DDCA} + V_{DDQ}	20		
1/8 array	V_{DD1}	240		
	V_{DD2}	400		
	V_{DDCA} + V_{DDQ}	20		

Note: 1. I_{DD6} 45°C is typical of the distribution of the arithmetic mean.

Table 8: I_{DD6} Partial-Array Self Refresh Current at 85°C

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V

PASR	Supply	Value	Unit	Parameter/Condition
Full array	V_{DD1}	1800	µA	**All devices in self refresh** CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are STABLE; Data bus inputs are STABLE
	V_{DD2}	6400		
	V_{DDCA} + V_{DDQ}	24		
1/2 array	V_{DD1}	1300		
	V_{DD2}	4400		
	V_{DDCA} + V_{DDQ}	24		
1/4 array	V_{DD1}	1100		
	V_{DD2}	3400		
	V_{DDCA} + V_{DDQ}	24		
1/8 array	V_{DD1}	1000		
	V_{DD2}	2800		
	V_{DDCA} + V_{DDQ}	24		

Note: 1. I_{DD6} 85°C is the maximum of the distribution of the arithmetic mean.

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I_{DD} Specifications – Quad Die, Dual Channel

Table 9: I_{DD} Specifications

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V; T_C = –30°C to +85°C

Symbol	Supply	Speed			Unit	Parameter/Condition
		1866	1600	1333		
I_{DD01}	V_{DD1}	12	12	12	mA	2 devices in operating one bank active-precharge; 2 devices in deep power-down. Conditions for operating devices are: ^{t}CK = ^{t}CK(avg) MIN;^{t}RC = ^{t}RC (MIN); CKE is HIGH; CS_n is HIGH between valid commands; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD02}	V_{DD2}	62	60	60		
$I_{DD0,in}$	V_{DDCA} + V_{DDQ}	12	12	12		
I_{DD2P1}	V_{DD1}	1.6	1.6	1.6	mA	All devices in idle power-down standby current ^{t}CK = ^{t}CK(avg) MIN; CKE is LOW; CS_n is HIGH; All banks are idle; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD2P2}	V_{DD2}	3.6	3.6	3.6		
$I_{DD2P,in}$	V_{DDCA} + V_{DDQ}	0.4	0.4	0.4		
I_{DD2PS1}	V_{DD1}	1.6	1.6	1.6	mA	All devices in idle power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is LOW; CS_n is HIGH; All banks are idle; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD2PS2}	V_{DD2}	3.6	3.6	3.6		
$I_{DD2PS,in}$	V_{DDCA} + V_{DDQ}	0.4	0.4	0.4		
I_{DD2N1}	V_{DD1}	1.6	1.6	1.6	mA	All devices in idle non power-down standby current ^{t}CK = ^{t}CK(avg) MIN; CKE is HIGH; CS_n is HIGH; All banks are idle; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD2N2}	V_{DD2}	48	46	44		
$I_{DD2N,in}$	V_{DDCA} + V_{DDQ}	24	24	24		
I_{DD2NS1}	V_{DD1}	1.6	1.6	1.6	mA	All devices in idle non power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is HIGH; CS_n is HIGH; All banks are idle; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD2NS2}	V_{DD2}	38	38	38		
$I_{DD2NS,in}$	V_{DDCA} + V_{DDQ}	24	24	24		
I_{DD3P1}	V_{DD1}	2.8	2.8	2.8	mA	All devices in active power-down standby current ^{t}CK = ^{t}CK(avg) MIN; CKE is LOW; CS_n is HIGH; One bank is active; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD3P2}	V_{DD2}	20	20	20		
$I_{DD3P,in}$	V_{DDCA} + V_{DDQ}	0.4	0.4	0.4		
I_{DD3PS1}	V_{DD1}	2.8	2.8	2.8	mA	All devices in active power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is LOW; CS_n is HIGH; One bank is active; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD3PS2}	V_{DD2}	20	20	20		
$I_{DD3PS,in}$	V_{DDCA} + V_{DDQ}	0.4	0.4	0.4		

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Table 9: I_{DD} Specifications (Continued)

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V; T_C = –30°C to +85°C

Symbol	Supply	Speed			Unit	Parameter/Condition
		1866	1600	1333		
I_{DD3N1}	V_{DD1}	4.0	4.0	4.0	mA	All devices in active non power-down standby current ^tCK = ^tCK(avg) MIN; CKE is HIGH; CS_n is HIGH; One bank is active; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD3N2}	V_{DD2}	52	50	48		
$I_{DD3N,in}$	V_{DDCA} + V_{DDQ}	24	24	24		
I_{DD3NS1}	V_{DD1}	4.0	4.0	4.0	mA	All devices in active non power-down standby current with clock stop CK_t = LOW, CK_c = HIGH; CKE is HIGH; CS_n is HIGH; One bank is active; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD3NS2}	V_{DD2}	42	42	42		
$I_{DD3NS,in}$	V_{DDCA} + V_{DDQ}	24	24	24		
I_{DD4R1}	V_{DD1}	4.0	4.0	4.0	mA	2 devices in operating burst read; 2 devices in deep power-down. Conditions for operating devices are: ^tCK = ^tCK(avg) MIN; CS_n is HIGH between valid commands; One bank is active; BL = 8; RL = RL (MIN); CA bus inputs are SWITCHING; 50% data change occurs at each burst transfer
I_{DD4R2}	V_{DD2}	460	400	350		
$I_{DD4R,in}$	V_{DDCA}	12	12	12		
I_{DD4W1}	V_{DD1}	4.0	4.0	4.0	mA	2 devices in operating burst write; 2 devices in deep power-down Conditions for operating devices are: ^tCK = ^tCK(avg) MIN; CS_n is HIGH between valid commands; One bank is active; BL = 8; WL = WL (MIN); CA bus inputs are SWITCHING; 50% data change occurs at each burst transfer
I_{DD4W2}	V_{DD2}	440	380	330		
$I_{DD4W,in}$	V_{DDCA} + V_{DDQ}	12	12	12		
I_{DD51}	V_{DD1}	40	40	40	mA	2 devices in all bank auto-refresh; 2 devices in deep power-down. Conditions for operating devices are: ^tCK = ^tCK(avg) MIN; CKE is HIGH between valid commands; ^tRC = ^tRFCab (MIN); Burst refresh; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD52}	V_{DD2}	200	200	200		
$I_{DD5,in}$	V_{DDCA} + V_{DDQ}	12	12	12		
I_{DD5AB1}	V_{DD1}	4.0	4.0	4.0	mA	2 devices in all bank auto-refresh; 2 devices in deep power-down. Conditions for operating devices are: ^tCK = ^tCK(avg) MIN; CKE is HIGH between valid commands; ^tRC = ^tREFI; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD5AB2}	V_{DD2}	25	24	23		
$I_{DD5AB,in}$	V_{DDCA} + V_{DDQ}	12	12	12		

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Table 9: I_{DD} Specifications (Continued)

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V; T_C = –30°C to +85°C

Symbol	Supply	Speed			Unit	Parameter/Condition
		1866	1600	1333		
I_{DD5PB1}	V_{DD1}	4.0	4.0	4.0	mA	2 devices in per bank auto-refresh; 2 devices in deep power-down. Conditions for operating devices are: ^{t}CK = $^{t}CK(avg)$ MIN; CKE is HIGH between valid commands; ^{t}RC = $^{t}REFIpb$; CA bus inputs are SWITCHING; Data bus inputs are STABLE
I_{DD5PB2}	V_{DD2}	25	24	23		
$I_{DD5PB,in}$	V_{DDCA} + V_{DDQ}	12	12	12		
I_{DD81}	V_{DD1}	64	64	64	µA	All devices in deep power-down CK_t = LOW, CK _c = HIGH; CKE is LOW; CA bus inputs are STABLE; Data bus inputs are STABLE
I_{DD82}	V_{DD2}	24	24	24		
$I_{DD8,in}$	V_{DDCA} + V_{DDQ}	48	48	48		

Notes:
1. Published I_{DD} values are the maximum of the distribution of the arithmetic mean.
2. I_{DD} current specifications are tested after the device is properly initialized.

Table 10: I_{DD6} Partial-Array Self Refresh Current at 45°C

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V

PASR	Supply	Value	Unit	Parameters/Conditions
Full array	V_{DD1}	800	µA	**All devices in self refresh** CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are STABLE; Data bus inputs are STABLE
	V_{DD2}	3200		
	V_{DDCA} + V_{DDQ}	40		
1/2 array	V_{DD1}	640		
	V_{DD2}	2000		
	V_{DDCA} + V_{DDQ}	40		
1/4 array	V_{DD1}	520		
	V_{DD2}	1200		
	V_{DDCA} + V_{DDQ}	40		
1/8 array	V_{DD1}	480		
	V_{DD2}	800		
	V_{DDCA} + V_{DDQ}	40		

Note:
1. I_{DD6} 45°C is typical of the distribution of the arithmetic mean.

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Table 11: I_{DD6} Partial-Array Self Refresh Current at 85°C

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V

PASR	Supply	Value	Unit	Parameters/Conditions
Full array	V_{DD1}	3600	µA	**All devices in self refresh** CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are STABLE; Data bus inputs are STABLE
	V_{DD2}	12,800		
	V_{DDCA} + V_{DDQ}	48		
1/2 array	V_{DD1}	2600		
	V_{DD2}	8800		
	V_{DDCA} + V_{DDQ}	48		
1/4 array	V_{DD1}	2200		
	V_{DD2}	6800		
	V_{DDCA} + V_{DDQ}	48		
1/8 array	V_{DD1}	2000		
	V_{DD2}	5600		
	V_{DDCA} + V_{DDQ}	48		

Note: 1. I_{DD6} 85°C is the maximum of the distribution of the arithmetic mean.

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Pin Capacitance

Table 12: Input/Output Capacitance

Part Number	Density	Parameter	Symbol	Min	Max	Unit	Notes
EDF8164A3PK	8Gb	Input capacitance, CK_t and CK_c	C_{CK}	1.0	2.5	pF	1, 2
EDFA164A2PK	16Gb			1.5	3.5		
EDF8164A3PK	8Gb	Input capacitance, all other input-only pins except CS_n, CKE, and ODT	C_{I1}	1.0	2.5	pF	1, 2
EDFA164A2PK	16Gb			1.0	3.5		
EDF8164A3PK	8Gb	Input/output capacitance, DQ, DM, DQS_t, DQS_c	C_{IO}	1.0	3.5	pF	1, 2, 3
EDFA164A2PK	16Gb			2.0	5.0		
EDF8164A3PK	8Gb	Input/output capacitance, ZQ	C_{ZQ}	1.0	2.5	pF	1, 2, 3
EDFA164A2PK	16Gb			1.5	3.5		

Notes:
1. This parameter is not subject to production testing. It is verified by design and characterization.
2. These parameters are measured on f = 100 MHz, $V_{OUT} = V_{DDQ/2}$, T_A = +25 °C.
3. D_{OUT} circuits are disabled.

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LPDDR3 Array Configuration

The 4Gb Mobile Low-Power DDR3 SDRAM (LPDDR3) is a high-speed CMOS, dynamic random-access memory containing 4,294,967,296-bits. The device is internally configured as an eight-bank DRAM. Each of the x16's 536,870,912-bit banks is organized as 16,384 rows by 2048 columns by 16 bits. Each of the x32's 536,870,912-bit banks is organized as 16,384 rows by 1024 columns by 32 bits.

General Notes

Throughout the data sheet, figures and text refer to DQs as "DQ." DQ should be interpreted as any or all DQ collectively, unless specifically stated otherwise.

"DQS" and "CK" should be interpreted as DQS_t, DQS_c and CK_t, CK_c, respectively, unless specifically stated otherwise. "BA" and "CA" include all BA and CA pins, respectively, used for a given density.

Complete functionality may be described throughout the entire document. Any page or diagram may have been simplified to convey a topic and may not be inclusive of all requirements.

Timing diagrams reflect a single-channel device.

In timing diagrams, "CMD" is used as an indicator only. Actual signals occur on CA[9:0].

V_{REF} indicates V_{REFCA} and V_{REFDQ}.

Any specific requirement takes precedence over a general statement.

Any functionality not specifically stated herein is considered undefined, illegal, is not supported, and will result in unknown operation.

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Functional Description

Mobile LPDDR3 is a high-speed SDRAM internally configured as an 8-bank memory device. LPDDR3 uses a double data rate architecture on the command/address (CA) bus to reduce the number of input pins in the system. The 10-bit CA bus is used to transmit command, address, and bank information. Each command uses one clock cycle, during which command information is transferred on both the rising and falling edges of the clock.

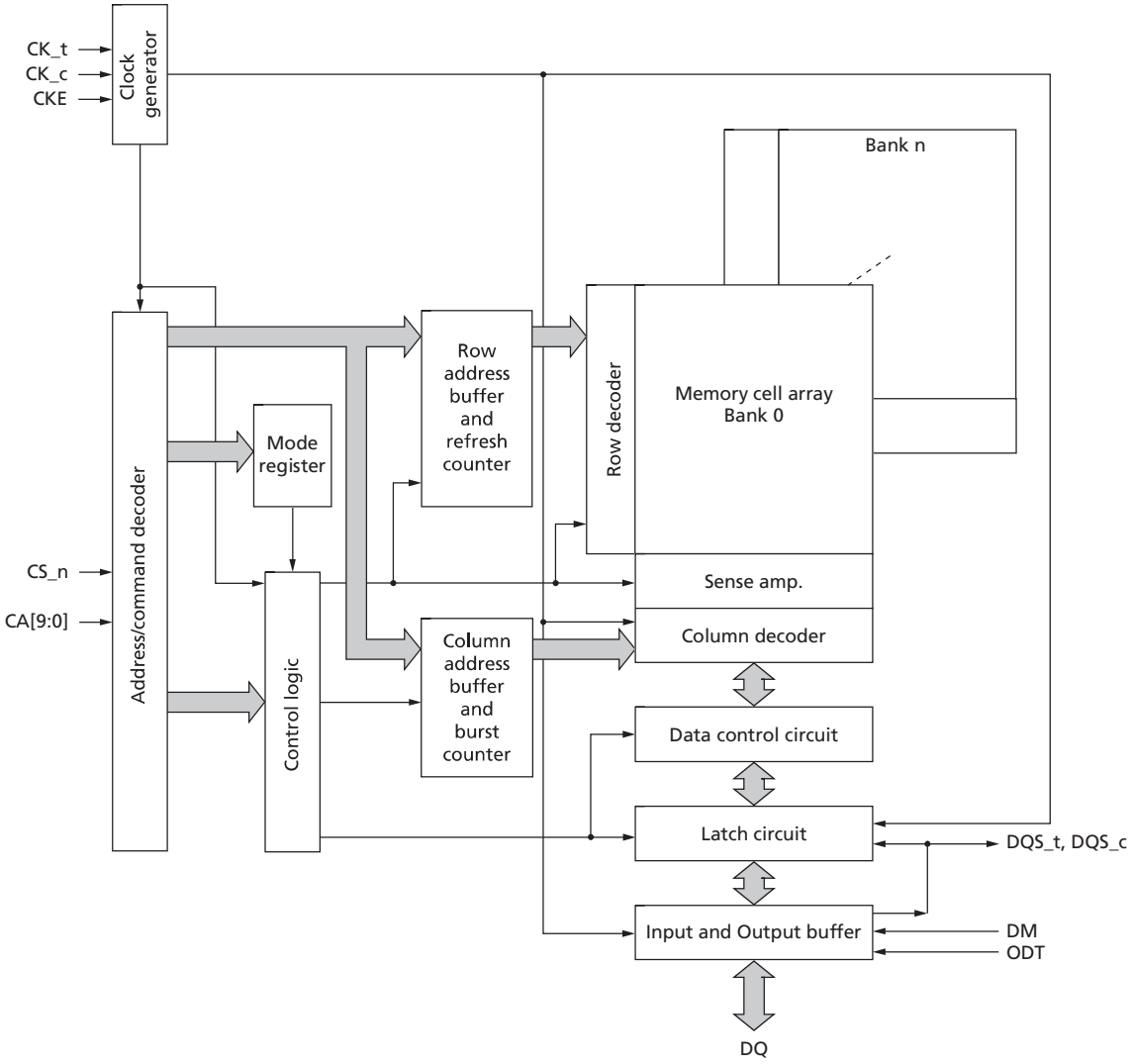
LPDDR3 uses a double data rate architecture on the DQ pins to achieve high-speed operation. The double data rate architecture is essentially an 8*n* prefetch architecture with an interface designed to transfer two data bits per DQ every clock cycle at the I/O pins. A single read or write access for LPDDR3 effectively consists of a single 8*n*-bit-wide, one-clock-cycle data transfer at the internal SDRAM core and eight corresponding *n*-bit-wide, one-half-clock-cycle data transfers at the I/O pins.

Read and write accesses to the device are burst oriented; accesses start at a selected location and continue for a programmed number of locations in a programmed sequence.

Accesses begin with the registration of an ACTIVATE command followed by a READ or WRITE command. The address and BA bits registered coincident with the ACTIVATE command are used to select the row and bank to be accessed. The address bits registered coincident with the READ or WRITE command are used to select the bank and the starting column location for the burst access.

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Figure 8: Functional Block Diagram



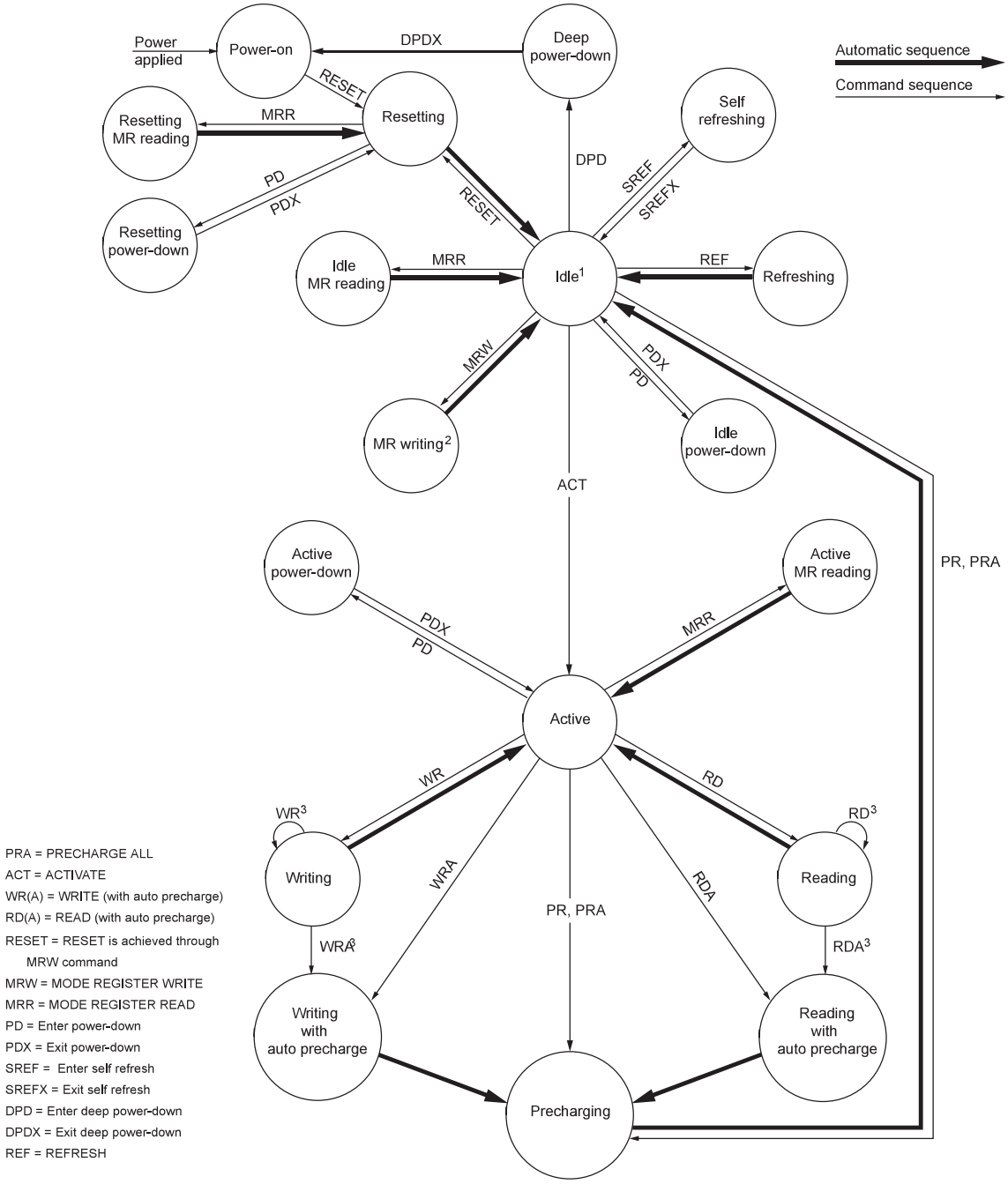
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Simplified Bus Interface State Diagram

The state diagram provides a simplified illustration of the bus interface, supported state transitions, and the commands that control them. For a complete description of device behavior, use the information provided in the state diagram with the truth tables and timing specifications. The truth tables describe device behavior and applicable restrictions when considering the actual state of all banks. For command descriptions, see the Commands and Timing section.

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Figure 9: Simplified State Diagram



Notes:
1. All banks are precharged in the idle state.
2. In the case of using MRW to enter CA training mode or write leveling mode, the state machine will not automatically return to the idle state. In these cases, an additional MRW command is required to exit either operating mode and return to the idle state. See the CA Training Mode or Write Leveling Mode sections.
3. Terminated bursts are not allowed. For these state transitions, the burst operation must be completed before a transition can occur.

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4. The state diagram is intended to provide a floorplan of the possible state transitions and commands used to control them, but it is not comprehensive. In particular, situations involving more than one bank are not captured in full detail.

Power-Up and Initialization

The device must be powered up and initialized in a predefined manner. Power-up and initialization by means other than those specified will result in undefined operation.

Voltage Ramp and Device Initialization

The following sequence must be used to power up the device. Unless specified otherwise, this procedure is mandatory.

1. Voltage Ramp: While applying power (after Ta), CKE must be held LOW, and all other inputs must be between V_{ILmin} and V_{IHmax}. The device outputs remain at High-Z while CKE is held LOW.

Following completion of the voltage ramp (Tb), CKE must be held LOW. DQ, DM and DQS voltage levels must be between V_{SSQ} and V_{DDQ} during voltage ramp to avoid latch-up. CK, CS_n, and CA input levels must be between V_{SSCA} and V_{DDCA} during voltage ramp to avoid latch-up. Voltage ramp power supply requirements are provided in the table below.

Table 13: Voltage Ramp Conditions

After	Applicable Conditions
Ta is reached	V_{DD1} must be greater than V_{DD2} - 200mV
	V_{DD1} and V_{DD2} must be greater than V_{DDCA} - 200mV
	V_{DD1} and V_{DD2} must be greater than V_{DDQ} - 200mV
	V_{REF} must always be less than all other supply voltages

Notes:
1. Ta is the point when any power supply first reaches 300mV.
2. Noted conditions apply between Ta and power-down (controlled or uncontrolled).
3. Tb is the point at which all supply and reference voltages are within their defined operating ranges.
4. For supply and reference voltage operating conditions, see the Recommended DC Operating Conditions table.
5. The voltage difference between any V_{SS}, V_{SSQ}, and V_{SSCA} pins must not exceed 100mV.

Beginning at Tb, CKE must remain LOW for at least ^{t}INIT1, after which CKE can be asserted HIGH. The clock must be stable at least ^{t}INIT2 prior to the first CKE LOW-to-HIGH transition (Tc). CKE, CS_n, and CA inputs must observe setup and hold requirements (^{t}IS, ^{t}IH) with respect to the first rising clock edge and to subsequent falling and rising edges.

If any MRRs are issued, the clock period must be within the range defined for ^{t}CKb. MRWs can be issued at normal clock frequencies as long as all AC timings are met. Some AC parameters (for example, ^{t}DQSCK) could have relaxed timings (such as ^{t}DQSCKb) before the system is appropriately configured. While keeping CKE HIGH, NOP commands must be issued for at least ^{t}INIT3 (Td). The ODT input signal may be in an undefined state until ^{t}IS before CKE is registered HIGH. When CKE is registered

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HIGH, the ODT input signal must be statically held either LOW or HIGH. The ODT input signal remains static until the power-up initialization sequence is finished, including the expiration of tZQINIT.

2. RESET Command: After tINIT3 is satisfied, the MRW RESET command must be issued (Td). An optional PRECHARGE ALL command can be issued prior to the MRW RESET command. Wait at least tINIT4 while keeping CKE asserted and issuing NOP commands. Only NOP commands are allowed during tINIT4.

3. MRRs and Device Auto Initialization (DAI) Polling: After tINIT4 is satisfied (Te), only MRR commands and POWER-DOWN ENTRY/EXIT commands are supported, and CKE can go LOW in alignment with power-down entry and exit specifications (see Power-Down). MRR commands are valid at this time only when the CA bus does not need to be trained. CA training can begin only after time Tf.

The MRR command can be initiated to poll the DAI bit, which indicates whether device auto initialization is complete. When the bit indicates completion, the device is in an idle state. The device is also in an idle state after tINIT5 (MAX) has expired, regardless whether the DAI bit has been read by the MRR command. Because the memory output buffers are not properly configured by Te, some AC parameters must use relaxed timing specifications before the system is appropriately configured.

After the DAI bit (MR0, DAI) is set to zero by the memory device (DAI complete), the device is in the idle state (Tf). DAI status can be determined by issuing the MRR command to MR0. The device sets the DAI bit no later than tINIT5 after the RESET command. The controller must wait at least tINIT5 (MAX) or until the DAI bit is set before proceeding.

4. ZQ Calibration: If CA training is not required, the MRW INITIALIZATION CALIBRATION (ZQ_CAL) command can be issued to the memory (MR10) after Tf. No other CA commands (other than RESET or NOP) may be issued prior to the completion of CA training. After the completion of CA training (Tf'), the MRW INITIALIZATION CALIBRATION (ZQ_CAL) command can be issued to the memory.

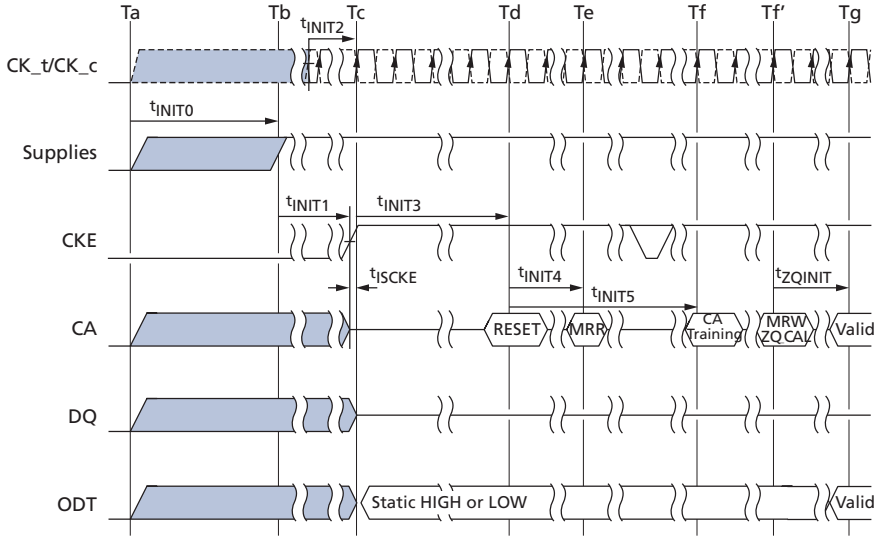
This command is used to calibrate output impedance over process, voltage, and temperature. In systems where more than one LPDDR3 device exists on the same bus, the controller must not overlap MRW ZQ_CAL commands. The device is ready for normal operation after tZQINIT.

5. Normal Operation: AftertZQINIT (Tg), MRW commands must be used to properly configure the memory (for example, output buffer drive strength, latencies, and so on). Specifically, MR1, MR2, and MR3 must be set to configure the memory for the target frequency and memory configuration.

After the initialization sequence is complete, the device is ready for any valid command. After Tg, the clock frequency can be changed using the procedure described in the Input Clock Frequency Changes and Clock Stop Events section.

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Figure 10: Voltage Ramp and Initialization Sequence



Notes:
1. High-Z on the CA bus indicates a valid NOP.
2. For tINIT values, see the Initialization Timing Parameters table.
3. After RESET command time (Tf), R_{TT} is disabled until ODT function is enabled by MRW to MR11 following Tg.
4. CA training is optional.

Table 14: Initialization Timing Parameters

Parameter	Min	Max	Unit	Comment
tINIT0	–	20	ms	Maximum voltage ramp time (Note 1)
tINIT1	100	–	ns	Minimum CKE LOW time after completion of voltage ramp
tINIT2	5	–	tCK	Minimum stable clock before first CKE HIGH
tINIT3	200	–	µs	Minimum idle time after first CKE assertion
tINIT4	1	–	µs	Minimum idle time after RESET command
tINIT5	–	10	µs	Maximum duration of device auto initialization (Note 2)
tZQINIT	1	–	µs	ZQ initial calibration
tCKb	18	100	ns	Clock cycle time during boot

Notes:
1. The tINIT0 maximum specification is not a tested limit and should be used as a general guideline. For voltage ramp times exceeding tINIT0 MAX, please contact the factory.
2. If the DAI bit is not read via MRR, the device will be in the idle state after tINIT5 (MAX) has expired.

Initialization After Reset (Without Voltage Ramp)

If the RESET command is issued before or after the power-up initialization sequence, the reinitialization procedure must begin at Td.

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Power-Off Sequence

The following procedure is required to power off the device.

While powering off, CKE must be held LOW; all other inputs must be between V_{ILmin} and V_{IHmax}. The device outputs remain at High-Z while CKE is held LOW.

DQ, DM, and DQS voltage levels must be between V_{SSQ} and V_{DDQ} during the power-off sequence to avoid latch-up. CK, CS_n, and CA input levels must be between V_{SSCA} and V_{DDCA} during the power-off sequence to avoid latch-up.

Tx is the point where any power supply drops below the minimum value specified in the Recommended DC Operating Conditions table.

Tz is the point where all power supplies are below 300mV. After Tz, the device is powered off.

Table 15: Power Supply Conditions

Between...	Applicable Conditions
Tx and Tz	V_{DD1} must be greater than V_{DD2} - 200mV
	V_{DD1} must be greater than V_{DDCA} - 200mV
	V_{DD1} must be greater than V_{DDQ} - 200mV
	V_{REF} must always be less than all other supply voltages

Notes:
1. The voltage difference between any V_{SS}, V_{SSQ}, and V_{SSCA} pins must not exceed 100mV.
2. For supply and reference voltage operating conditions, see Recommended DC Operating Conditions table.

Uncontrolled Power-Off Sequence

When an uncontrolled power-off occurs, the following conditions must be met.

- At Tx, when the power supply drops below the minimum values specified in the Recommended DC Operating Conditions table, all power supplies must be turned off and all power supply current capacity must be at zero, except for any static charge remaining in the system.
- After Tz (the point at which all power supplies first reach 300mV), the device must power off. During this period, the relative voltage between power supplies is uncontrolled. V_{DD1} and V_{DD2} must decrease with a slope lower than 0.5 V/µs between Tx and Tz.

An uncontrolled power-off sequence can occur a maximum of 400 times over the life of the device.

Table 16: Power-Off Timing

Parameter	Symbol	Min	Max	Unit
Maximum power-off ramp time	^{t}POFF	–	2	sec

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Standard Mode Register Definition

For LPDDR3, a set of mode registers is used for programming device operating parameters, reading device information and status, and for initiating special operations such as DQ calibration, ZQ calibration, and device reset.

Mode Register Assignments and Definitions

Mode register definitions are provided in the Mode Register Assignments table. An "R" in the access column of the table indicates read-only; "W" indicates write-only; "R/W" indicates read- or write-capable or enabled. The MRR command is used to read from a register. The MRW command is used to write to a register.

Table 17: Mode Register Assignments

Notes 1–5 apply to entire table

MR#	MA[7:0]	Function	Access	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0	Link
0	00h	Device info	R	RL3	WL-B	RFU	RZQI		RFU		DAI	Go to MR0
1	01h	Device feature 1	W	*n*WR (for AP)			RFU		BL			Go to MR1
2	02h	Device feature 2	W	WR Lev	WL Select	RFU	*n*WRE	RL and WL				Go to MR2
3	03h	I/O config-1	W	RFU				DS				Go to MR3
4	04h	SDRAM refresh rate	R	TUF	RFU			Refresh rate				Go to MR4
5	05h	Basic config-1	R	Manufacturer ID								Go to MR5
6	06h	Basic config-2	R	Revision ID1								Go to MR6
7	07h	Basic config-3	R	Revision ID2								Go to MR7
8	08h	Basic config-4	R	I/O width		Density				Type		Go to MR8
9	09h	Test mode	W	Vendor-specific test mode								Go to MR9
10	0Ah	I/O calibration	W	Calibration code								Go to MR10
11	0Bh	ODT	W	RFU					PD ctl	DQ ODT		Go to MR11
12–15	0Ch–0Fh	Reserved	–	RFU								Go to MR12
16	10h	PASR_Bank	W	PASR bank mask								Go to MR16
17	11h	PASR_Seg	W	PASR segment mask								Go to MR17
18–31	12h–1Fh	Reserved	–	RFU								Go to MR18–MR31
32	20h	DQ calibration pattern A	R	See Data Calibration Pattern Description								
33–39	21h–27h	Do not use	–									Go to MR33
40	28h	DQ calibration pattern B	R	See Data Calibration Pattern Description								
41	29h	CA training 1	W	See MRW - CA Training Mode								
42	2Ah	CA training 2	W	See MRW - CA Training Mode								
43–47	2Bh–2Fh	Do not use	–									Go to MR43
48	30h	CA training 3	W	See MRW - CA Training Mode								
49–62	31h–3Eh	Reserved	–	RFU								Go to MR49

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Table 17: Mode Register Assignments (Continued)

Notes 1–5 apply to entire table

MR#	MA[7:0]	Function	Access	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0	Link
63	3Fh	RESET	W	X								Go to MR63
64–255	40h–FFh	Reserved	–	RFU								Go to MR64

Notes:
1. RFU bits must be set to 0 during MRW.
2. RFU bits must be read as 0 during MRR.
3. For Reads to a write-only or RFU register, DQS is toggled and undefined data is returned.
4. RFU mode registers must not be written.
5. Writes to read-only registers must have no impact on the functionality of the device.

Table 18: MR0 Device Feature 0 (MA[7:0] = 00h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
RL3	WL-B	RFU	RZQI		RFU		DAI

Table 19: MR0 Op-Code BIt Definitions

Register Information	Tag	Type	OP	Definition
Device auto initialization status	DAI	Read-only	OP0	0b: DAI complete 1b: DAI in progress
Built-in self-test for RZQ information	RZQI[1]	Read-only	OP[4:3]	00b: RZQ self-test not supported 01b: ZQ pin can connect to V_{DDCA} or float 10b: ZQ pin can short to GND 11b: ZQ pin self-test completed, no error condition detected (ZQ pin must not float; connect to V_{DD} or short to GND
WL Set B support	WL-B	Read-only	OP[6]	0b: Device does not support WL Set B 1b: Device supports WL Set B
RL3 support	RL3	Read-only	OP[7]	0b: Device does not support RL = 3, *n*WR = 3, WL = 1 1b: Device supports RL= 3, *n*WR = 3, WL = 1 for frequencies ≤166 MHz

Notes:
1. RZQI will be set upon completion of the MRW ZQ INITIALIZATION CALIBRATION command.
2. If ZQ is connected to V_{DDCA} to set default calibration, OP[4:3] must be set to 01. If ZQ is not connected to V_{DDCA}, either OP[4:3] = 01 or OP[4:3] = 10 may indicate a ZQ pin assembly error.
3. In the case of a possible assembly error, the device will default to factory trim settings for R_{ON} and will ignore ZQ CALIBRATION commands. In either case, the system may not function as intended.
4. If the ZQ self-test returns a value of 11b, it indicates that the device has detected a resistor connection to the ZQ pin. However, that result cannot be used to validate the ZQ resistor value or that the ZQ resistor tolerance meets the specified limit of 240Ω ±1%.

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Table 20: MR1 Device Feature 1 (MA[7:0] = 01h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
*n*WR (for AP)			RFU		BL		

Table 21: MR1 Op-Code Bit Definitions

Feature	Type	OP	Definition	Notes
BL	Write-only	OP[2:0]	011b: BL8 (default) All others: Reserved	
*n*WR	Write-only	OP[7:5]	If *n*WR (MR2 OP[4]) = 0 001b: *n*WR = 3 100b: *n*WR = 6 110b: *n*WR = 8 111b: *n*WR = 9 If *n*WR (MR2 OP[4]) = 1 000b: *n*WR = 10 (default) 001b: *n*WR = 11 010b: *n*WR = 12 100b: *n*WR = 14 110b: *n*WR = 16 All others: Reserved	1, 2

Notes:
1. The programmed value in the *n*WR register is the number of clock cycles that determine when to start the internal precharge operation for a WRITE burst with AP enabled. It is determined by RU (^{t}WR/^{t}CK).
2. The range of *n*WR is extended (MR2 OP[4] = 1) by using an extra bit (*n*WRE) in MR2.

Table 22: Burst Sequence

C2	C1	C0	BL	Burst Cycle Number and Burst Address Sequence							
				1	2	3	4	5	6	7	8
0b	0b	0b	8	0	1	2	3	4	5	6	7
0b	1b	0b		2	3	4	5	6	7	0	1
1b	0b	0b		4	5	6	7	0	1	2	3
1b	1b	0b		6	7	0	1	2	3	4	5

Note:
1. C0 input is not present on CA bus; it is implied zero.

Table 23: MR2 Device Feature 2 (MA[7:0] = 02h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
WR Lev	WL Sel	RFU	*n*WRE	RL and WL			

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Table 24: MR2 Op-Code Bit Definitions

Feature	Type	OP	Definition
RL and WL	Write-only	OP[3:0]	If OP[6] = 0 (default, WL Set A) 0001b: RL3/WL1 (≤166 MHz)[1] 0100b: RL6/WL3 (≤400 MHz) 0110b: RL8/WL4 (≤533 MHz) 0111b: RL9/WL5 (≤600 MHz) 1000b: RL10/WL6 (≤667 MHz, default) 1001b: RL11/WL6 (≤733 MHz) 1010b: RL12/WL6 (≤800 MHz) 1100b: RL14/WL8 (≤933 MHz) 1110b: RL16/WL8 (≤1066 MHz) All others: Reserved If OP[6] = 1 (WL Set B) 0001b: RL3/WL1 (≤166 MHz)[1] 0100b: RL6/WL3 (≤400 MHz) 0110b: RL8/WL4 (≤533 MHz) 0111b: RL9/WL5 (≤600 MHz) 1000b: RL10/WL8 (≤667 MHz, default) 1001b: RL11/WL9 (≤733 MHz) 1010b: RL12/WL9 (≤800 MHz) 1100b: RL14/WL11 (≤933 MHz) 1110b: RL16/WL13 (≤1066 MHz) All others: Reserved
*n*WRE	Write-only	OP[4]	0b: Enable *n*WRE programming ≤9
			1b: Enable *n*WRE programming >9 (default)
WL select	Write-only	OP[6]	0b: Use WL Set A (default)
			1b: Use WL Set B[2]
WR Lev	Write-only	OP[7]	0b: Disable write leveling (default)
			1b: Enable write leveling

Notes: 1. See MR0 OP7.
2. See MR0 OP6.

Table 25: LPDDR3 READ and WRITE Latency

Data Rate (Mb/p/s)	333	800	1066	1200	1333	1466	1600	1866	2133
^{t}CK(ns)	6	2.5	1.875	1.67	1.5	1.36	1.25	1.071	0.938
RL	3	6	8	9	10	11	12	14	16
WL (Set A)	1	3	4	5	6	6	6	8	8
WL (Set B)	1	3	4	5	8	9	9	11	13

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Table 26: MR3 I/O Configuration 1 (MA[7:0] = 03h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
RFU				DS			

Table 27: MR3 Op-Code Bit Definitions

Feature	Type	OP	Definition
DS	Write-only	OP[3:0]	0001b: 34.3Ω typical 0010b: 40Ω typical (default) 0011b: 48Ω typical 0100b: Reserved 0110b: Reserved 1001b: 34.3Ω pull-down, 40Ω pull-up 1010b: 40Ω pull-down, 48Ω pull-up 1011b: 34.3Ω pull-down, 48Ω pull-up All others: Reserved

Table 28: MR4 Device Temperature (MA[7:0] = 04h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
TUF	RFU				SDRAM refresh rate		

Table 29: MR4 Op-Code Bit Definitions

Notes 1–8 apply to entire table

Feature	Type	OP	Definition
SDRAM refresh rate	Read-only	OP[2:0]	000b: SDRAM low-temperature operating limit exceeded 001b: 4 × ^{t}REFI, 4 × ^{t}REFIpb, 4 × ^{t}REFW 010b: 2 × ^{t}REFI, 2 × ^{t}REFIpb, 2 × ^{t}REFW 011b: 1 × ^{t}REFI, 1 × ^{t}REFIpb, 1 × ^{t}REFW (≤85°C) 100b: 0.5 × ^{t}REFI, 0.5 × ^{t}REFIpb, 0.5 × ^{t}REFW, no AC timing derating 101b: 0.25 × ^{t}REFI, 0.25 × ^{t}REFIpb, 0.25 × ^{t}REFW, no AC timing derating 110b: 0.25 × ^{t}REFI, 0.25 × ^{t}REFIpb, 0.25 × ^{t}REFW, timing derating required 111b: SDRAM high-temperature operating limit exceeded
Temperature update flag (TUF)	Read-only	OP7	0b: OP[2:0] value has not changed since last read of MR4 1b: OP[2:0] value has changed since last read of MR4

Notes:
1. A mode register read from MR4 will reset OP7 to 0.
2. OP7 is reset to 0 at power-up.
3. If OP2 = 1, the device temperature is greater than 85°C.
4. OP7 is set to 1 if OP[2:0] has changed at any time since the last MR4 read.
5. The device might not operate properly when OP[2:0] = 000b or 111b.
6. For the specified operating temperature range and maximum operating temperature, refer to the Operating Temperature Range table.

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7. LPDDR3 devices must be derated by adding 1.875ns to the following core timing parameters: ^{t}RCD, ^{t}RC, ^{t}RAS, ^{t}RP, and ^{t}RRD. The ^{t}DQSCK parameter must be derated as specified in the AC Timing table. Prevailing clock frequency specifications and related setup and hold timings remain unchanged.
8. The recommended frequency for reading MR4 is provided in the Temperature Sensor section.

Table 30: MR5 Basic Configuration 1 (MA[7:0] = 05h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Manufacturer ID							

Table 31: MR5 Op-Code Bit Definitions

Feature	Type	OP	Definition
Manufacturer ID	Read-only	OP[7:0]	0000 0011b: Micron
			1111 1111b: Micron
			All others: Reserved

Table 32: MR6 Basic Configuration 2 (MA[7:0] = 06h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Revision ID1							

Note: 1. MR6 is vendor-specific.

Table 33: MR6 Op-Code Bit Definitions

Feature	Type	OP	Definition
Revision ID1	Read-only	OP[7:0]	0000 0000b: Revision A
			0000 0001b: Revision B
			0000 0010b: Revision C

Table 34: MR7 Basic Configuration 3 (MA[7:0] = 07h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Revision ID2							

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Table 35: MR7 Op-Code Bit Definitions

Feature	Type	OP	Definition
Revision ID2	Read-only	OP[7:0]	RFU

Note: 1. MR7 is vendor-specific.

Table 36: MR8 Basic Configuration 4 (MA[7:0] = 08h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
I/O width		Density				Type	

Table 37: MR8 Op-Code Bit Definitions

Feature	Type	OP	Definition
Type	Read-only	OP[1:0]	11b: LPDDR3 All other states reserved
Density	Read-only	OP[5:2]	0110b: 4Gb 1110b: 6Gb 0111b: 8Gb 1101b: 12Gb 1000b: 16Gb 1001b: 32Gb All others: Reserved
I/O width	Read-only	OP[7:6]	00b: x32 01b: x16 All others: Reserved

Table 38: MR9 Test Mode (MA[7:0] = 09h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Vendor-specific test mode							

Table 39: MR10 Calibration (MA[7:0] = 0Ah)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Calibration code							

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Table 40: MR10 Op-Code Bit Definitions

Notes 1–4 apply to entire table

Feature	Type	OP	Definition
Calibration code	Write-only	OP[7:0]	0xFF: CALIBRATION command after initialization 0xAB: Long calibration 0x56: Short calibration 0xC3: ZQ reset All others: Reserved

Notes:
1. The device ignores calibration commands when a reserved value is written into MR10.
2. See AC Timing table for the calibration latency.
3. If ZQ is connected to V_{SSCA} through R_{ZQ}, either the ZQ calibration function (see MRW ZQ CALIBRATION Command) or default calibration (through the ZQ RESET command) is supported. If ZQ is connected to V_{DDCA}, the device operates with default calibration and ZQ CALIBRATION commands are ignored. In both cases, the ZQ connection must not change after power is supplied to the device.
4. Devices that do not support calibration ignore the ZQ CALIBRATION command.

Table 41: MR11 ODT Control (MA[7:0] = 0Bh)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Reserved					PD CTL	DQ ODT	

Table 42: MR11 Op-Code Bit Definitions

Feature	Type	OP	Definition
DQ ODT	Write-only	OP[1:0]	00b: Disable (default) 01b: RZQ/4 (Note1) 10b: RZQ/2 11b: RZQ/1
PD control	Write-only	OP[2]	00b: ODT disabled by DRAM during power-down (default) 01b: ODT enabled by DRAM during power-down

Note:
1. RZQ/4 is supported for LPDDR3-1866 and LPDDR3-2133 devices. RZQ/4 support is optional for LPDDR3-1333 and LPDDR3-1600 devices. Consult Micron specifications for RZQ/4 support for LPDDR3-1333 and LPDDR3-1600.

Table 43: MR16 PASR Bank Mask (MA[7:0] = 010h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
PASR bank mask							

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Table 44: MR16 Op-Code Bit Definitions

Feature	Type	OP	Definition
Bank[7:0] mask	Write-only	OP[7:0]	0b: Refresh enable to the bank = unmasked (default) 1b: Refresh blocked = masked

Table 45: MR17 PASR Segment Mask (MA[7:0] = 011h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
PASR segment mask							

Table 46: MR17 PASR Segment Mask Definitions

Feature	Type	OP	Definition
Segment[7:0] mask	Write-only	OP[7:0]	0b: Refresh enable to the segment = unmasked (default) 1b: Refresh blocked = masked

Table 47: MR17 PASR Row Address Ranges in Masked Segments

Segment	OP	Segment Mask	4Gb	6Gb[2], 8Gb, 12Gb[2] & 16Gb	32Gb
			R[13:11]	R[14:12]	TBD
0	0	XXXXXXX1	000b		
1	1	XXXXXX1X	001b		
2	2	XXXXX1XX	010b		
3	3	XXXX1XXX	011b		
4	4	XXX1XXXX	100b		
5	5	XX1XXXXX	101b		
6	6	X1XXXXXX	110b		
7	7	1XXXXXXX	111b		

Notes: 1. X = "Don't Care" for the designated segment.
2. No memory present at addresses with R13 = R14 = HIGH. Segment masks 6 and 7 are ignored.

Table 48: MR63 RESET (MA[7:0] = 3Fh) – MRW Only

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
X or 0xFCh							

Note: 1. For additional information on MRW RESET, see the Mode Register Write (MRW) section.

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Table 49: Reserved Mode Registers

Mode Register	MA	Address	Restriction	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
MR[12:15]	MA[7:0]	0Ch-0Fh	Reserved	Reserved							
MR[18:31]		12h–1Fh	Reserved	Reserved							
MR[33:39]		21h–27h	DNU	DNU							
MR[43:47]		2Bh–2Fh	DNU	DNU							
MR[49:62]		31h–3Eh	Reserved	Reserved							
MR[64:255]		40h–FFh	Reserved	Reserved							

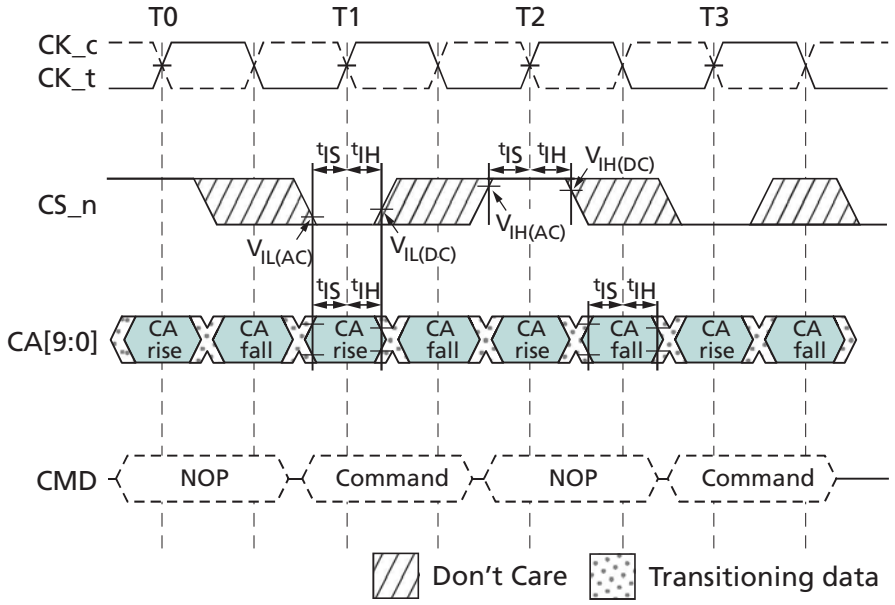
Note: 1. DNU = Do not use; RVU = Reserved for vendor use.

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Commands and Timing

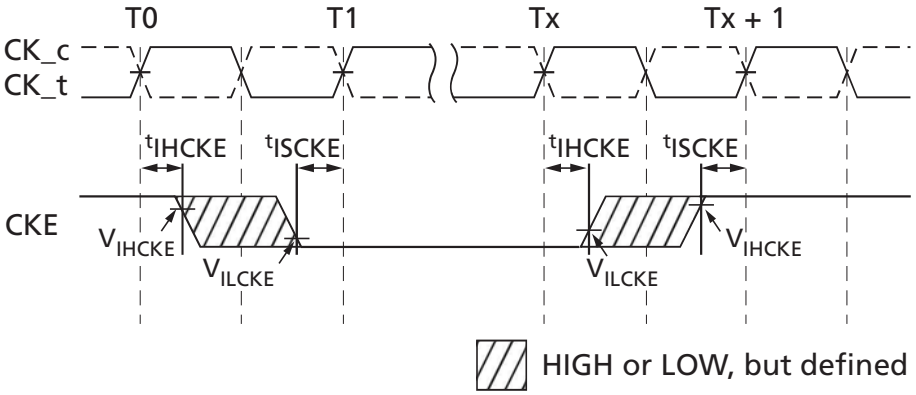
The setup and hold timings shown in the figures below apply for all commands.

Figure 11: Command and Input Setup and Hold



Note: 1. Setup and hold conditions also apply to the CKE pin. For timing diagrams related to the CKE pin, see the Power-Down section.

Figure 12: CKE Input Setup and Hold



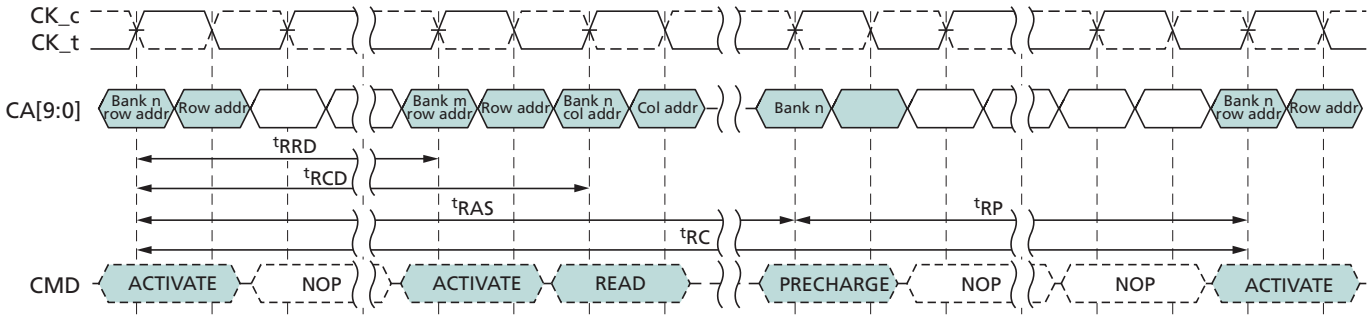
Notes: 1. After CKE is registered LOW, the CKE signal level is maintained below V_{ILCKE} for ^{t}CKE specification (LOW pulse width).
2. After CKE is registered HIGH, the CKE signal level is maintained above V_{IHCKE} for ^{t}CKE (HIGH pulse width).

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ACTIVATE Command

The ACTIVATE command is issued by holding CS_n LOW, CA0 LOW, and CA1 HIGH at the rising edge of the clock. The bank addresses BA[2:0] are used to select the desired bank. Row addresses are used to determine which row to activate in the selected bank. The ACTIVATE command must be applied before any READ or WRITE operation can be executed. The device can accept a READ or WRITE command at ^{t}RCD after the ACTIVATE command is issued. After a bank has been activated, it must be precharged before another ACTIVATE command can be applied to the same bank. The bank active and precharge times are defined as ^{t}RAS and ^{t}RP, respectively. The minimum time interval between successive ACTIVATE commands to the same bank is determined by the RAS cycle time of the device (^{t}RC). The minimum time interval between ACTIVATE commands to different banks is ^{t}RRD.

Figure 13: ACTIVATE Command



Note: 1. A PRECHARGE ALL command uses ^{t}RPab timing, and a single-bank PRECHARGE command uses ^{t}RPpb timing. In this figure, ^{t}RP denotes either an all-bank PRECHARGE or a single-bank PRECHARGE.

8-Bank Device Operation

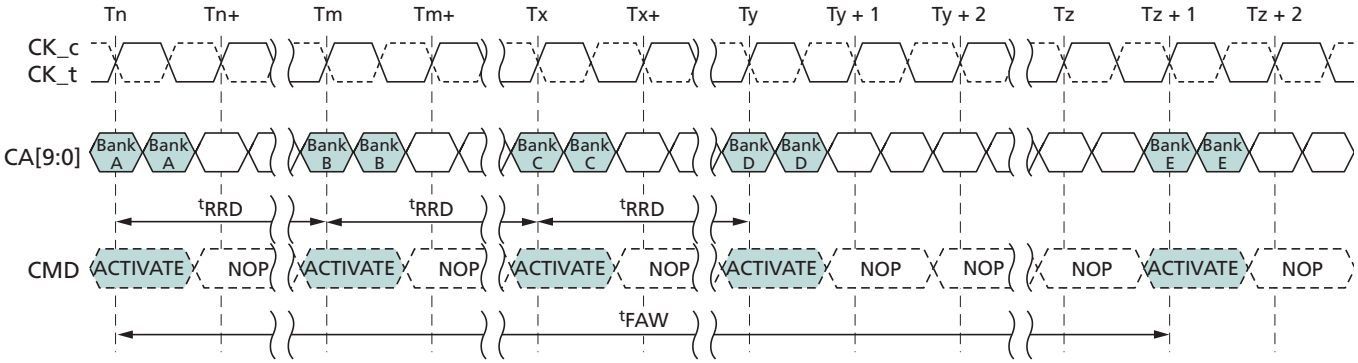
Certain restrictions must be taken into consideration when operating 8-bank devices; one restricts the number of sequential ACTIVATE commands that can be issued and one provides additional RAS precharge time for a PRECHARGE ALL command.

The 8-Bank Device Sequential Bank Activation Restriction: No more than four banks can be activated (or refreshed, in the case of REFpb) in a rolling ^{t}FAW window. The number of clocks in a ^{t}FAW period depends on the clock frequency, which may vary. If the clock frequency is not changed over this period, convert to clocks by dividing ^{t}FAW[ns] by ^{t}CK[ns] and then rounding up to the next integer value. As an example of the rolling window, if RU(^{t}FAW/^{t}CK) is 10 clocks, and an ACTIVATE command is issued in clock *n*, no more than three further ACTIVATE commands can be issued at or between clock *n* + 1 and *n* + 9. REFpb also counts as bank activation for purposes of ^{t}FAW. If the clock is changed during the ^{t}FAW period, the rolling ^{t}FAW window may be calculated in clock cycles by adding together the time spent in each clock period. The ^{t}FAW requirement is met when the previous *n* clock cycles exceeds the ^{t}FAW time.

The 8-Bank Device PRECHARGE ALL Provision: ^{t}RP for a PRECHARGE ALL command must equal ^{t}RPab, which is greater than ^{t}RPpb.

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Figure 14: tFAW Timing



Read and Write Access Modes

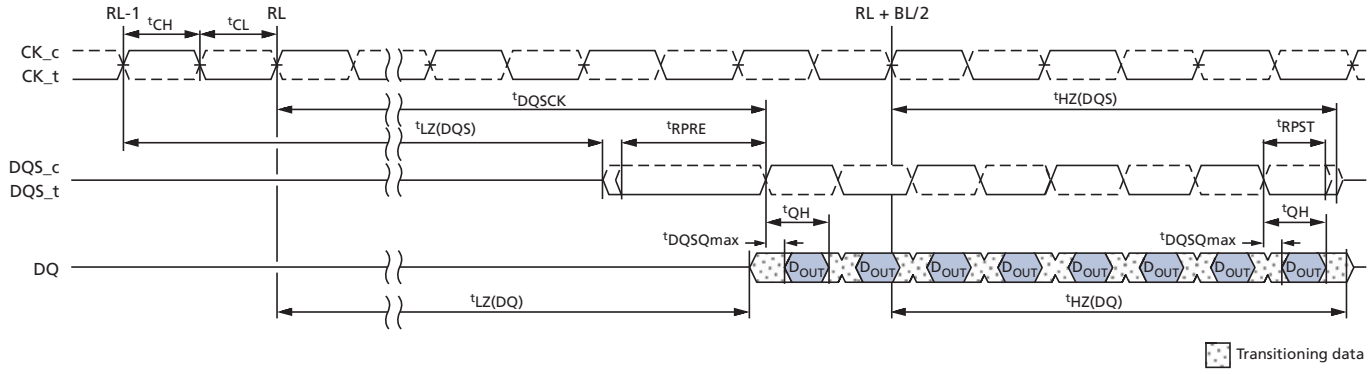
After a bank is activated, a READ or WRITE command can be issued with CS_n LOW, CA0 HIGH, and CA1 LOW at the rising edge of the clock. CA2 must also be defined at this time to determine whether the access cycle is a READ operation (CA2 HIGH) or a WRITE operation (CA2 LOW). A single READ or WRITE command initiates a burst READ or burst WRITE operation on successive clock cycles. Burst interrupts are not allowed.

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Burst READ Command

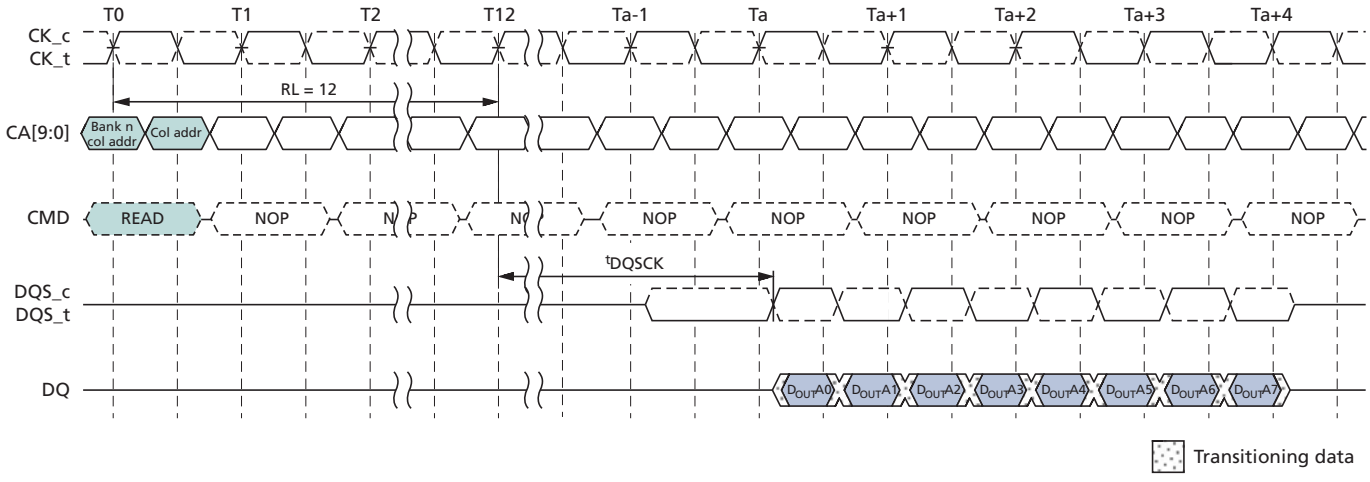
The burst READ command is initiated with CS_n LOW, CA0 HIGH, CA1 LOW, and CA2 HIGH at the rising edge of the clock. The command address bus inputs, CA5r–CA6r and CA1f–CA9f, determine the starting column address for the burst. The read latency (RL) is defined from the rising edge of the clock on which the READ command is issued to the rising edge of the clock from which the ^{t}DQSCK delay is measured. The first valid data is available RL × ^{t}CK + ^{t}DQSCK + ^{t}DQSQ after the rising edge of the clock when the READ command is issued. The data strobe output is driven LOW ^{t}RPRE before the first valid rising strobe edge. The first bit of the burst is synchronized with the first rising edge of the data strobe. Each subsequent data-out appears on each DQ pin, edge-aligned with the data strobe. The RL is programmed in the mode registers. Pin input timings for the data strobe are measured relative to the crosspoint of DQS_t and its complement, DQS_c.

Figure 15: READ Output Timing



Note: 1. ^{t}DQSCK can span multiple clock periods.

Figure 16: Burst READ – RL = 12, BL = 8, ^{t}DQSCK > ^{t}CK



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Figure 17: Burst READ – RL = 12, BL = 8, ^{t}DQSCK < ^{t}CK

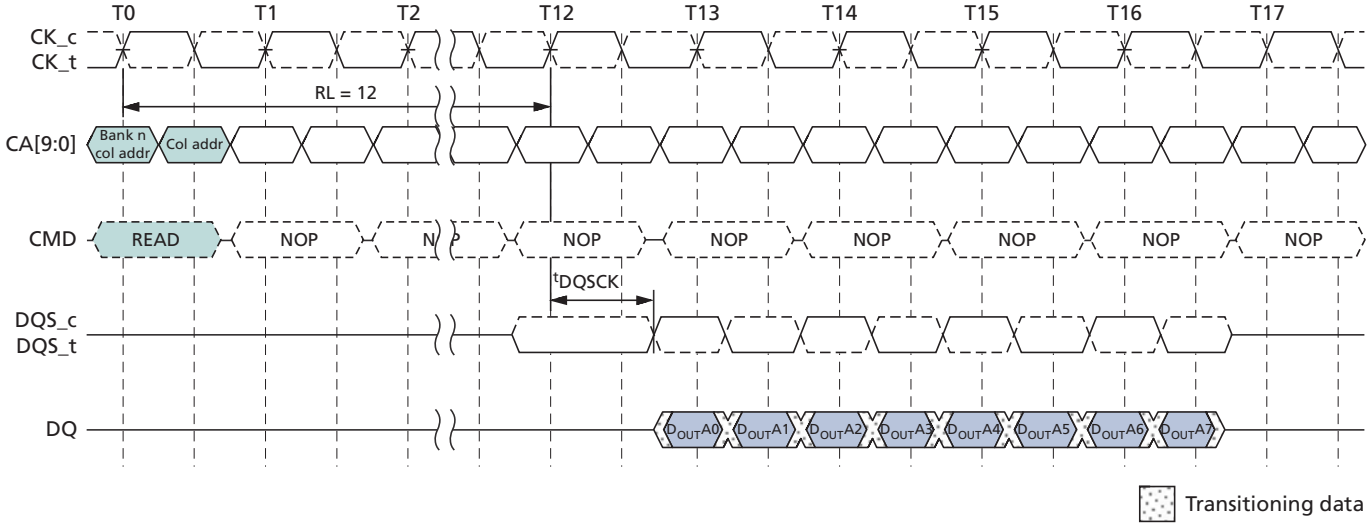
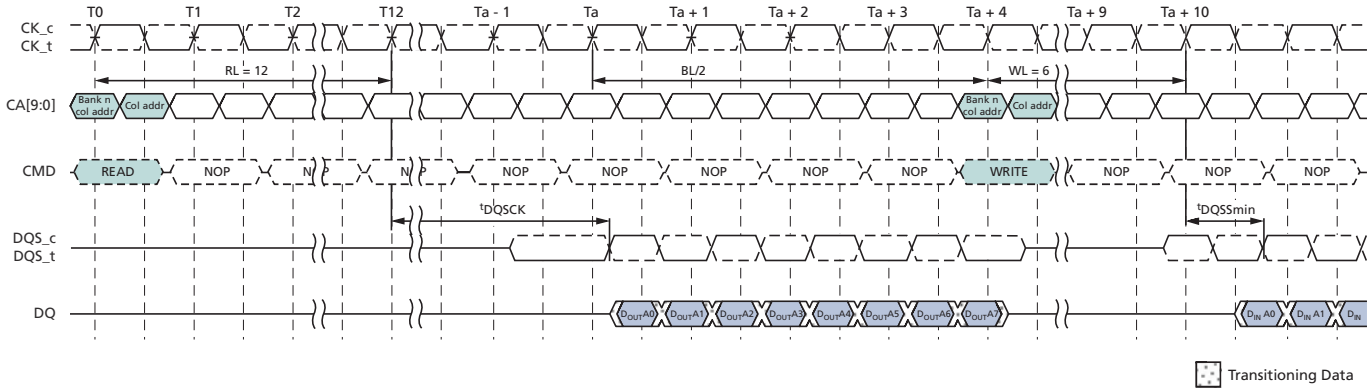


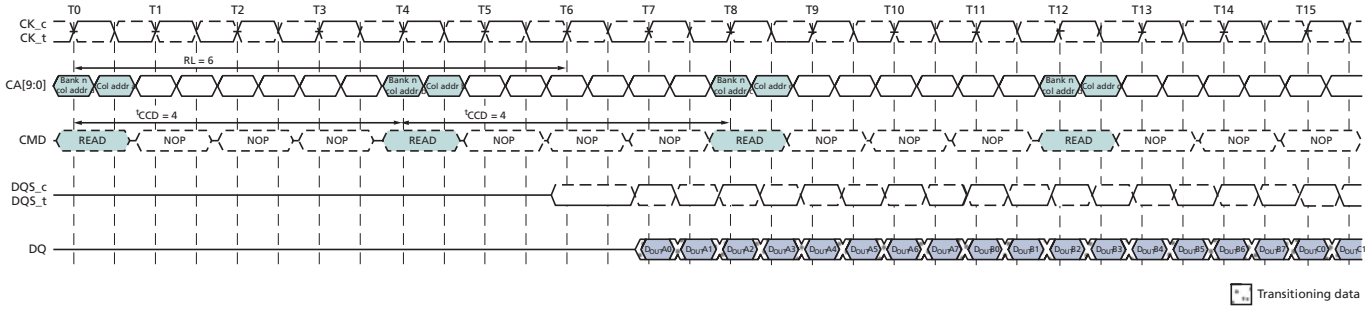
Figure 18: Burst READ Followed by Burst WRITE – RL = 12, WL = 6, BL = 8



The minimum time from the burst READ command to the burst WRITE command is defined by the read latency (RL) and the burst length (BL). Minimum READ-to-WRITE latency is RL + RU(^{t}DQSCK(MAX)/^{t}CK) + BL/2 + 1 - WL clock cycles.

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Figure 19: Seamless Burst READ – RL = 6, BL = 8, tCCD = 4



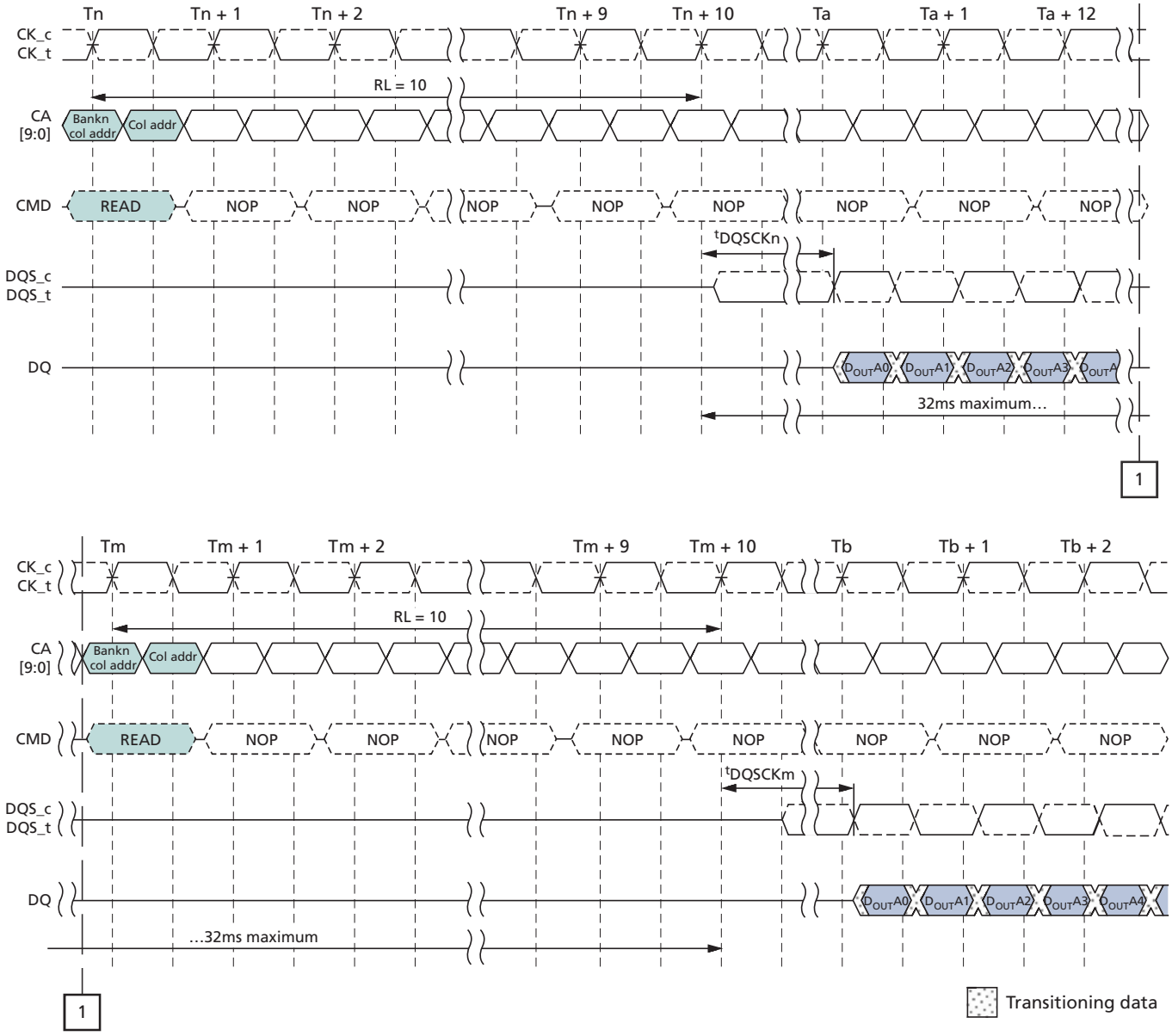
The seamless burst READ operation is supported by enabling a READ command at every fourth clock cycle for BL = 8 operation. This operation is supported as long as the banks are activated, whether the accesses read the same or different banks.

tDQSCK Delta Timing

To allow the system to track variations in tDQSCK output across multiple clock cycles, three parameters are provided: tDQSCKDL (delta long), tDQSCKDM (delta medium), and tDQSCKDS (delta short). Each of these parameters defines the change in tDQSCK over a short, medium, or long rolling window, respectively. The definition for each tDQSCK-delta parameter is shown in the figures below.

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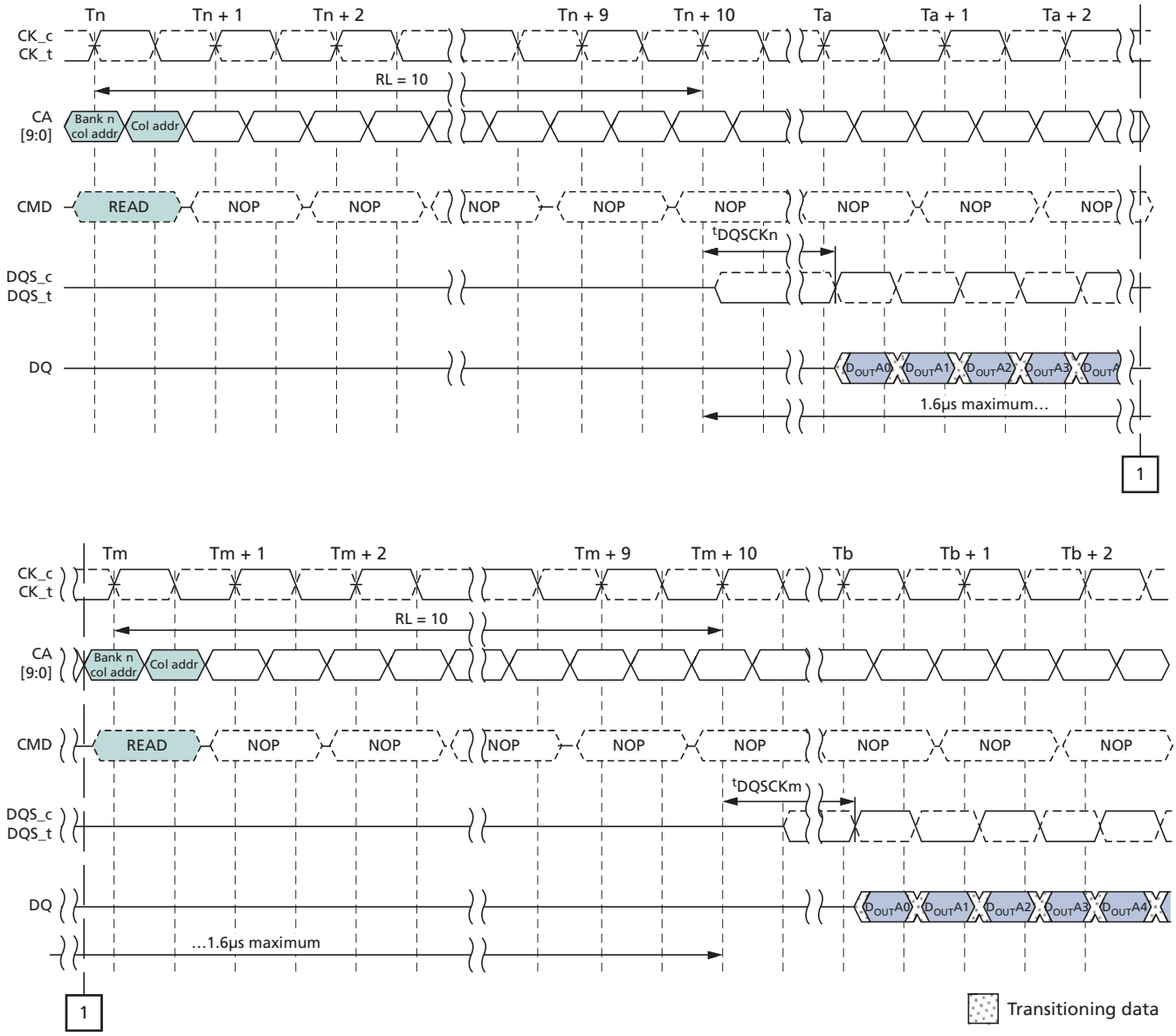
Figure 20: tDQSCKDL Timing



Notes:
1. tDQSCKDL = (tDQSCK*n* - tDQSCK*m*).
2. tDQSCKDL (MAX) is defined as the maximum of ABS (tDQSCK*n* - tDQSCK*m*) for any (tDQSCK*n*, tDQSCK*m*) pair within any 32ms rolling window.

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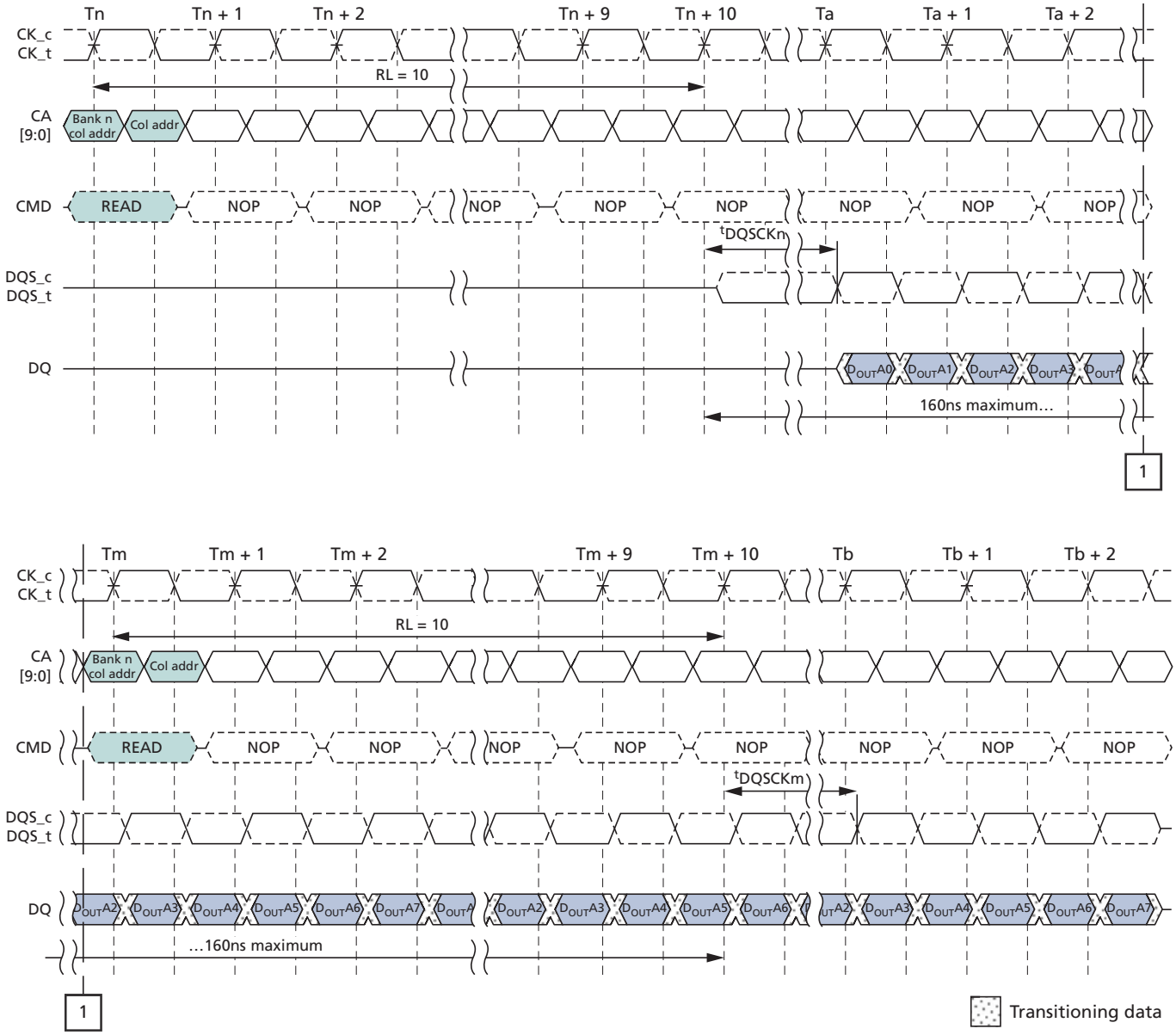
Figure 21: tDQSCKDM Timing



Notes:
1. tDQSCKDM = (tDQSCK*n* - tDQSCK*m*).
2. tDQSCKDM (MAX) is defined as the maximum of ABS (tDQSCK*n* - tDQSCK*m*) for any (tDQSCK*n*, tDQSCK*m*) pair within any 1.6µs rolling window.

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Figure 22: tDQSCKDS Timing



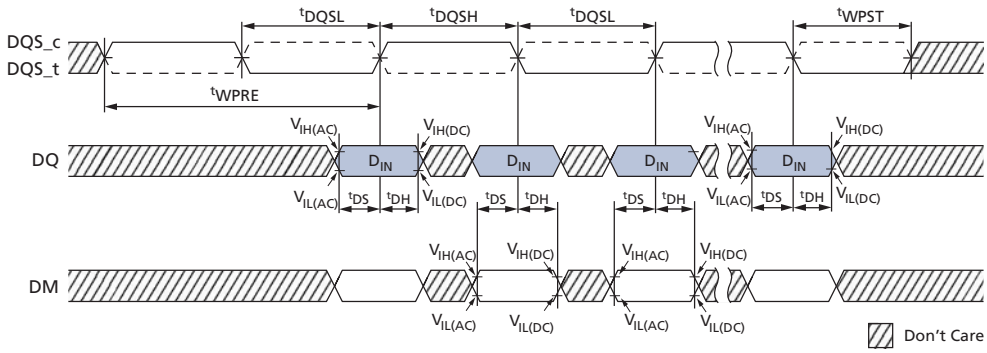
Notes:
1. tDQSCKDS = (tDQSCK*n* - tDQSCK*m*).
2. tDQSCKDS (MAX) is defined as the maximum of ABS (tDQSCK*n* - tDQSCK*m*) for any (tDQSCK*n*, tDQSCK*m*) pair for READs within a consecutive burst, within any 160ns rolling window.

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Burst WRITE Command

The burst WRITE command is initiated with CS_n LOW, CA0 HIGH, CA1 LOW, and CA2 LOW at the rising edge of the clock. The command address bus inputs, CA5r–CA6r and CA1f–CA9f, determine the starting column address for the burst. Write latency (WL) is defined from the rising edge of the clock on which the WRITE command is issued to the rising edge of the clock from which the ^{t}DQSS delay is measured. The first valid data must be driven WL × ^{t}CK + ^{t}DQSS from the rising edge of the clock from which the WRITE command is issued. The data strobe signals (DQS) must be driven as shown in Figure 25 (page 56). The burst cycle data bits must be applied to the DQ pins ^{t}DS prior to the associated edge of the DQS and held valid until ^{t}DH after that edge. Burst data is sampled on successive edges of the DQS_t until the burst length is completed. After a burst WRITE operation, ^{t}WR must be satisfied before a PRECHARGE command to the same bank can be issued. Pin input timings are measured relative to the crosspoint of DQS_t and its complement, DQS_c.

Figure 23: Data Input (WRITE) Timing



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Figure 24: Burst WRITE

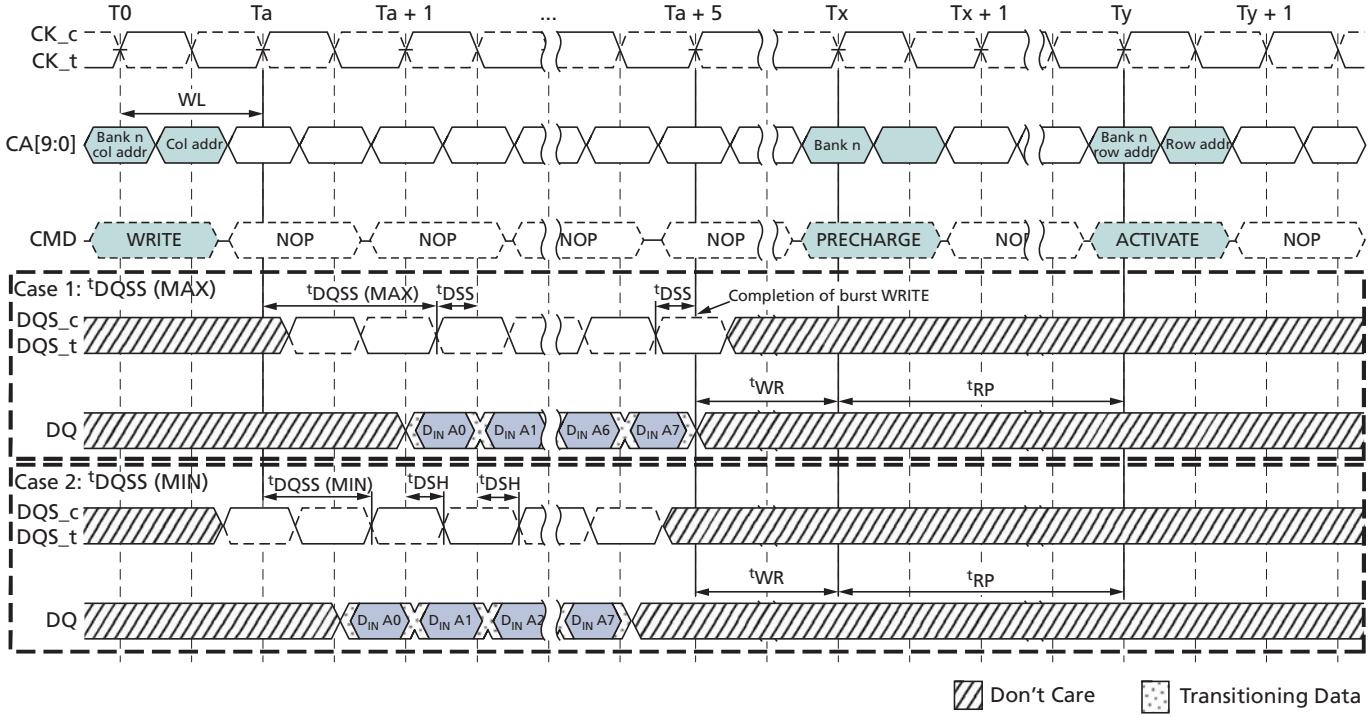
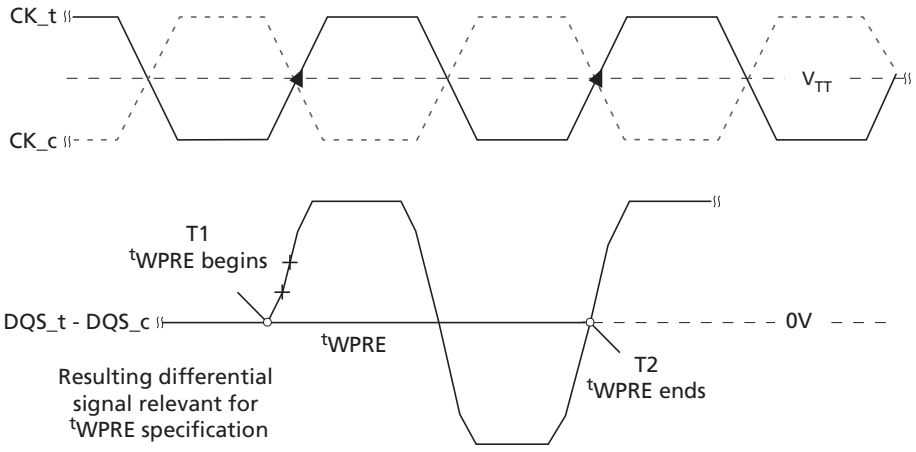


Figure 25: Method for Calculating tWPRE Transitions and Endpoints



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Figure 26: Method for Calculating tWPST Transitions and Endpoints

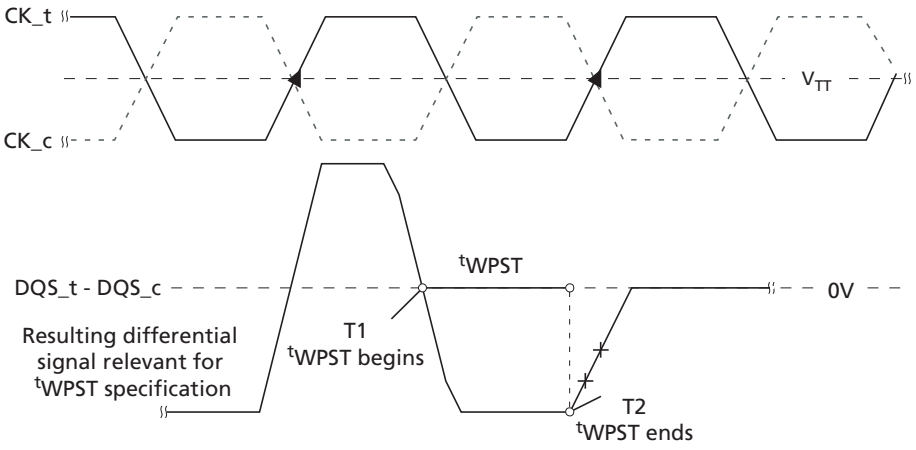
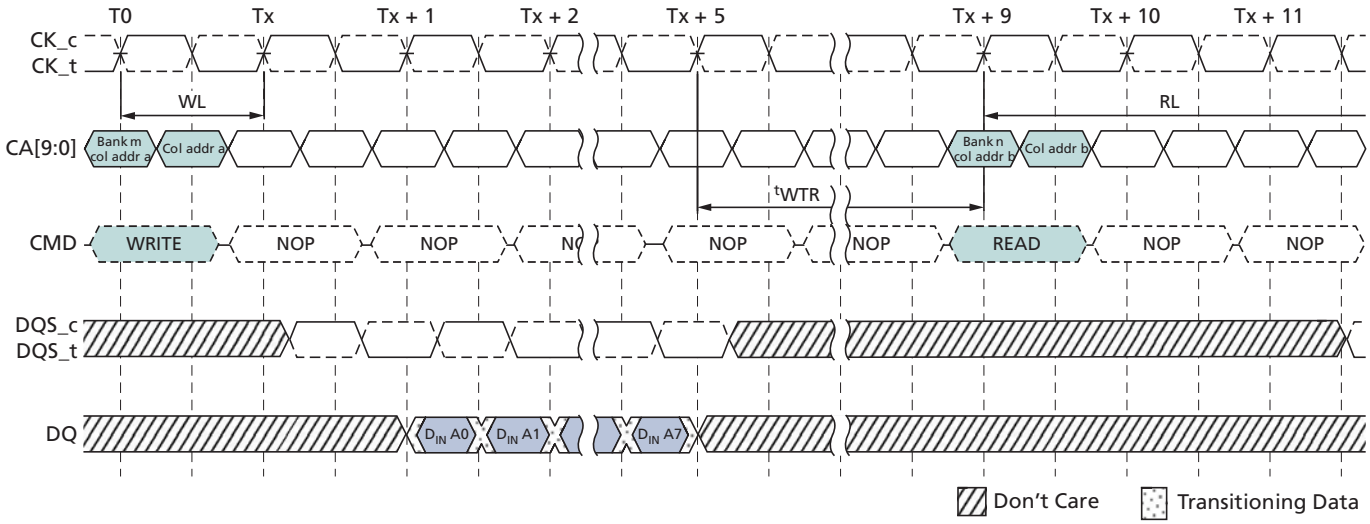


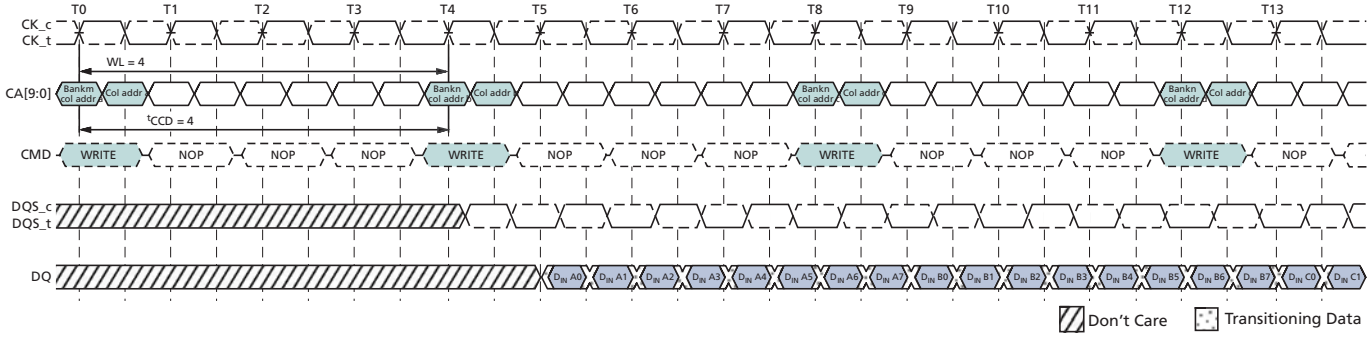
Figure 27: Burst WRITE Followed by Burst READ



Notes:
1. The minimum number of clock cycles from the burst WRITE command to the burst READ command for any bank is [WL + 1 + BL/2 + RU(tWTR/tCK)].
2. tWTR starts at the rising edge of the clock after the last valid input data.

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Figure 28: Seamless Burst WRITE – WL = 4, BL = 8, ^{t}CCD = 4



Note: 1. The seamless burst WRITE operation is supported by enabling a WRITE command every four clocks for BL = 8 operation. This operation is supported for any activated bank.

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Write Data Mask

LPDDR3 devices support one write data mask (DM) pin for each data byte (DQ), which is consistent with LPDDR2 devices. Each DM can mask its respective DQ for any given cycle of the burst. Data mask timings match data bit timing, but are inputs only. Internal data mask loading is identical to data bit loading to ensure matched system timing.

Figure 29: Data Mask Timing

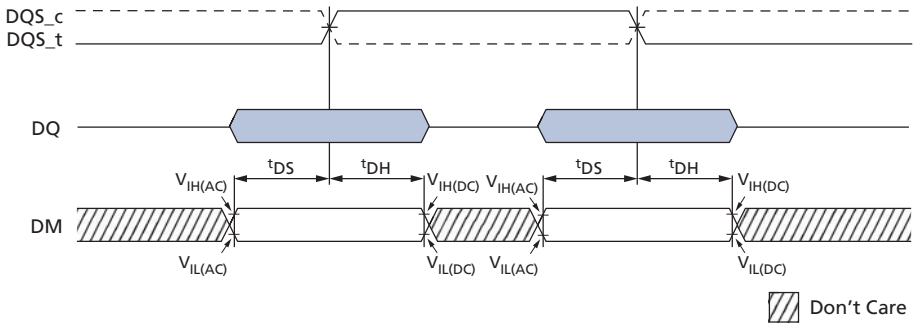
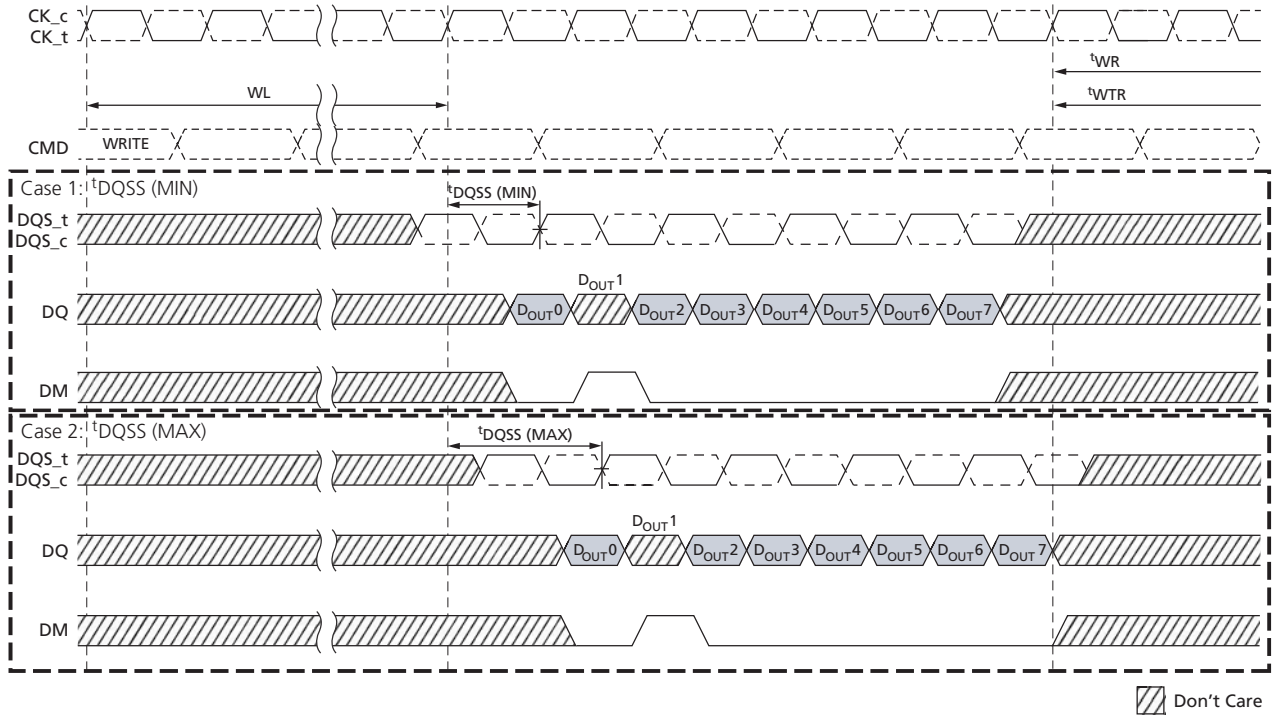


Figure 30: Write Data Mask – Second Data Bit Masked



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PRECHARGE Command

The PRECHARGE command is used to precharge or close a bank that has been activated. The PRECHARGE command is initiated with CS_n LOW, CA0 HIGH, CA1 HIGH, CA2 LOW, and CA3 HIGH at the rising edge of the clock. The PRECHARGE command can be used to precharge each bank independently or all banks simultaneously. The AB flag and the bank address bits BA0, BA1, and BA2 are used to determine which bank(s) to precharge. The precharged bank(s) will be available for subsequent row access ^{t}RPab after an all-bank PRECHARGE command is issued, or ^{t}RPpb after a single-bank PRECHARGE command is issued.

To ensure that LPDDR3 devices can meet the instantaneous current demand required to operate, the row precharge time (^{t}RP) for an all bank PRECHARGE (^{t}RPab) will be longer than the row precharge time for a single-bank PRECHARGE (^{t}RPpb). ACTIVATE to PRECHARGE timing is shown in the ACTIVATE Command figure.

Table 50: Bank Selection for PRECHARGE by Address Bits

AB (CA4r)	BA2 (CA9r)	BA1 (CA8r)	BA0 (CA7r)	Precharged Bank(s) 8-Bank Device
0	0	0	0	Bank 0 only
0	0	0	1	Bank 1 only
0	0	1	0	Bank 2 only
0	0	1	1	Bank 3 only
0	1	0	0	Bank 4 only
0	1	0	1	Bank 5 only
0	1	1	0	Bank 6 only
0	1	1	1	Bank 7 only
1	Don't Care	Don't Care	Don't Care	All banks

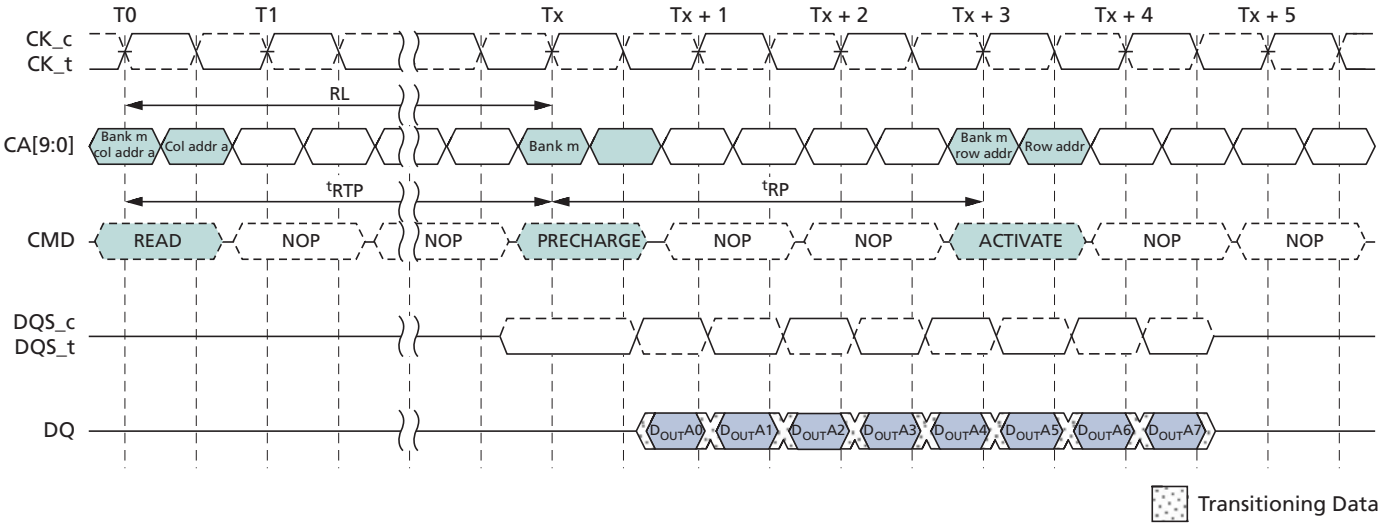
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Burst READ Operation Followed by PRECHARGE

For the earliest possible precharge, the PRECHARGE command can be issued BL/2 clock cycles after a READ command. A new bank ACTIVATE command can be issued to the same bank after the row precharge time (^{t}RP) has elapsed. A PRECHARGE command cannot be issued until after ^{t}RAS is satisfied.

For LPDDR3 devices, the minimum READ-to-PRECHARGE time (^{t}RTP) must also satisfy a minimum analog time from the rising clock edge that initiates the last 8-bit prefetch of a READ command. ^{t}RTP begins BL/2 - 4 clock cycles after the READ command. For LPDDR3 READ-to-PRECHARGE timings, see the PRECHARGE and Auto Precharge Clarification table.

Figure 31: Burst READ Followed by PRECHARGE – BL = 8, RU(^{t}RTP(MIN)/^{t}CK) = 2



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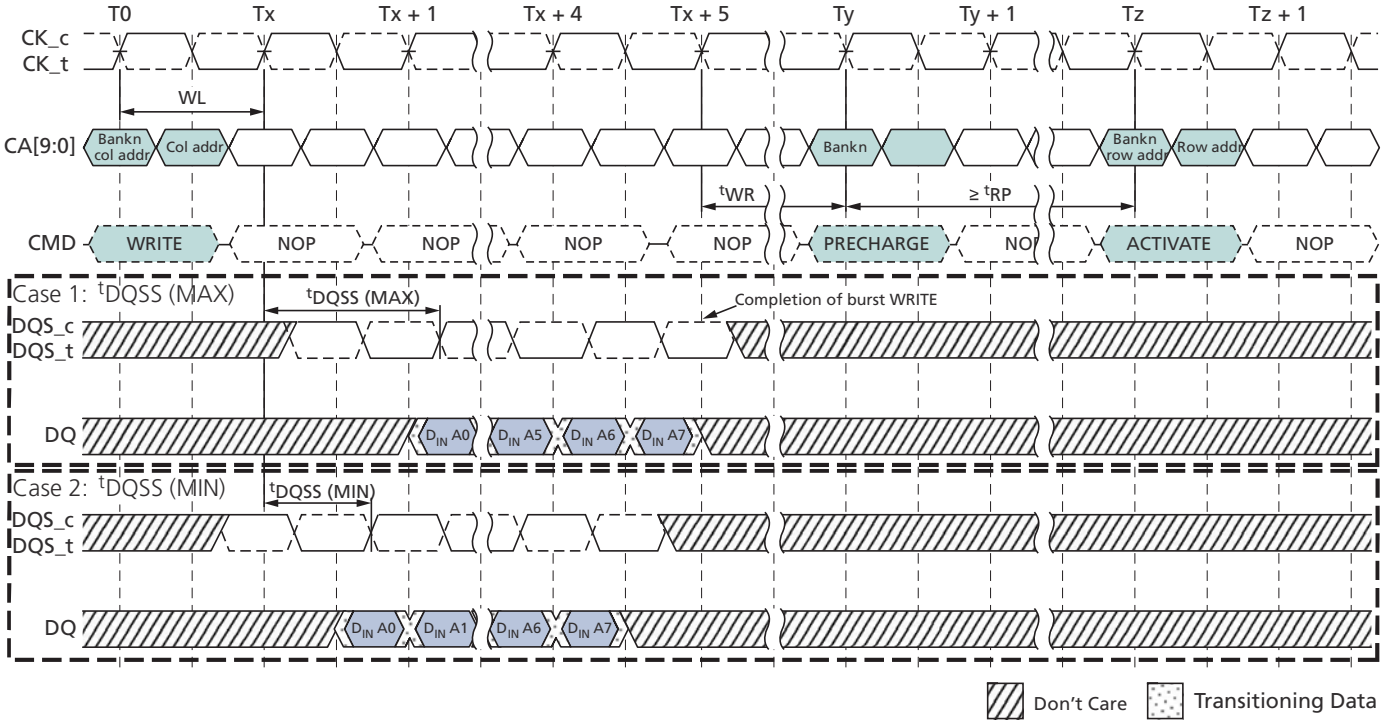
Burst WRITE Followed by PRECHARGE

For WRITE cycles, a WRITE recovery time (^{t}WR) must be provided before a PRECHARGE command can be issued. This delay is referenced from the last valid burst input data to the completion of the burst WRITE. The PRECHARGE command must not be issued prior to the ^{t}WR delay. For LPDDR3 WRITE-to-PRECHARGE timings, see the PRECHARGE and Auto Precharge Clarification table.

LPDDR3 devices write data to the array in prefetch multiples (prefetch = 8). An internal WRITE operation can begin only after a prefetch group has been completely latched, so ^{t}WR starts at prefetch bondaries.

The minimum WRITE-to-PRECHARGE time for commands to the same bank is WL + BL/2 + 1 + RU(^{t}WR/^{t}CK) clock cycles.

Figure 32: Burst WRITE Followed by PRECHARGE – BL = 8



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Auto Precharge

Before a new row can be opened in an active bank, the active bank must be precharged using either the PRECHARGE command or the auto precharge function. When a READ or WRITE command is issued to the device, the AP bit (CA0f) can be set to enable the active bank to automatically begin precharge at the earliest possible moment during the burst READ or WRITE cycle.

If AP is LOW when the READ or WRITE command is issued, a normal READ or WRITE burst operation is executed and the bank remains active at the completion of the burst.

If AP is HIGH when the READ or WRITE command is issued, the auto precharge function is engaged. This feature enables the PRECHARGE operation to be partially or completely hidden during burst READ cycles (dependent upon READ or WRITE latency), thus improving system performance for random data access.

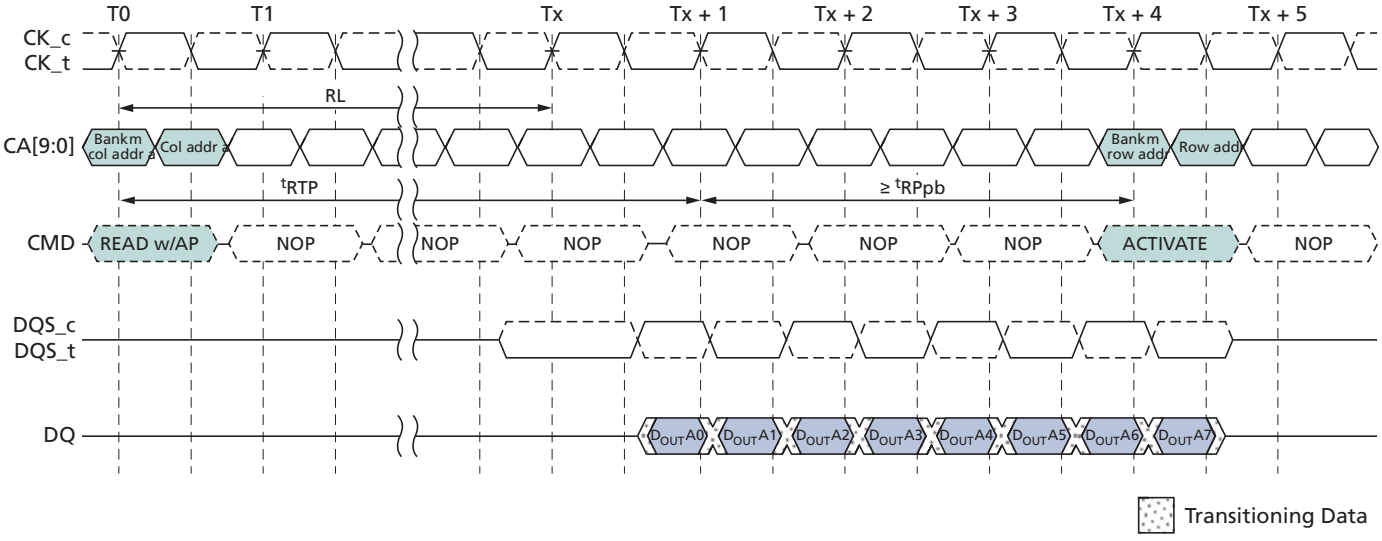
Burst READ with Auto Precharge

If AP (CA0f) is HIGH when a READ command is issued, the READ with auto precharge function is engaged. The device starts an auto precharge on the rising edge of the clock, BL/2 or BL/2 - 4 + RU(^{t}RTP/^{t}CK) clock cycles later than the READ with auto precharge command, whichever is greater. For LPDDR3 auto precharge calculations, see the PRECHARGE and Auto Precharge Clarification table.

Following an auto precharge operation, an ACTIVATE command can be issued to the same bank if the following two conditions are satisfied simultaneously:

- The RAS precharge time (^{t}RP) has been satisfied from the clock at which the auto precharge begins.
- The RAS cycle time (^{t}RC) from the previous bank activation has been satisfied.

Figure 33: LPDDR3 – Burst READ with Auto Precharge



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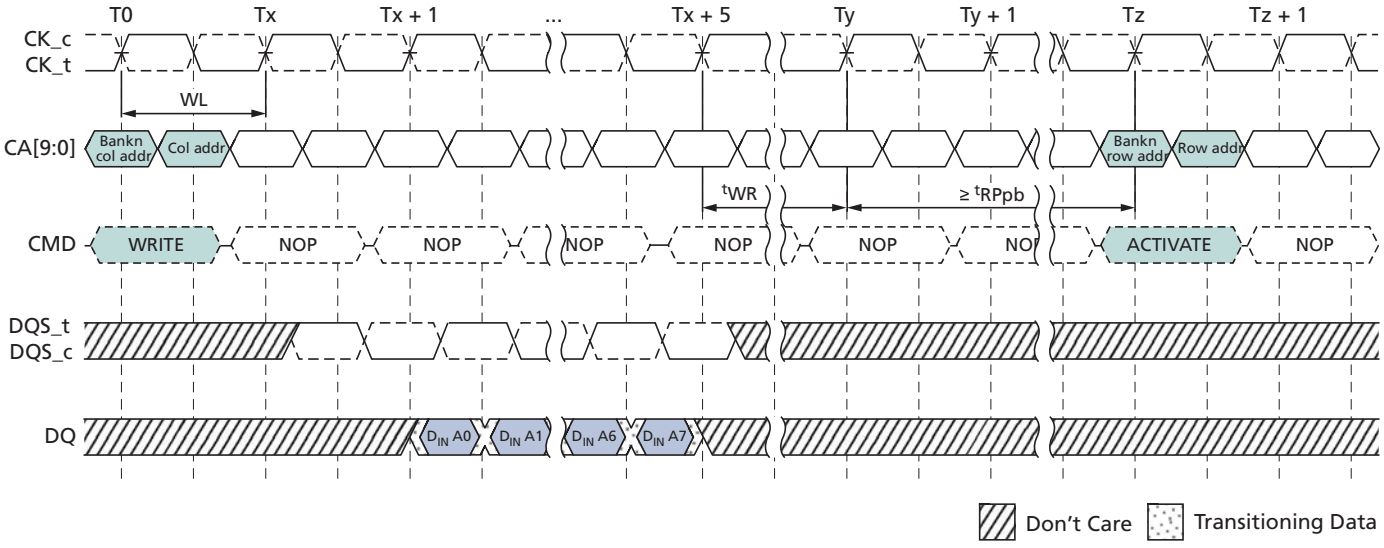
Burst WRITE with Auto Precharge

If AP (CA0f) is HIGH when a WRITE command is issued, the WRITE with auto precharge function is engaged. The device starts an auto precharge at the clock rising edge ^{t}WR cycles after the completion of the burst WRITE.

Following a WRITE with auto precharge, an ACTIVATE command can be issued to the same bank if the following two conditions are met:

- The RAS precharge time (^{t}RP) has been satisfied from the clock at which the auto precharge begins.
- The RAS cycle time (^{t}RC) from the previous bank activation has been satisfied.

Figure 34: Burst WRITE with Auto Precharge – BL = 8



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Table 51: PRECHARGE and Auto Precharge Clarification

From Command	To Command	Minimum Delay Between Commands	Unit	Notes
READ	PRECHARGE to same bank as READ	BL/2 + MAX (4, RU(^{t}RTP/^{t}CK)) - 4	CLK	1
	PRECHARGE ALL	BL/2 + MAX (4, RU(^{t}RTP/^{t}CK)) - 4		1
READ w/AP	PRECHARGE to same bank as READ w/AP	BL/2 + MAX (4, RU(^{t}RTP/^{t}CK)) - 4	CLK	1, 2
	PRECHARGE ALL	BL/2 + MAX(4, RU(^{t}RTP/^{t}CK)) - 4		1
	ACTIVATE to same bank as READ w/AP	BL/2 + MAX(4, RU(^{t}RTP/^{t}CK)) - 4 + RU(^{t}RPpb/^{t}CK)		1
	WRITE or WRITE w/AP (same bank)	Illegal		3
	WRITE or WRITE w/AP (different bank)	RL + BL/2 + RU(^{t}DQSCKmax/^{t}CK) - WL + 1		3
	READ or READ w/AP (same bank)	Illegal		3
	READ or READ w/AP (different bank)	BL/2		3
WRITE	PRECHARGE to same bank as WRITE	WL + BL/2 + RU(^{t}WR/^{t}CK) + 1	CLK	1
	PRECHARGE ALL	WL + BL/2 + RU(^{t}WR/^{t}CK) + 1		1
WRITE w/AP	PRECHARGE to same bank as WRITE w/AP	WL + BL/2 + RU(^{t}WR/^{t}CK) + 1	CLK	1
	PRECHARGE ALL	WL + BL/2 + RU(^{t}WR/^{t}CK) + 1		1
	ACTIVATE to same bank as WRITE w/AP	WL + BL/2 + RU(^{t}WR/^{t}CK) + 1 + RU(^{t}RPpb/^{t}CK)		1
	WRITE or WRITE w/AP (same bank)	Illegal		3
	WRITE or WRITE w/AP (different bank)	BL/2		3
	READ or READ w/AP (same bank)	Illegal		3
	READ or READ w/AP (different bank)	WL + BL/2 + RU(^{t}WTR/^{t}CK) + 1		3
PRECHARGE	PRECHARGE to same bank as PRECHARGE	1	CLK	1
	PRECHARGE ALL	1		1
PRECHARGE ALL	PRECHARGE	1	CLK	1
	PRECHARGE ALL	1		1

Notes:
1. For a given bank, the PRECHARGE period should be counted from the latest PRECHARGE command, which will be either a one-bank PRECHARGE command or a PRECHARGE ALL command, issued to that bank. The PRECHARGE period is satisfied after ^{t}RP, depending on the latest PRECHARGE command issued to that bank.
2. Any command issued during the specified minimum delay time is illegal.
3. After a READ with auto precharge command, seamless READ operations to different banks are supported. After a WRITE with auto precharge command, seamless WRITE operations to different banks are supported. READ with auto precharge and WRITE with auto precharge commands must not be interrupted or truncated.

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REFRESH Command

The REFRESH command is initiated with CS_n LOW, CA0 LOW, CA1 LOW, and CA2 HIGH at the rising edge of the clock. Per-bank REFRESH is initiated with CA3 LOW at the rising edge of the clock. All-bank REFRESH is initiated with CA3 HIGH at the rising edge of the clock.

A per-bank REFRESH command (REFpb) performs a per-bank REFRESH operation to the bank scheduled by the bank counter in the memory device. The bank sequence for per-bank REFRESH is fixed to be a sequential round-robin: 0-1-2-3-4-5-6-7-0-1-.... The bank count is synchronized between the controller and the SDRAM by resetting the bank count to zero. Synchronization can occur upon issuing a RESET command or at every exit from self refresh.

A bank must be idle before it can be refreshed. The controller must track the bank being refreshed by the per-bank REFRESH command.

The REFpb command must not be issued to the device until the following conditions have been met (see the REFRESH Command Scheduling Separation Requirements table):

- ^{t}RFCab has been satisfied after the prior REFab command
- ^{t}RFCpb has been satisfied after the prior REFpb command
- ^{t}RP has been satisfied after the prior PRECHARGE command to that bank
- ^{t}RRD has been satisfied after the prior ACTIVATE command (if applicable, for example after activating a row in a different bank than the one affected by the REFpb command)

The target bank is inaccessible during per-bank REFRESH cycle time (^{t}RFCpb); however, other banks within the device are accessible and can be addressed during the cycle. During the REFpb operation, any of the banks other than the one being refreshed can be maintained in an active state or accessed by a READ or WRITE command. When the per-bank REFRESH cycle has completed, the affected bank will be in the idle state.

After issuing REFpb, the following conditions must be met (see the REFRESH Command Scheduling Separation Requirements table):

- ^{t}RFCpb must be satisfied before issuing a REFab command
- ^{t}RFCpb must be satisfied before issuing an ACTIVATE command to the same bank
- ^{t}RRD must be satisfied before issuing an ACTIVATE command to a different bank
- ^{t}RFCpb must be satisfied before issuing another REFpb command

An all-bank REFRESH command (REFab) issues a REFRESH command to all banks. All banks must be idle when REFab is issued (for instance, by issuing a PRECHARGE ALL command prior to issuing an all-bank REFRESH command). REFab also synchronizes the bank count between the controller and the SDRAM to zero. The REFab command must not be issued to the device until the following conditions have been met (see the REFRESH Command Scheduling Separation Requirements table):

- ^{t}RFCab has been satisfied following the prior REFab command
- ^{t}RFCpb has been satisfied following the prior REFpb command
- ^{t}RP has been satisfied following the prior PRECHARGE commands

When an all-bank REFRESH cycle has completed, all banks will be idle. After issuing REFab:

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- ^{t}RFCab latency must be satisfied before issuing an ACTIVATE command
- ^{t}RFCab latency must be satisfied before issuing a REFab or REFpb command

Table 52: REFRESH Command Scheduling Separation Requirements

Symbol	Minimum Delay From	To	Notes
^{t}RFCab	REFab	REFab	
		ACTIVATE command to any bank	
		REFpb	
^{t}RFCpb	REFpb	REFab	
		ACTIVATE command to same bank as REFpb	
		REFpb	
^{t}RRD	REFpb	ACTIVATE command to a different bank than REFpb	
	ACTIVATE	REFpb	1
		ACTIVATE command to a different bank than the prior ACTIVATE command	

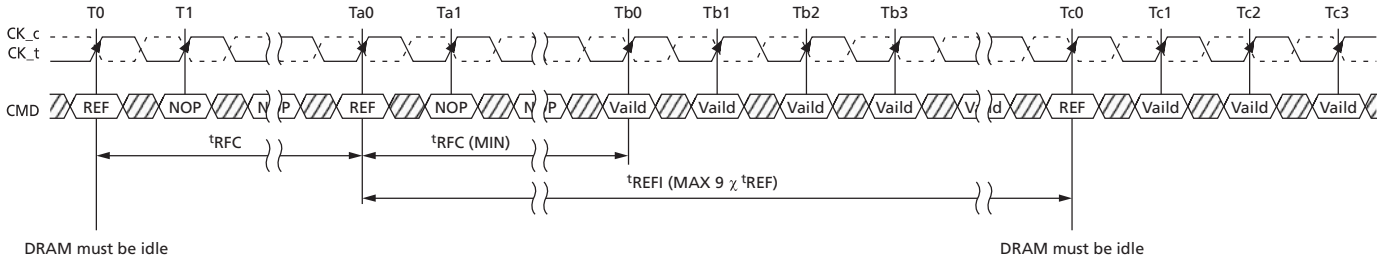
Note: 1. A bank must be in the idle state before it is refreshed, so following an ACTIVATE command REFab is prohibited. REFpb is supported only if it affects a bank that is in the idle state.

In general, an all bank REFRESH command needs to be issued to the device regularly every ^{t}REFI interval. To allow for improved efficiency in scheduling and switching between tasks, some flexibility in the absolute refresh interval is provided for postponing and pulling in the refresh command. A maximum of eight REFRESH commands can be postponed during operation of the device, but at no point in time are more than a total of eight REFRESH commands allowed to be postponed. In the case where eight REFRESH commands are postponed in a row, the resulting maximum interval between the surrounding REFRESH commands is limited to 9 × ^{t}REFI. A maximum of eight additional REFRESH commands can be issued in advance (pulled in), with each one reducing the number of regular REFRESH commands required later by one. Note that pulling in more than eight REFRESH commands in advance does not reduce the number of regular REFRESH commands required later; therefore, the resulting maximum interval between two surrounding REFRESH commands is limited to 9 x ^{t}REFI. At any given time, a maximum of 16 REFRESH commands can be issued within 2 x ^{t}REFI.

For per bank refresh, a maximum of 8 × 8 per bank REFRESH commands can be postponed or pulled in for scheduling efficiency. At any given time, a maximum of 2 × 8 × 8 per bank REFRESH commands may be issued within 2 × ^{t}REFI.

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Figure 35: REFRESH Command Timing



Notes:
1. Only NOP commands are allowed after the REFRESH command is registered until ^{t}RFC (MIN) expires.
2. The time interval between two REFRESH commands may be extended to a maximum of 9 ×^{t}REFI.

Figure 36: Postponing REFRESH Commands

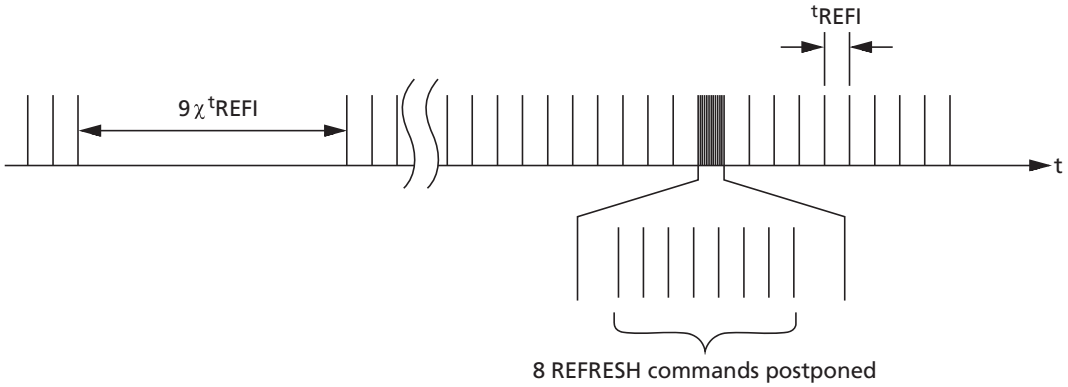
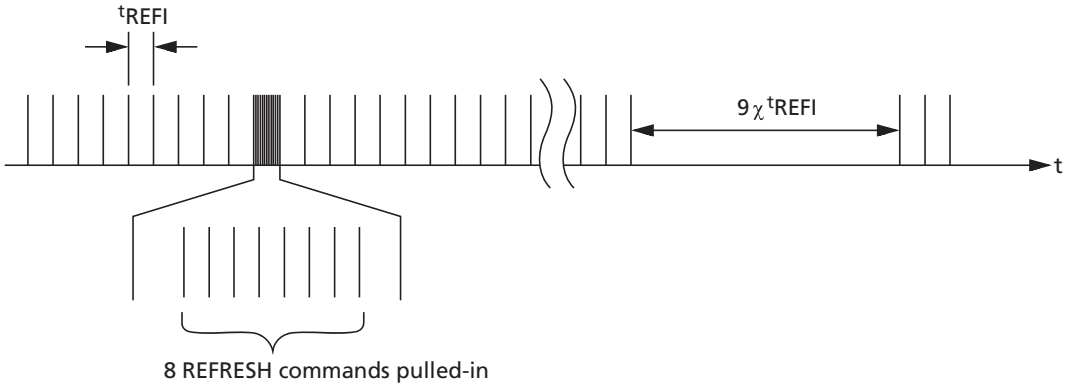


Figure 37: Pulling In REFRESH Commands



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REFRESH Requirements

Minimum REFRESH Commands

LPDDR3 requires a minimum number, R, of REFRESH (REFab) commands within any rolling refresh window (^{t}REFW = 32ms @ MR4[2:0] = 011 or $T_C \leq 85^{\circ}C$). For actual values per density and the resulting average refresh interval (^{t}REFI), see the Refresh Requirement Parameters (Per Density) table.

For ^{t}REFW and ^{t}REFI refresh multipliers at different MR4 settings, see the MR4 Device Temperature (MA[7:0] = 04h) and the MR4 Op-Code Bit Definitions tables.

When using per-bank REFRESH, a REFab command can be replaced by a full cycle of eight REFpb commands.

REFRESH Requirements and Self Refresh

Self refresh mode may be entered with a maximum of eight REFRESH commands being postponed. After exiting self refresh mode with one or more REFRESH commands postponed, additional REFRESH commands may be postponed, but the total number of postponed refresh commands (before and after the self refresh) must never exceed eight. During self refresh mode, the number of postponed or pulled-in REFRESH commands does not change.

An internally timed refresh event can be missed when CKE is raised for exit from self refresh mode. After exiting self refresh, the device requires a minimum of one extra REFRESH command before it is put back into self refresh mode.

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Figure 38: All-Bank REFRESH Operation

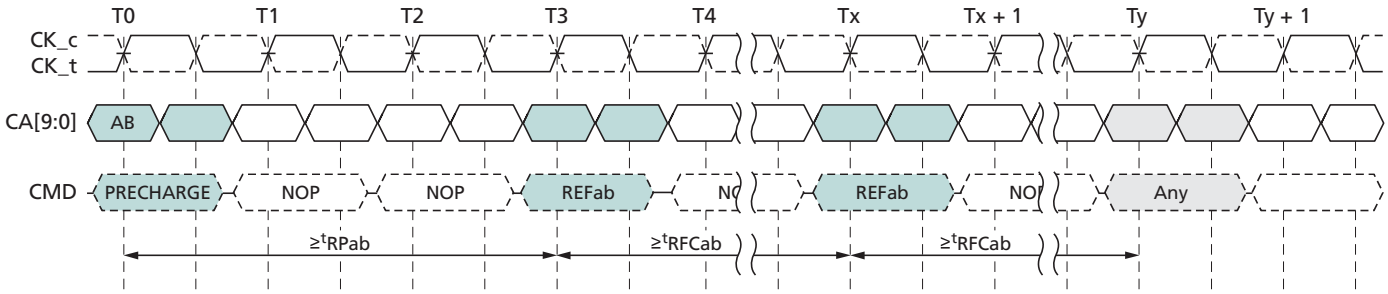
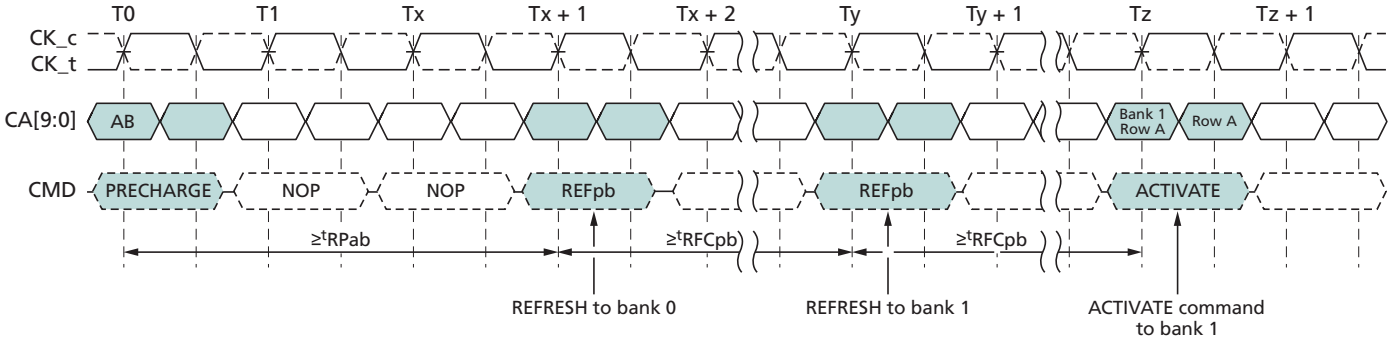


Figure 39: Per-Bank REFRESH Operation



Notes:
1. In the beginning of this example, the REFpb bank counter points to bank 0.
2. Operations to banks other than the bank being refreshed are supported during the ^{t}RFCpb period.

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SELF REFRESH Operation

The SELF REFRESH command can be used to retain data in the array, even if the rest of the system is powered-down. When in the self refresh mode, the device retains data without external clocking. The device has a built-in timer to accommodate SELF REFRESH operation. The SELF REFRESH command is executed by taking CKE LOW, CS_n LOW, CA0 LOW, CA1 LOW, and CA2 HIGH at the rising edge of the clock. CKE must be HIGH during the clock cycle preceding a SELF REFRESH command. CKE must not go LOW while MRR, MRW, READ, or WRITE operations are in progress.

To ensure that there is enough time to account for internal delay on the CKE signal path, two NOP commands are required after CKE is driven LOW; this timing period is defined as ^{t}CPDED. CKE LOW will result in deactivation of input receivers after ^{t}CPDED has expired. After the power-down command is registered, CKE must be held LOW to keep the device in self refresh mode.

Mobile LPDDR3 devices can operate in self refresh mode in both the standard and extended temperature ranges. These devices also manage self refresh power consumption when the operating temperature changes, resulting in the lowest possible power consumption across the operating temperature range. See the I_{DD} Specification Parameters and Operating Conditions table for details.

After the device has entered self refresh mode, all external signals other than CKE are "Don't Care." For proper SELF REFRESH operation, power supply pins (V_{DD1}, V_{DD2}, V_{DDQ}, and V_{DDCA}) must be at valid levels. V_{DDQ} can be turned off during self refresh. If V_{DDQ} is turned off, V_{REFDQ} must also be turned off. Prior to exiting self refresh, both V_{DDQ} and V_{REFDQ} must be within their respective minimum/maximum operating ranges (see AC and DC Operating Conditions). V_{REFDQ} can be at any level between 0 and V_{DDQ}; V_{REFCA} can be at any level between 0 and V_{DDCA} during self refresh.

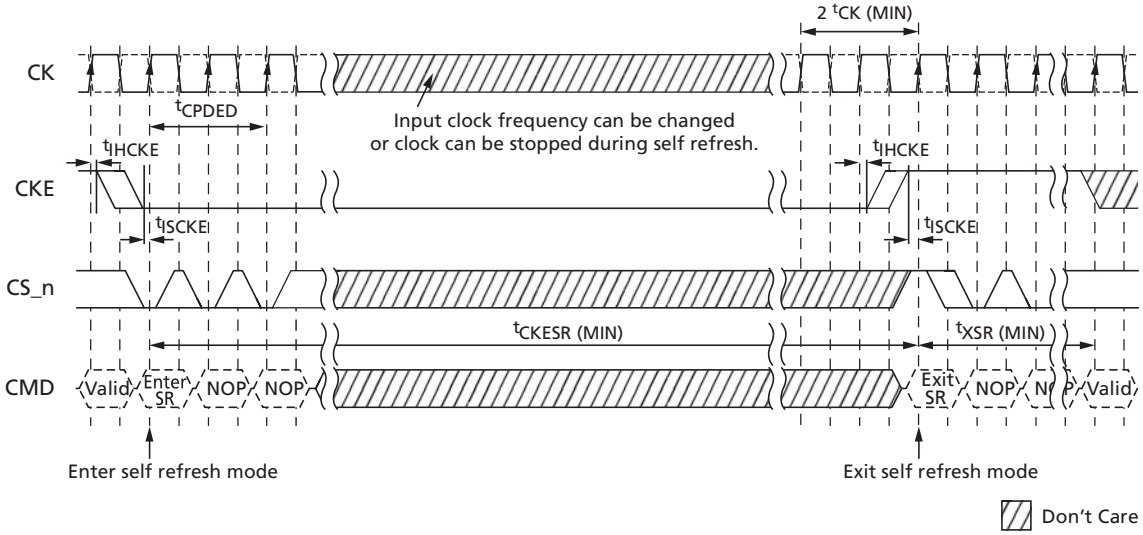
Before exiting self refresh, V_{REFDQ} and V_{REFCA} must be within specified limits (see the AC and DC Logic Input Measurement Levels for Single-Ended Signals section). After entering self refresh mode, the device initiates at least one all-bank REFRESH command internally during ^{t}CKESR. The clock is internally disabled during SELF REFRESH operation to save power. The device must remain in self refresh mode for at least ^{t}CKESR. The user can change the external clock frequency or halt the external clock one clock after self refresh entry is registered; however, the clock must be restarted and stable before the device can exit SELF REFRESH operation.

Exiting self refresh requires a series of commands. First, the clock must be stable prior to CKE returning HIGH. After the self refresh exit is registered, a minimum delay, at least equal to the self refresh exit interval (^{t}XSR), must be satisfied before a valid command can be issued to the device. This provides completion time for any internal refresh in progress. For proper operation, CKE must remain HIGH throughout ^{t}XSR. NOP commands must be registered on each rising clock edge during ^{t}XSR. For the description of ODT operation and specifications during self-refresh entry and exit, see "On Die Termination" section.

Using self refresh mode introduces the possibility that an internally timed refresh event could be missed when CKE is driven HIGH for exit from self refresh mode. Upon exiting self refresh, at least one REFRESH command (one all-bank command or eight per-bank commands) must be issued before issuing a subsequent SELF REFRESH command.

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Figure 40: SELF REFRESH Operation



Notes:
1. Input clock frequency can be changed or stopped during self refresh, provided that upon exiting self-refresh, a minimum of two cycles of stable clocks are provided, and the clock frequency is between the minimum and maximum frequencies for the particular speed grade.
2. The device must be in the all-banks-idle state prior to entering self refresh mode.
3. ^{t}XSR begins at the rising edge of the clock after CKE is driven HIGH.
4. A valid command can be issued only after ^{t}XSR is satisfied. NOPs must be issued during ^{t}XSR.

Partial-Array Self Refresh (PASR) – Bank Masking

LPDDR3 SDRAMs comprise eight banks. Each bank can be configured independently whether or not a SELF REFRESH operation will occur in that bank. One 8-bit mode register (accessible via the MRW command) is assigned to program the bank-masking status of each bank up to eight banks. For bank-masking bit assignments, see the MR16 PASR Bank Mask (MA[7:0] = 010h) and MR16 Op-Code Bit Definitions tables.

The mask bit to the bank enables or disables a refresh operation of the entire memory space within the bank. If a bank is masked using the bank-mask register, a REFRESH operation to the entire bank is blocked, and bank data retention is not guaranteed in self refresh mode. To enable a REFRESH operation to a bank, the corresponding bank mask bit must be programmed as "unmasked." When a bank mask bit is unmasked, the array space being refreshed within that bank is determined by the programmed status of the segment mask bits.

Partial-Array Self Refresh – Segment Masking

Programming segment-mask bits is similar to programming bank-mask bits. Eight segments are used for masking (see the MR17 PASR Segment Mask (MA[7:0] = 011h) and MR17 PASR Segment Mask Definitions tables). A mode register is used for programming segment-mask bits up to eight bits.

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When the mask bit to an address range (represented as a segment) is programmed as "masked," a REFRESH operation to that segment is blocked. Conversely, when a segment mask bit to an address range is unmasked, refresh to that segment is enabled.

A segment-masking scheme can be used in place of or in combination with a bank-masking scheme. Each segment mask bit setting is applied across all banks. For segment-masking bit assignments, see the MR17 PASR Segment Mask (MA[7:0] = 011h) and MR17 PASR Segment Mask Definitions tables.

Table 53: Bank- and Segment-Masking Example

	Segment Mask (MR17)	Bank 0	Bank 1	Bank 2	Bank 3	Bank 4	Bank 5	Bank 6	Bank 7
Bank Mask (MR16)		**0**	**1**	**0**	**0**	**0**	**0**	**0**	**1**
Segment 0	0	–	M	–	–	–	–	–	M
Segment 1	0	–	M	–	–	–	–	–	M
Segment 2	1	M	M	M	M	M	M	M	M
Segment 3	0	–	M	–	–	–	–	–	M
Segment 4	0	–	M	–	–	–	–	–	M
Segment 5	0	–	M	–	–	–	–	–	M
Segment 6	0	–	M	–	–	–	–	–	M
Segment 7	1	M	M	M	M	M	M	M	M

Note: 1. This table provides values for an eight-bank device with REFRESH operations masked to banks 1 and 7 and to segments 2 and 7.

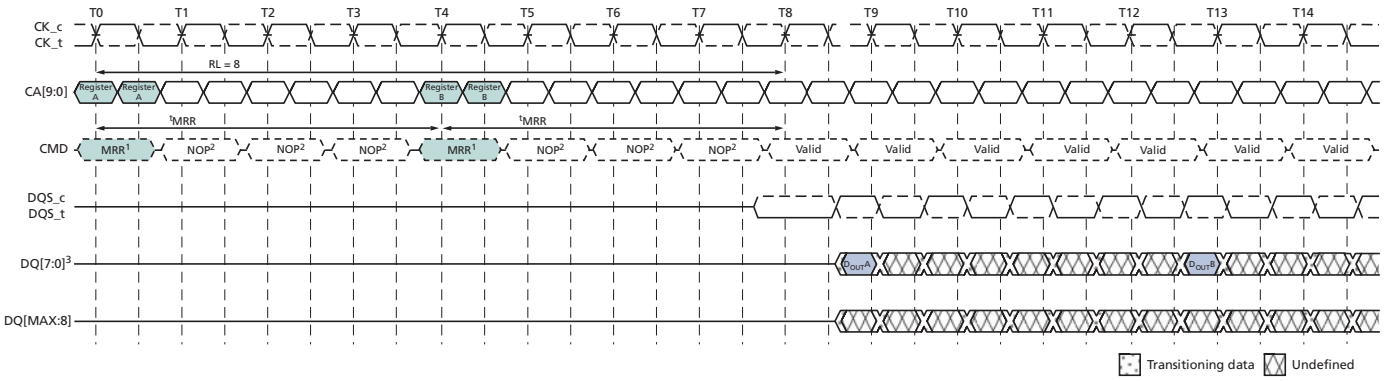
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MODE REGISTER READ

The MODE REGISTER READ (MRR) command is used to read configuration and status data from SDRAM mode registers. The MRR command is initiated with CS_n LOW, CA0 LOW, CA1 LOW, CA2 LOW, and CA3 HIGH at the rising edge of the clock. The mode register is selected by CA1f–CA0f and CA9r–CA4r. The mode register contents are available on the first data beat of DQ[7:0] after RL × ^{t}CK + ^{t}DQSCK + ^{t}DQSQ and following the rising edge of the clock where MRR is issued. Subsequent data beats contain valid but undefined content, except in the case of the DQ calibration function, where subsequent data beats contain valid content as described in the Data Calibration Pattern Description table. All DQS are toggled for the duration of the mode register READ burst.

The MRR command has a burst length of eight. MRR operation (consisting of the MRR command and the corresponding data traffic) must not be interrupted. The MRR command period is ^{t}MRR.

Figure 41: MRR Timing

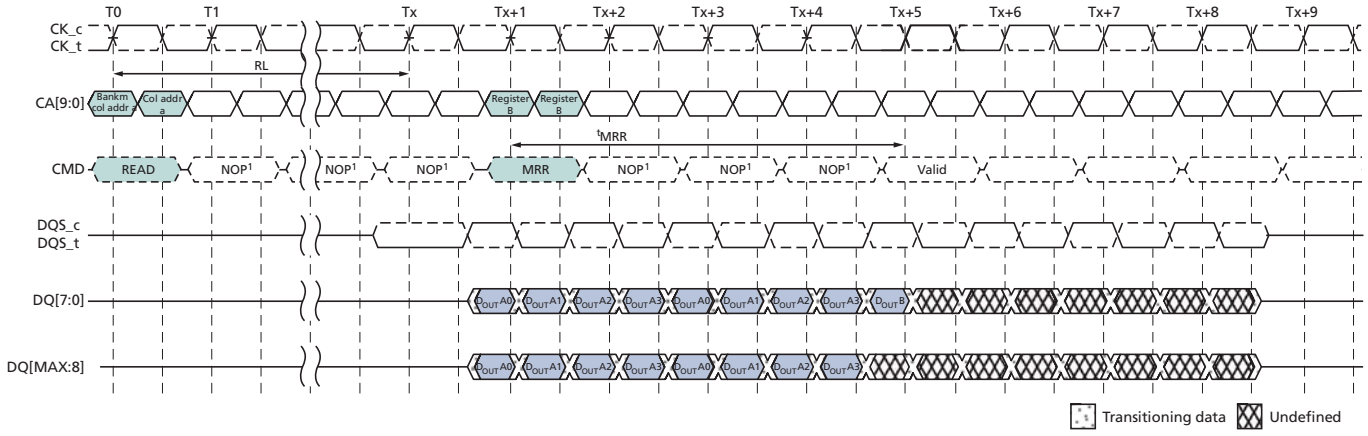


Notes:
1. MRRs to DQ calibration registers MR32 and MR40 are described in the DQ Calibration section.
2. Only the NOP command is supported during ^{t}MRR.
3. Mode register data is valid only on DQ[7:0] on the first beat. Subsequent beats contain valid but undefined data. DQ[MAX:8] contain valid but undefined data for the duration of the MRR burst.
4. Minimum MRR to write latency is RL + RU(^{t}DQSCK (MAX)/^{t}CK) + 8/2 + 1 - WL clock cycles.
5. Minimum MRR to MRW latency is RL + RU(^{t}DQSCK (MAX)/^{t}CK) + 8/2 + 1 clock cycles.
6. In this example, RL = 8 for illustration purposes only.

After a prior READ command, the MRR command must not be issued before BL/2 clock cycles have completed. Following a WRITE command, the MRR command must not be issued before WL + 1 + BL/2 + RU(^{t}WTR/^{t}CK) clock cycles have completed, as READ bursts and WRITE bursts must not be truncated my MRR.

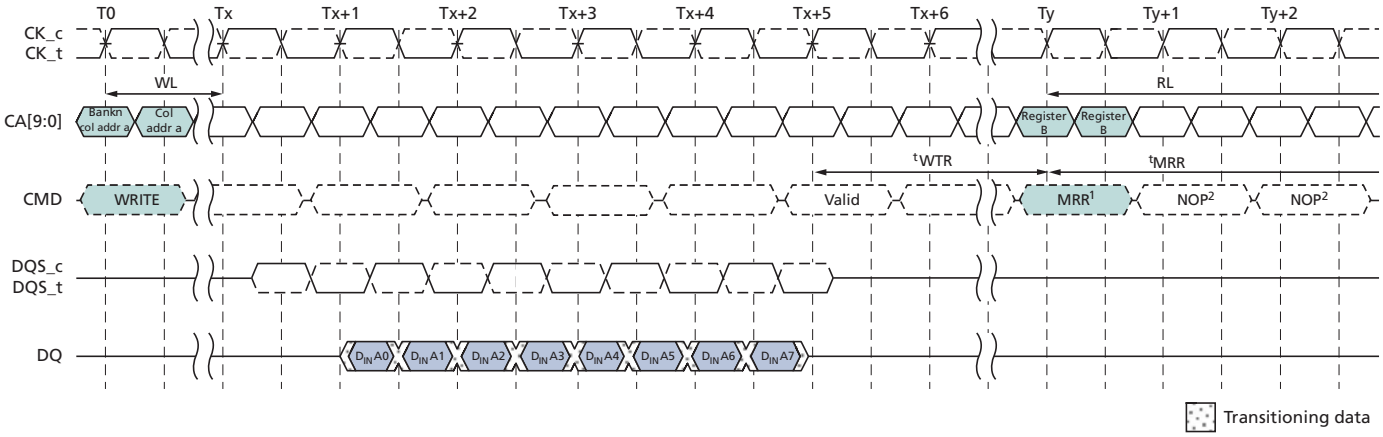
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Figure 42: READ to MRR Timing



Notes:
1. The minimum number of clock cycles from the burst READ command to the MRR command is BL/2.
2. Only the NOP command is supported during ^{t}MRR.

Figure 43: Burst WRITE Followed by MRR



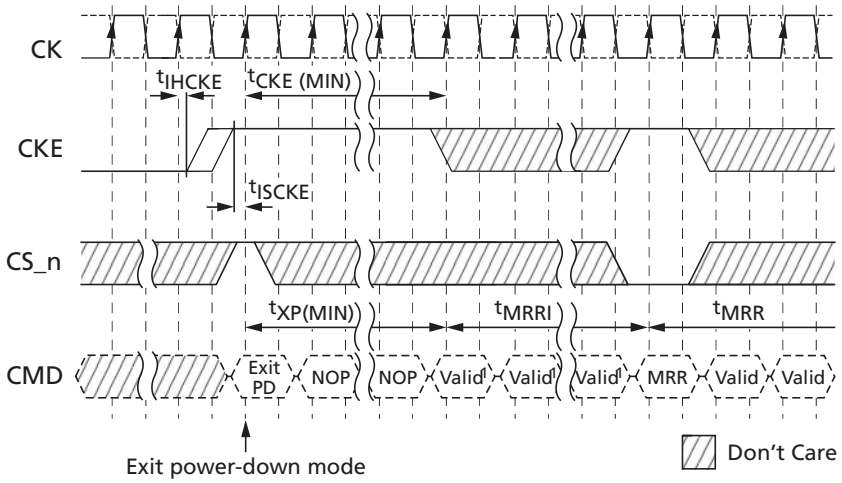
Notes:
1. The minimum number of clock cycles from the burst WRITE command to the MRR command is [WL + 1 + BL/2 + RU(^{t}WTR/^{t}CK)].
2. Only the NOP command is supported during ^{t}MRR.

MRR Following Idle Power-Down State

Following the idle power-down state, an additional time, ^{t}MRRI, is required prior to issuing the MODE REGISTER READ (MRR) command. This additional time (equivalent to ^{t}RCD) is required in order to maximize power-down current savings by allowing more power-up time for the MRR data path after exit from the idle power-down state.

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Figure 44: MRR After Idle Power-Down Exit



Note: 1. Any valid command except MRR.

Temperature Sensor

LPDDR3 devices feature a temperature sensor whose status can be read from MR4. This sensor can be used to determine an appropriate refresh rate, determine whether AC timing derating is required in the extended temperature range, and/or monitor the operating temperature. Either the temperature sensor or the device operating temperature can be used to determine whether operating temperature requirements are being met (see the Operating Temperature Range table).

Temperature sensor data can be read from MR4 using the mode register read protocol. Upon exiting self-refresh or power-down, the device temperature status bits will be no older than ^{t}TSI.

When using the temperature sensor, the actual device case temperature may be higher than the operating temperature specification that applies for the standard or extended temperature ranges (see the Operating Temperature Range table). For example, T_{CASE} could be above 85°C when MR4[2:0] equals 011b.

To ensure proper operation using the temperature sensor, applications must accommodate the following table.

Table 54: Temperature Sensor Definitions and Operating Conditions

Parameter	Description	Symbol	Min/Max	Value	Unit
System temperature gradient	Maximum temperature gradient experienced by the memory device at the temperature of interest over a range of 2°C	TempGradient	MAX	System-dependent	°C/s
MR4 READ interval	Time period between MR4 READs from the system	ReadInterval	MAX	System-dependent	ms
Temperature sensor interval	Maximum delay between internal updates of MR4	^{t}TSI	MAX	32	ms
System response delay	Maximum response time from an MR4 READ to the system response	SysRespDelay	MAX	System-dependent	ms

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Table 54: Temperature Sensor Definitions and Operating Conditions (Continued)

Parameter	Description	Symbol	Min/Max	Value	Unit
Device temperature margin	Margin above maximum temperature to support controller response	TempMargin	MAX	2	°C

These devices accommodate the temperature margin between the point at which the device temperature enters the extended temperature range and the point at which the controller reconfigures the system accordingly. To determine the required MR4 polling frequency, the system must use the maximum TempGradient and the maximum response time of the system according to the following equation:

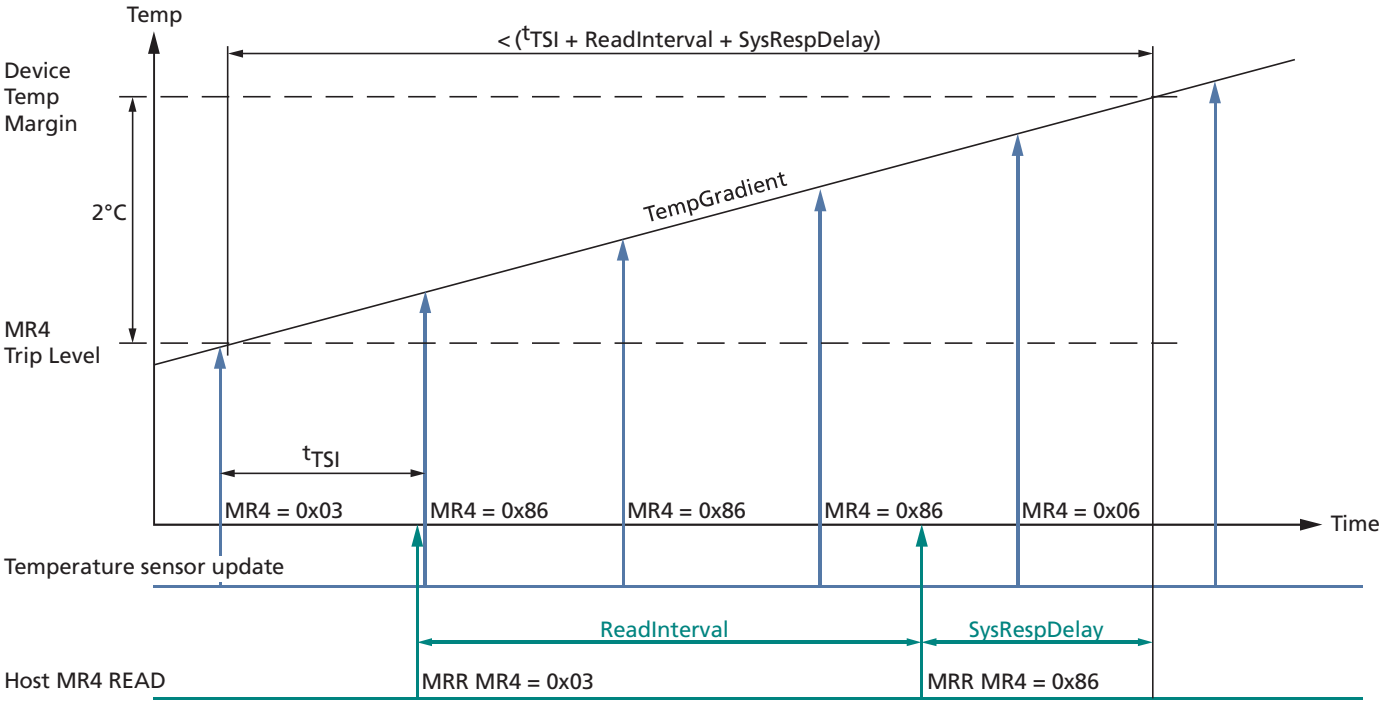
$$\text{TempGradient} \times (\text{ReadInterval} + {}^{t}\text{TSI} + \text{SysRespDelay}) \leq 2°\text{C}$$

For example, if TempGradient is 10˚C/s, and the SysRespDelay is 1ms:

$$\frac{10°\text{C}}{\text{s}} \times (\text{ReadInterval} + 32\text{ms} + 1\text{ms}) \leq 2°\text{C}$$

In this case, ReadInterval must not exceed 167ms.

Figure 45: Temperature Sensor Timing



DQ Calibration

LPDDR3 devices feature a DQ calibration function that outputs one of two predefined system timing calibration patterns. An MRR operation to MR32 (pattern A) or and MRR

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operation to MR40 (pattern B) will return the specified pattern on DQ0 and DQ8—for x32 devices, on DQ0, DQ8, DQ16 and DQ24.

For x16 devices, DQ[7:1] and DQ[15:9] drive the same information as DQ0 during the MRR burst. For x32 devices, DQ[7:1], DQ[15:9], DQ[23:17], and DQ[31:25] drive the same information as DQ0 during the MRR burst. MRR DQ calibration commands can occur only in the idle state.

Figure 46: MR32 and MR40 DQ Calibration Timing

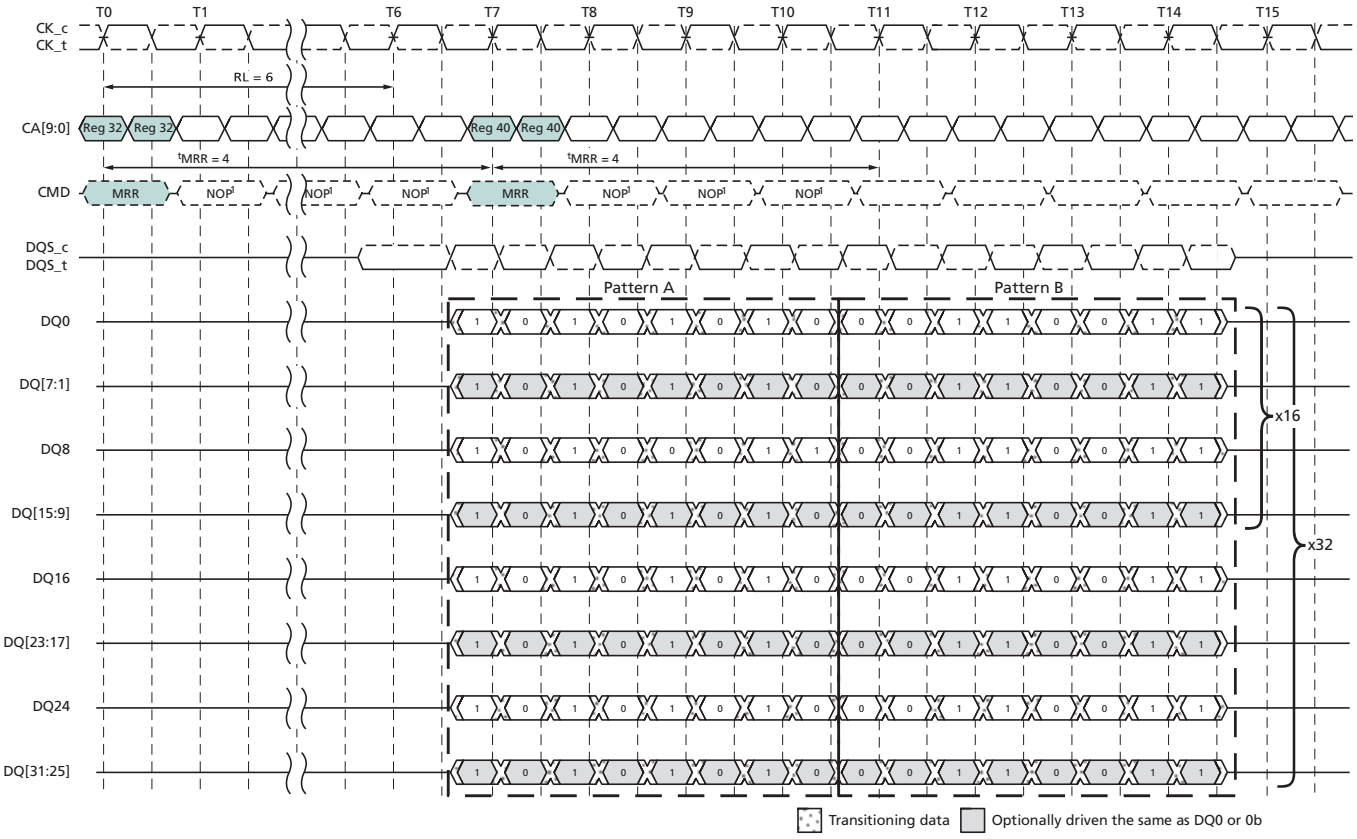


Table 55: Data Calibration Pattern Description

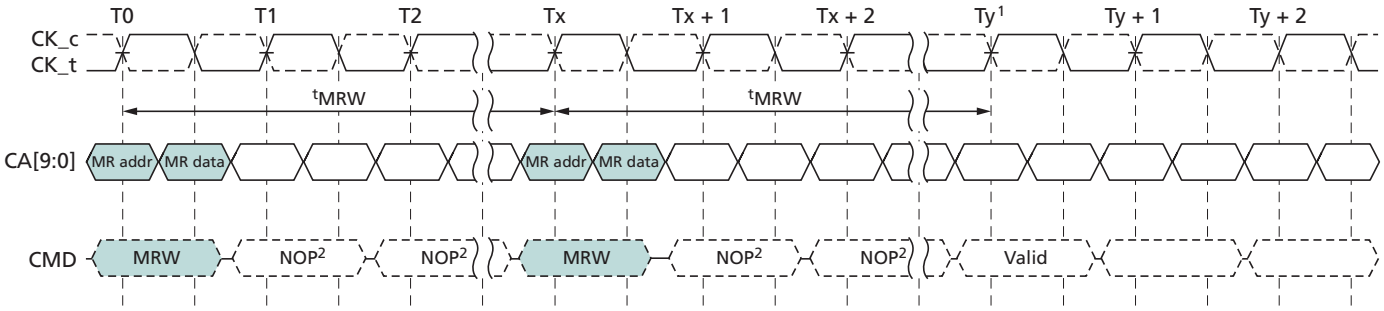
Pattern	MR#	Bit Time 0	Bit Time 1	Bit Time 2	Bit Time 3	Bit Time 4	Bit Time 5	Bit Time 6	Bit Time 7	
Pattern A	MR32	1	0	1	0	1	0	1	0	Reads to MR32 return DQ calibration pattern A
Pattern B	MR40	0	0	1	1	0	0	1	1	Reads to MR40 return DQ calibration pattern B

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MODE REGISTER WRITE

The MRW command is used to write configuration data to the mode registers. The MRW command is initiated with CS_n LOW, CA0 LOW, CA1 LOW, CA2 LOW, and CA3 LOW at the rising edge of the clock. The mode register is selected by CA1f–CA0f, CA9r–CA4r. The data to be written to the mode register is contained in CA9f–CA2f. The MRW command period is defined by ^{t}MRW. Mode register writes to read-only registers have no impact on the functionality of the device.

Figure 47: MODE REGISTER WRITE Timing



Notes:
1. At time Ty, the device is in the idle state.
2. Only the NOP command is supported during ^{t}MRW.

MRW can be issued only when all banks are in the idle precharge state. One method of ensuring that the banks are in this state is to issue a PRECHARGE ALL command.

MRW RESET Command

The MRW RESET command brings the device to the device auto initialization (resetting) state in the power-on initialization sequence (see the Voltage Ramp and Device Initialization section). The MRW RESET command can be issued from the idle state. This command resets all mode registers to their default values. After MRW RESET, boot timings must be observed until the device initialization sequence is complete, and the device is in the idle state. Array data is undefined after the MRW RESET command.

If the initialization is to be performed at-speed (greater than the recommended boot clock frequency), then CA training may be necessary to ensure setup and hold timings. As the MRW RESET command is required prior to CA Training, an alternate MRW RESET command with an op-code of 0xFCh should be used. This encoding ensures that no transitions occur on the CA bus. Prior to CA training, it is recommended to hold the CA bus stable for one cycle prior to, and one cycle after, the issuance of the MRW RESET command to ensure setup and hold timings on the CA bus.

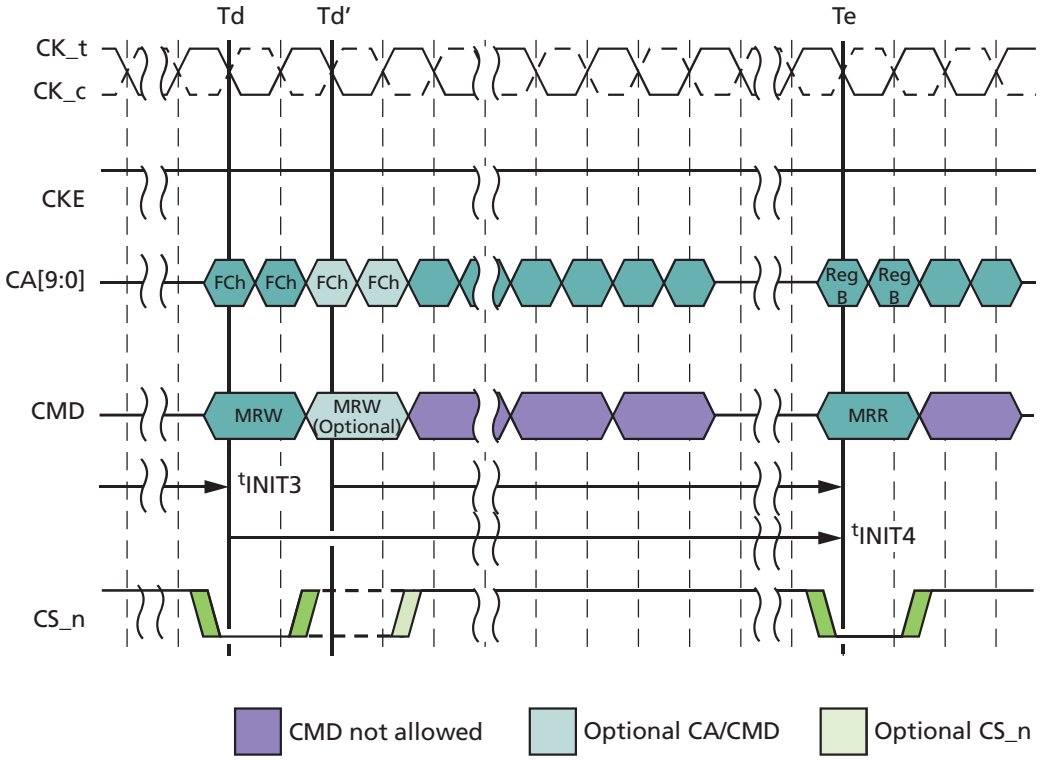
For MRW RESET timing, see the figure below and see the Voltage Ramp and Initialization Sequence figure.

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Table 56: Truth Table for MRR and MRW

Current State	Command	Intermediate State	Next State
All banks idle	MRR	Reading mode register, all banks idle	All banks idle
	MRW	Writing mode register, all banks idle	All banks idle
	MRW (RESET)	Resetting, device auto initialization	All banks idle
Bank(s) active	MRR	Reading mode register, bank(s) active	Bank(s) active
	MRW	Not allowed	Not allowed
	MRW (RESET)	Not allowed	Not allowed

Figure 48: MODE REGISTER WRITE Timing for MRW RESET



Note: 1. Optional MRW RESET command and optional CS_n assertion are allowed. When the optional MRW RESET command is used, ^{t}INIT4 starts at Td'.

MRW ZQ Calibration Commands

The MRW command is used to initiate a ZQ calibration command that calibrates output driver impedance across process, temperature, and voltage. LPDDR3 devices support ZQ calibration.

There are four ZQ calibration commands and related timings: ^{t}ZQINIT, ^{t}ZQRESET, ^{t}ZQCL, and ^{t}ZQCS. ^{t}ZQINIT is used for initialization calibration; ^{t}ZQRESET is used for resetting ZQ to the default output impedance; ^{t}ZQCL is used for long calibration(s); and

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^{t}ZQCS is used for short calibration(s). See the MR10 Calibration (MA[7:0] = 0Ah) table for ZQ calibration command code definitions.

The initialization ZQ calibration (ZQINIT) must be performed for LPDDR3. ZQINIT provides an output impedance accuracy of ±15%. After initialization, the ZQ calibration long (ZQCL) can be used to recalibrate the system to an output impedance accuracy of ±15%. A ZQ calibration short (ZQCS) can be used periodically to compensate for temperature and voltage drift in the system.

ZQRESET resets the output impedance calibration to a default accuracy of ±30% across process, voltage, and temperature. This command is used to ensure output impedance accuracy to ±30% when ZQCS and ZQCL commands are not used.

One ZQCS command can effectively correct at least 1.5% (ZQ correction) of output impedance errors within ^{t}ZQCS for all speed bins, assuming the maximum sensitivities specified in the Output Driver Sensitivity Definition and Output Driver Temperature and Voltage Sensitivity tables are met. The appropriate interval between ZQCS commands can be determined using these tables and system-specific parameters.

LPDDR3 devices are subject to temperature drift rate ($T_{driftrate}$) and voltage drift rate ($V_{driftrate}$) in various applications. To accommodate drift rates and calculate the necessary interval between ZQCS commands, apply the following formula:

$$\frac{ZQ_{correction}}{(T_{sens} \times T_{driftrate}) + (V_{sens} \times V_{driftrate})}$$

Where T_{sens} = MAX ($dR_{ON}dT$) and V_{sens} = MAX ($dR_{ON}dV$) define temperature and voltage sensitivities.

For example, if T_{sens} = 0.75%/˚C, V_{sens} = 0.20%/mV, $T_{driftrate}$ = 1˚C/sec, and $V_{driftrate}$ = 15 mV/sec, then the interval between ZQCS commands is calculated as:

$$\frac{1.5}{(0.75 \times 1) + (0.20 \times 15)} = 0.4s$$

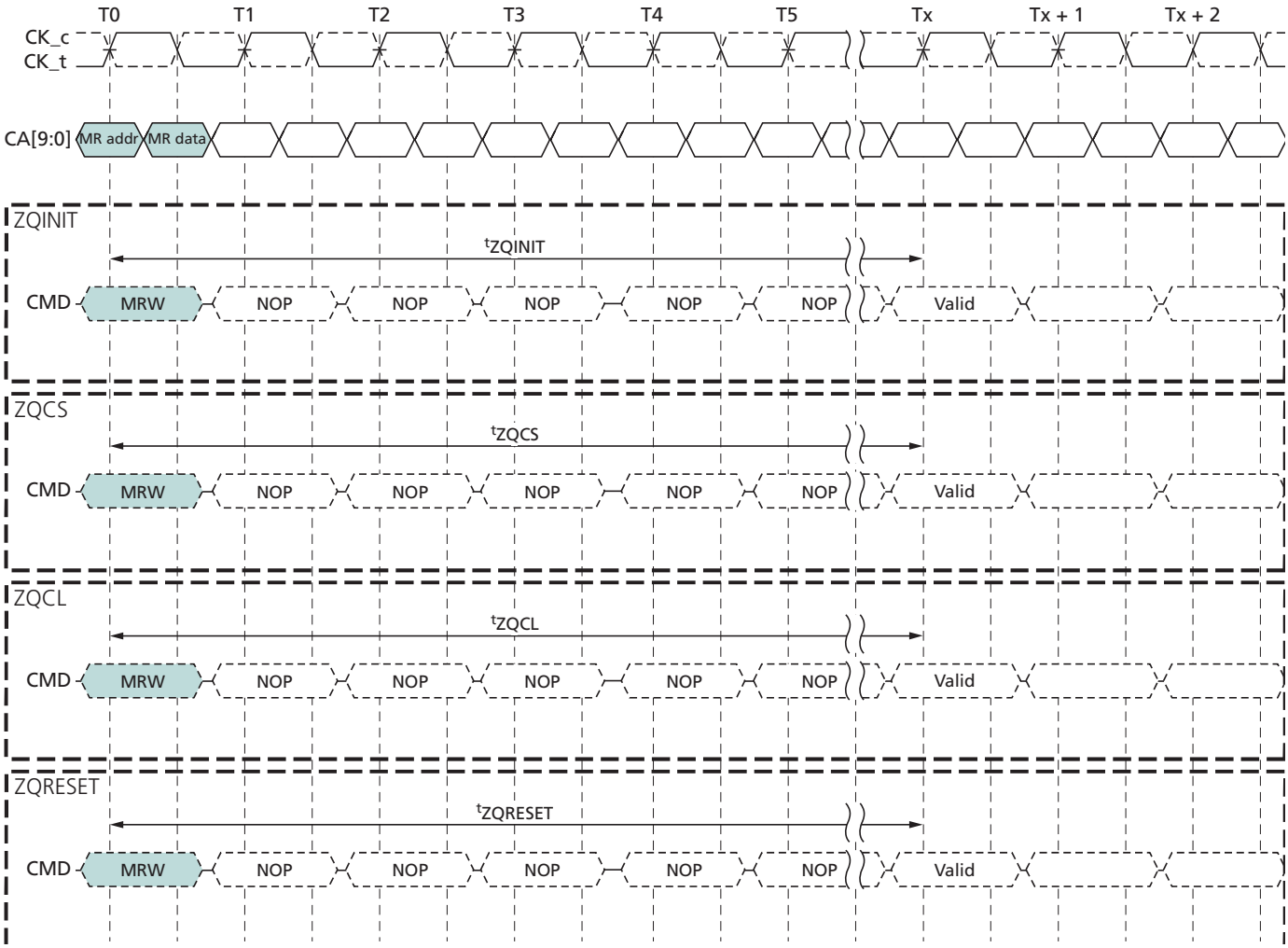
A ZQ calibration command can be issued only when the device is in the idle state with all banks precharged.

No other activities can be performed on the data bus during calibration periods (^{t}ZQINIT, ^{t}ZQCL, or ^{t}ZQCS). The quiet time on the data bus helps to accurately calibrate output impedance. There is no required quiet time after the ZQRESET command. If multiple devices share a single ZQ resistor, only one device can be calibrating at any given time. After calibration is complete, the ZQ ball circuitry is disabled to reduce power consumption.

In systems sharing a ZQ resistor among devices, the controller must prevent ^{t}ZQINIT, ^{t}ZQCS, and ^{t}ZQCL overlap between the devices. ZQRESET overlap is acceptable. If the ZQ resistor is absent from the system, ZQ must be connected to V_{DDCA}. In this situation, the device must ignore ZQ calibration commands, and the device will use the default calibration settings.

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Figure 49: ZQ Timings



Notes:
1. Only the NOP command is supported during ZQ calibration.
2. CKE must be registered HIGH continuously during the calibration period.
3. All devices connected to the DQ bus should be High-Z during the calibration process.

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ZQ External Resistor Value, Tolerance, and Capacitive Loading

To use the ZQ calibration function, a 240Ω (±1% tolerance) external resistor must be connected between the ZQ pin and ground. A single resistor can be used for each device, or one resistor can be shared among multiple devices if the ZQ calibration timings for each device do not overlap. The total capacitive loading on the ZQ pin must be limited (see the Input/Output Capacitance table).

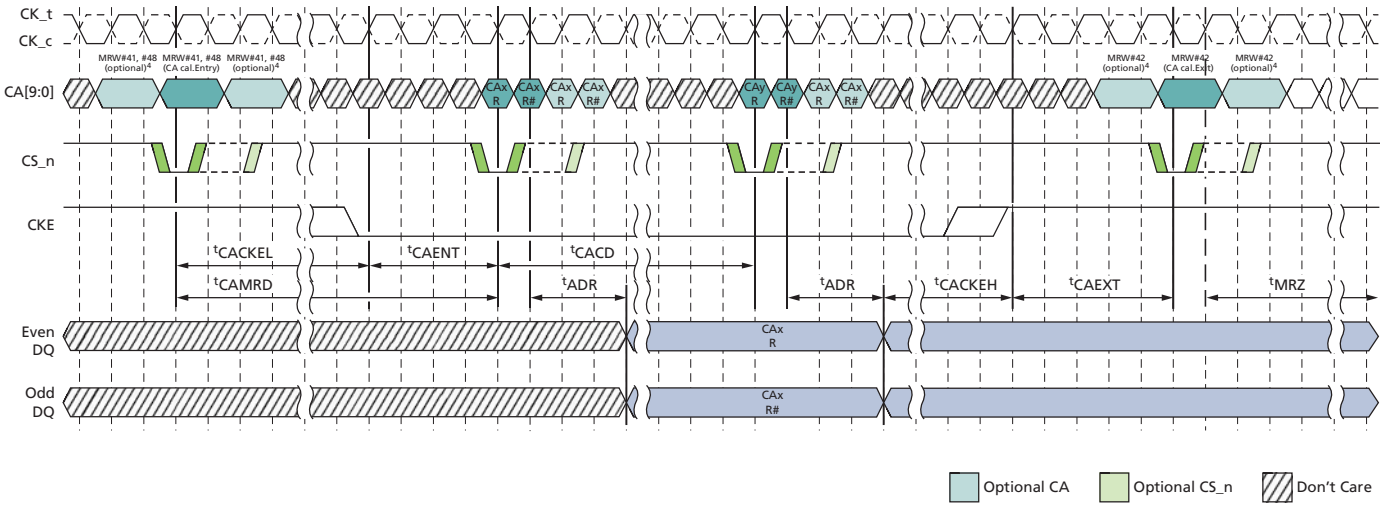
MRW – CA Training Mode

Because CA inputs operate as double data rate, it may be difficult for the memory controller to satisfy CA input setup/hold timings at higher frequency. A CA training mechanism is provided.

CA Training Sequence

1. CA training mode entry: MODE REGISTER WRITE command to MR41
2. CA training session: Calibrate CA0, CA1, CA2, CA3, CA5, CA6, CA7 and CA8 (see the CA Training Mode Enable [MR41] table)
3. CA to DQ mapping change: MODE REGISTER WRITE command to MR48
4. Additional CA training session: Calibrate remaining CA pins (CA4 and CA9) (see the CA Training Mode Enable [MR48] table)
5. CA training mode exit: MODE REGISTER WRITE command to MR42

Figure 50: CA Training Timing



Notes:
1. Unused DQ must be valid HIGH or LOW during data output period. Unused DQ may transition at the same time as the active DQ. DQS must remain static and not transition.
2. CA to DQ mapping change via MR 48 omitted here for clarity of the timing diagram. Both MR41 and MR48 training sequences must be completed before exiting the training mode (MR42). To enable a CA to DQ mapping change, CKE must be driven HIGH prior to issuance of the MRW 48 command. (See the steps in the CA Training Sequence section for details.)
3. Because data-out control is asynchronous and will be an analog delay from when all the CA data is available, ^{t}ADR and ^{t}MRZ are defined from the falling edge of CK.

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4. It is recommended to hold the CA bus stable for one cycle prior to and one cycle after the issuance of the MRW CA TRAINING ENTRY command to ensure setup and hold timings on the CA bus.
5. Optional MRW 41, 48, 42 commands and the CA CALIBRATION command are allowed. To complement these optional commands, optional CS_n assertions are also allowed. All timing must comprehend these optional CS_n assertions: a) ^{t}ADR starts at the falling clock edge after the last registered CS_n assertion; b) ^{t}CACD, ^{t}CACKEL, and ^{t}CAMRD start with the rising clock edge of the last CS_n assertion; c) ^{t}CAENT and ^{t}CAEXT need to be met by the first CS_n assertion; and d) ^{t}MRZ will be met after the falling clock edge following the first CS_n assertion with exit (MRW42) command.
6. Clock phase may be adjusted in CA training mode while CS_n is HIGH and CKE is LOW, resulting in an irregular clock with shorter/longer periods and pulse widths.

The device may not properly recognize a MODE REGISTER WRITE command at normal operation frequency before CA training is finished. Special encodings are provided for CA training mode enable/disable.

MR41 and MR42 encodings are selected so that rising-edge and falling-edge values are the same. The device will recognize MR41 and MR42 at normal operation frequency even before CA timing adjustments have been made. Calibration data will be output through DQ pins. CA to DQ mapping is described in the CA to DQ mapping (CA training mode enabled with MR41) table.

After timing calibration with MR41 is finished, issue MRW to MR48 and calibrate the remaining CA pins (CA4 and CA9) using (DQ0/DQ1and DQ8/DQ9) as calibration data output pins (see the CA to DQ mapping (CA training mode enabled with MR48) table).

Table 57: CA Training Mode Enable (MR41 (29H, 0010 1001b), OP = A4H (1010 0100b))

Clock Edge	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9
CK rising edge	L	L	L	L	H	L	L	H	L	H
CK falling edge	L	L	L	L	H	L	L	H	L	H

Table 58: CA Training Mode Disable (MR42 (2AH, 0010 1010b), OP = A8H(1010 1000b))

Clock Edge	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9
CK rising edge	L	L	L	L	L	H	L	H	L	H
CK falling edge	L	L	L	L	L	H	L	H	L	H

Table 59: CA to DQ Mapping (CA Training Mode Enabled with MR41)

Clock Edge	CA0	CA1	CA2	CA3	CA5	CA6	CA7	CA8
CK rising edge	DQ0	DQ2	DQ4	DQ6	DQ8	DQ10	DQ12	DQ14
CK falling edge	DQ1	DQ3	DQ5	DQ7	DQ9	DQ11	DQ13	DQ15

Note: 1. Other DQs must have valid output (either HIGH or LOW).

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Table 60: CA Training Mode Enable (MR48 (30H, 0011 0000b), OP = C0H (1100 0000b))

Clock Edge	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9
CK rising edge	L	L	L	L	L	L	L	L	H	H
CK falling edge	L	L	L	L	L	L	L	L	H	H

Table 61: CA to DQ Mapping (CA Training Mode Enabled with MR48)

Clock Edge	CA4	CA9
CK rising edge	DQ0	DQ8
CK falling edge	DQ1	DQ9

Note: 1. Other DQs must have valid output (either HIGH or LOW).

MRW - Write Leveling Mode

To improve signal integrity performance, the device provides a write-leveling feature to compensate for timing skew, which affects timing parameters such as ^{t}DQSS, ^{t}DSS, and ^{t}DSH.

The memory controller uses the write-leveling feature to receive feedback from the device, enabling it to adjust the clock-to-data strobe signal relationship for each DQS signal pair. The memory controller performing the leveling must have an adjustable delay setting on the DQS signal pair to align the rising edge of DQS_t signals with that of the clock signal at the DRAM pin. The device asynchronously feeds back CLK, sampled with the rising edge of DQS_t signals. The controller repeatedly delays DQS_t signals until a transition from 0 to 1 is detected. The DQS_t signal delay established through this exercise ensures the ^{t}DQSS specification can be met.

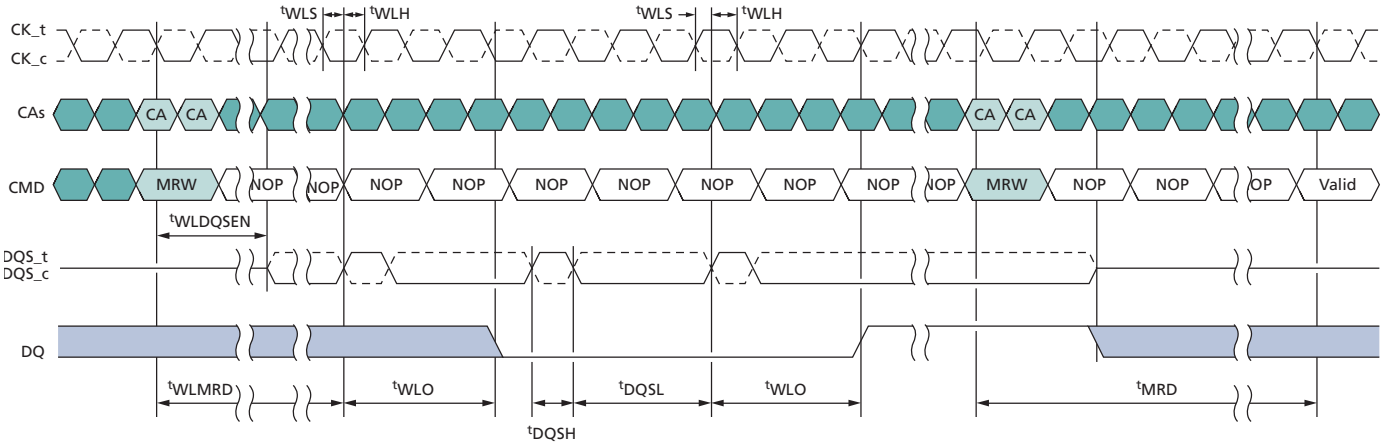
All data bits carry the leveling feedback to the controller (DQ[15:0] for x16 configuration, DQ[31:0] for x32 configuration). All DQS_t signals must be leveled independently.

The device enters write-leveling mode when mode register MR2[7] is set HIGH. When entering write-leveling mode, the state of the DQ pins is undefined. During write-leveling mode, only NOP commands are allowed, or a MRW command to exit the write-leveling operation. Upon completion of the write-leveling operation, the device exits from write-leveling mode when MR2[7] is reset LOW.

The controller drives DQS_t LOW and DQS_c HIGH after a delay of ^{t}WLDQSEN. After time ^{t}WLMRD, the controller provides DQS_t signal input, which is used by the DRAM to sample the clock signal driven from the controller. The delay time ^{t}WLMRD (MAX) is controller-dependent. The DRAM samples the clock input with the rising edge of DQS_t and provides asynchronous feedback on all the DQ bits after time ^{t}WLO. The controller samples this information and either increments or decrements the DQS_t and/or DQS_c delay settings and launches the next DQS_t/DQS_c pulse. The sample time and trigger time are controller-dependent. After the following DQS_t/DQS_c transition is sampled, the controller locks the strobe delay settings, and write leveling is achieved for the device.

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Figure 51: Write-Leveling Timing



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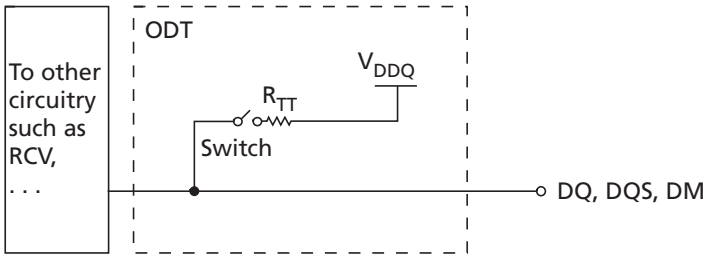
On-Die Termination (ODT)

On-die termination (ODT) is a feature that enables the device to enable/disable and turn on/off termination resistance for each DQ, DQS, and DM signal via the ODT control pin. ODT is designed to improve signal integrity of the memory channel by enabling the DRAM controller to independently turn on/off the internal termination resistance for any or all DRAM devices. The ODT pin directly controls ODT operation and is not sampled by the clock.

ODT is turned off and not supported in self refresh and deep power-down modes. The device will also disable termination during READ operations. ODT operation can be enabled optionally during power-down mode via a mode register. Note that if ODT is enabled during power-down mode, V_{DDQ} may not be turned off during power down. The DRAM will also disable termination during READ operations.

A simple functional representation of the ODT feature is shown below.

Figure 52: Functional Representation of On-Die Termination



The switch is enabled by the internal ODT control logic, which uses the external ODT pin and other control information. The value of R_{TT} (ODT termination resistance value) is determined by the settings of several mode register bits. The ODT pin will be ignored if MR11 is programmed to disable ODT in self refresh, in deep power-down, in CKE power-down (mode register option), and during READ operations.

ODT Mode Register

ODT mode is enabled if MR11[1:0] are non-zero. In this case, the value of R_{TT} is determined by the settings of those bits. ODT mode is disabled if MR11[1:0] are zero. MR11[2] determines whether ODT will operate during power-down mode if enabled through MR11[1:0].

Asychronous ODT

When enabled, the ODT feature is controlled asynchronously based on the status of the ODT pin. ODT is off under any of the following conditions:

- ODT is disabled through MR11[1:0]
- Device is performing a READ operation (READ or MRR)
- Device is in power-down mode and MR11[2] is zero
- Device is in self refresh or deep power-down mode
- Device is in CA training mode

In asynchronous ODT mode, the following timing parameters apply when ODT operation is controlled by the ODT pin ^{t}ODToff, ^{t}ODTon.

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Minimum R_{TT} turn-on time (^{t}ODTon [MIN]) is the point in time when the device termination circuit leaves High-Z state and ODT resistance begins to turn on. Maximum R_{TT} turn-on time (^{t}ODTon,max) is the point in time when ODT resistance is fully on. ^{t}ODTon (MIN) and ^{t}ODTon (MAX) are measured from ODT pin HIGH.

Minimum R_{TT} turn-off time (^{t}ODToff [MIN]) is the point in time when the device termination circuit starts to turn off the ODT resistance. Maximum ODT turn off time (^{t}ODToff [MAX]) is the point in time when the on-die termination has reached High-Z. ^{t}ODToff,min and ^{t}ODToff (MAX) are measured from ODT pin LOW.

ODT During READ Operations (READ or MRR)

During READ operations, the device will disable termination and disable ODT control through the ODT pin. After READ operations are completed, ODT control is resumed through the ODT pin (if ODT mode is enabled).

ODT During Power-Down

When MR11[2] is zero, termination control through the ODT pin will be disabled when the DRAM enters power-down. After a power-down entry is registered, termination will be disabled within a time window specified by ^{t}ODTd (MIN) (MAX). ODT pin control is resumed when power-down is exited (if ODT mode is enabled). Between the POWER-DOWN EXIT command and until ^{t}XP is satisfied, termination will transition from disabled to control by the ODT pin. When ^{t}XP is satisfied, the ODT pin is used to control termination.

Minimum R_{TT} disable time (^{t}ODTd [MIN]) is the point in time when the device termination circuit is no longer controlled by the ODT pin. Maximum ODT disable time (^{t}ODTd [MAX]) is the point in time when ODT will be in High-Z.

When MR11[2] is enabled and MR11[1:0] are non-zero, ODT operation is supported during CKE power-down with ODT control through the ODT pin.

ODT During Self Refresh

The device disables the ODT function during self refresh. After a SELF REFRESH command is registered, termination will be disabled within a time window specified by ^{t}ODTd (MIN) (MAX). During self refresh exit, ODT control through the ODT pin is resumed (if ODT mode is enabled). Between the SELF REFRESH EXIT command and until ^{t}XSR is satisfied, termination will transition from disabled to control by the ODT pin. When ^{t}XSR is satisfied, the ODT pin is used to control termination.

ODT During Deep Power-Down

The device disables the ODT function during deep power-down. After a DEEP POWER-DOWN command is registered, termination will be disabled within a time window specified by ^{t}ODTd (MIN) (MAX).

ODT During CA Training and Write Leveling

During CA training mode, the device will disable ODT and ignore the state of the ODT control pin. For ODT operation during write leveling mode, refer to the DRAM Termination Function in Write-Leveling Mode table for termination activation and deactivation for DQ and DQS_t/DQS_c. If ODT is enabled, the ODT pin must be HIGH in write leveling mode.

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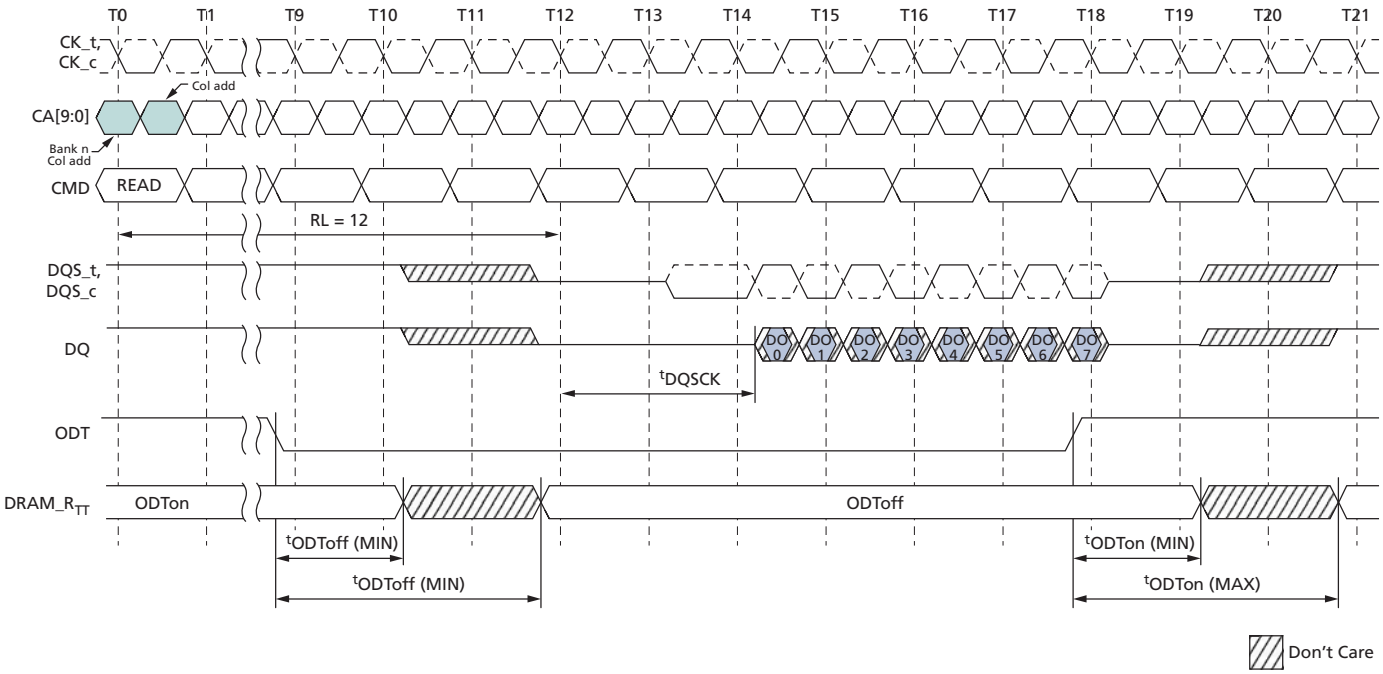
Table 62: DRAM Termination Function in Write-Leveling Mode

ODT Pin	DQS Termination	DQ Termination
De-asserted	OFF	OFF
Asserted	ON	OFF

Table 63: ODT States Truth Table

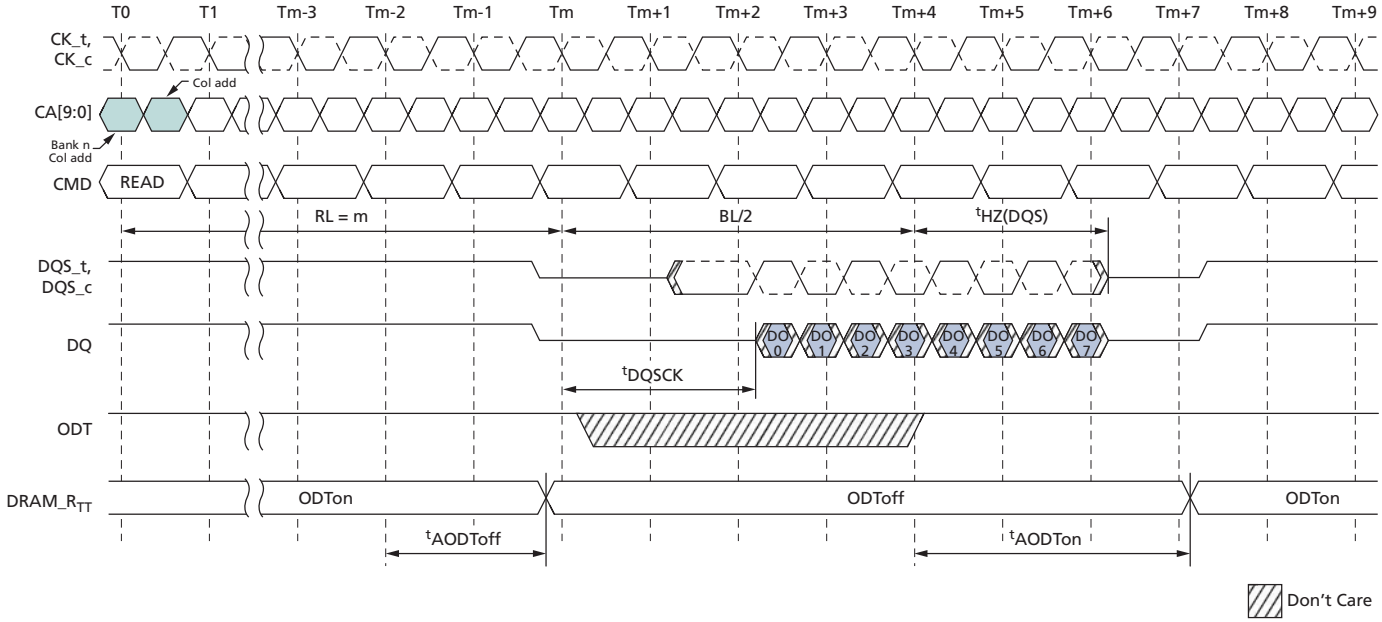
	Write	Read/DQ Calibration	ZQ Calibration	CA Training	Write Leveling
DQ termination	Enabled	Disabled	Disabled	Disabled	Disabled
DQS termination	Enabled	Disabled	Disabled	Disabled	Enabled

Figure 53: Asynchronous ODT Timing – RL = 12



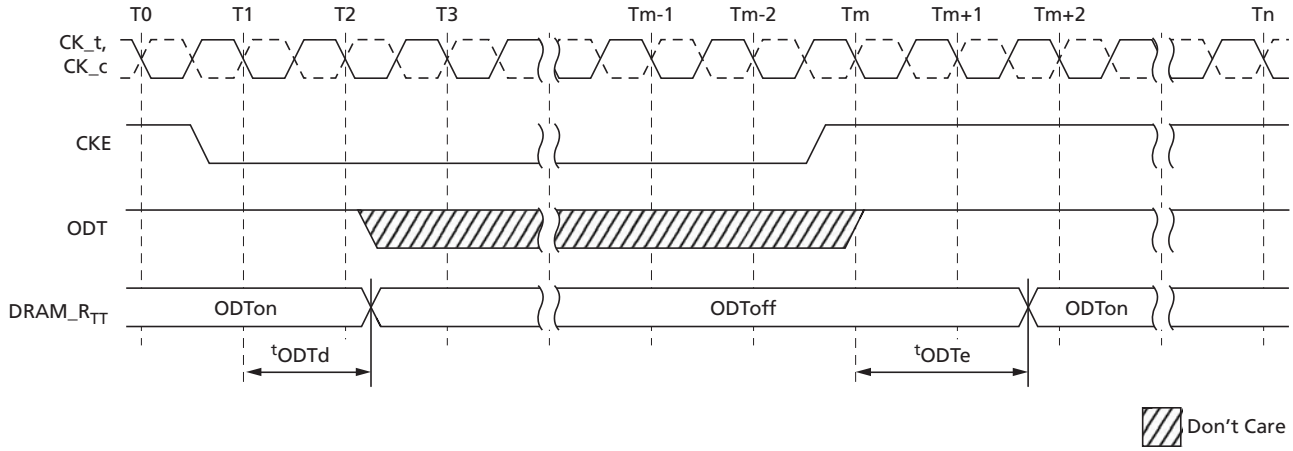
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Figure 54: Automatic ODT Timing During READ Operation – RL = *m*



Notes:
1. The automatic R_{TT} turn-off delay, ^{t}AODToff, is referenced from the rising edge of RL - 2 clock at T_{m-2}.
2. The automatic R_{TT} turn-on delay, ^{t}AODTon, is referenced from the rising edge of RL + BL/2 clock at T_{m+4}.

Figure 55: ODT Timing During Power-Down, Self Refresh, Deep Power-Down Entry/Exit



Note:
1. Upon exiting of deep power-down mode, a complete power-up initialization sequence is required.

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Power-Down

Power-down is entered synchronously when CKE is registered LOW and CS_n is HIGH at the rising edge of clock. A NOP command must be driven in the clock cycle following the POWER-DOWN command. CKE must not go LOW while MRR, MRW, READ, or WRITE operations are in progress. CKE can go LOW while any other operations, such as ROW ACTIVATION, PRECHARGE, AUTO PRECHARGE, or REFRESH are in progress, but the power-down I_{DD} specification is not applied until such operations are complete.

Entering power-down deactivates the input and output buffers, excluding CKE. To ensure enough time to account for internal delay on the CKE signal path, two NOP commands are required after CKE is driven LOW. this timing period is defined as ^{t}CPDED. CKE LOW results in deactivation of input receivers after ^{t}CPDED has expired. In power-down mode, CKE must be held LOW; all other input signals are "Don't Care." CKE LOW must be maintained until ^{t}CKE is satisfied, and V_{REFCA} must be maintained at a valid level during power-down.

V_{DDQ} can be turned off during power-down. If V_{DDQ} is turned off, V_{REFDQ} must also be turned off. Prior to exiting power-down, both V_{DDQ} and V_{REFDQ} must be within their respective minimum/maximum operating ranges (see the AC and DC Operating Conditions section).

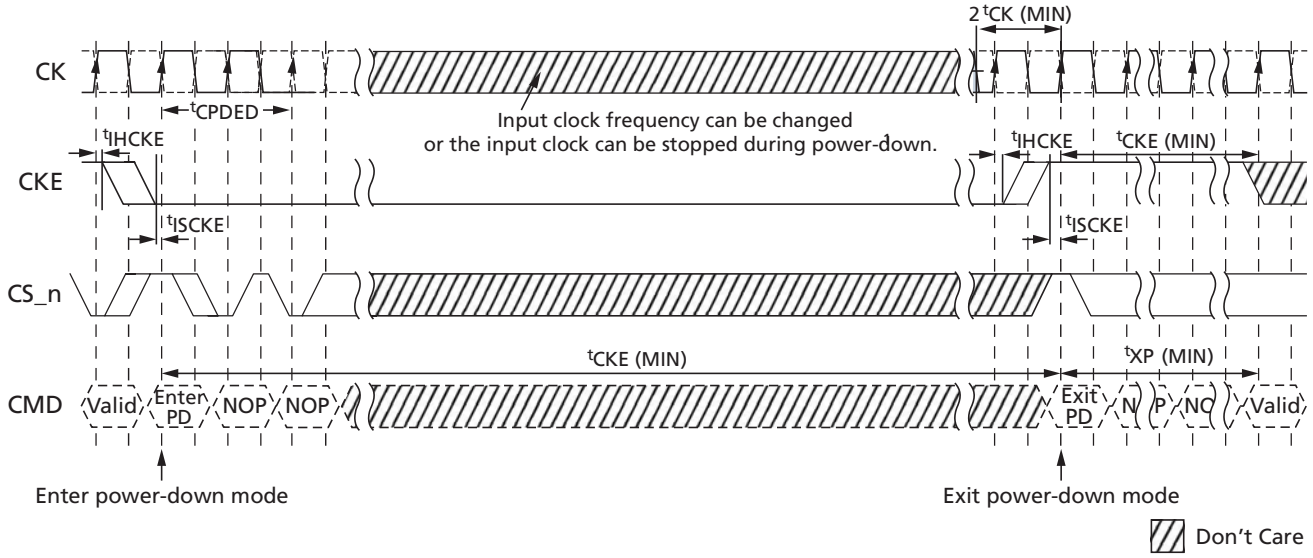
No refresh operations are performed in power-down mode. The maximum duration in power-down mode is only limited by the refresh requirements outlined in the REFRESH Command section.

The power-down state is exited when CKE is registered HIGH. The controller must drive CS_n HIGH in conjunction with CKE HIGH when exiting the power-down state. CKE HIGH must be maintained until ^{t}CKE is satisfied. A valid, executable command can be applied with power-down exit latency ^{t}XP after CKE goes HIGH. Power-down exit latency is defined in the AC Timing table.

If power-down occurs when all banks are idle, this mode is referred to as idle power-down; if power-down occurs when a row is active in any bank, this mode is referred to as active power-down. For the description of ODT operation and specifications during power-down entry and exit, see the On-Die Termination section.

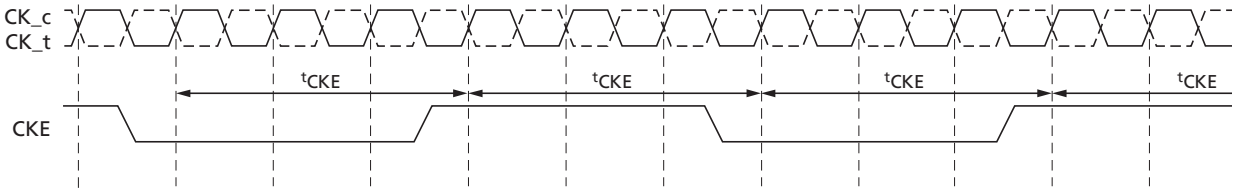
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Figure 56: Power-Down Entry and Exit Timing



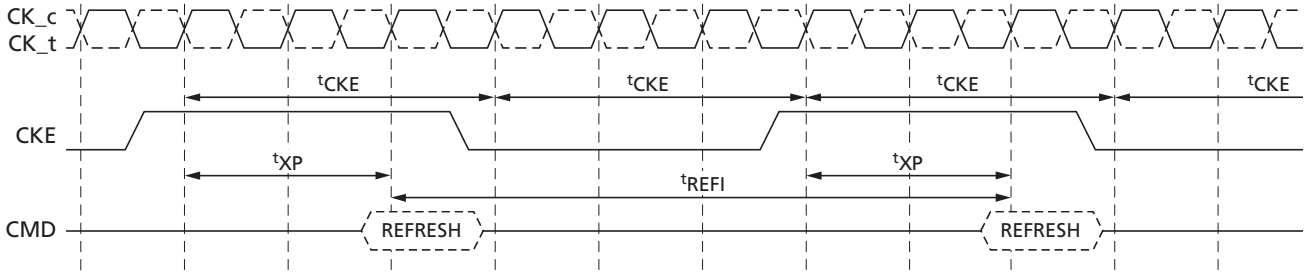
Note: 1. Input clock frequency can be changed or the input clock stopped during power-down, provided that the clock frequency is between the minimum and maximum specified frequencies for the speed grade in use and that prior to power-down exit, a minimum of two stable clocks complete.

Figure 57: CKE Intensive Environment



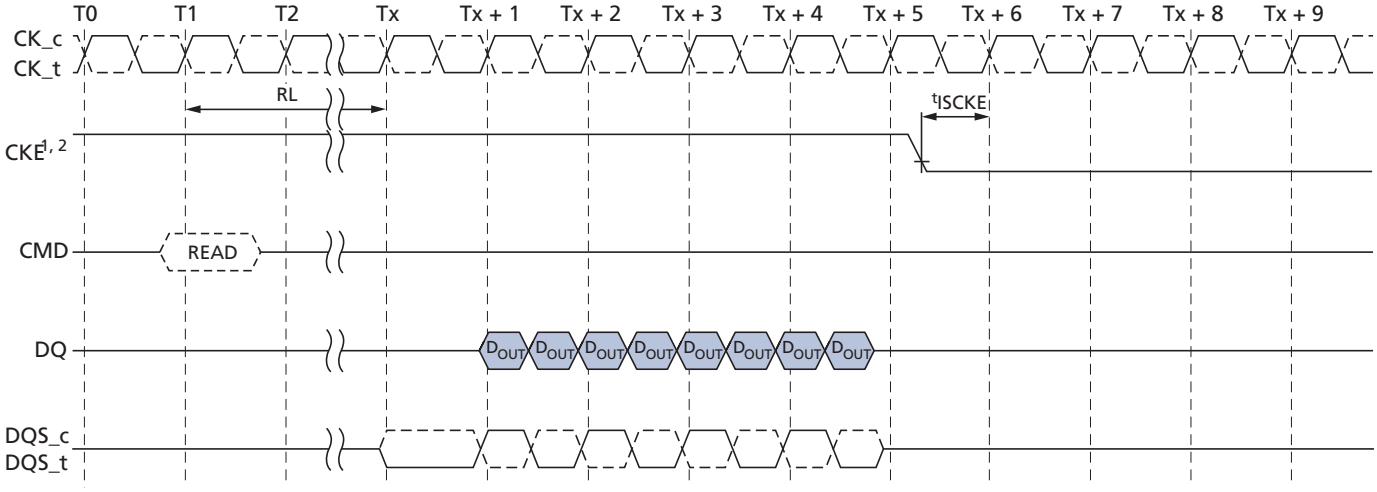
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Figure 58: REFRESH to REFRESH Timing in CKE Intensive Environments



Note: 1. The pattern shown can repeat over an extended period of time. With this pattern, all AC and DC timing and voltage specifications with temperature and voltage drift are ensured.

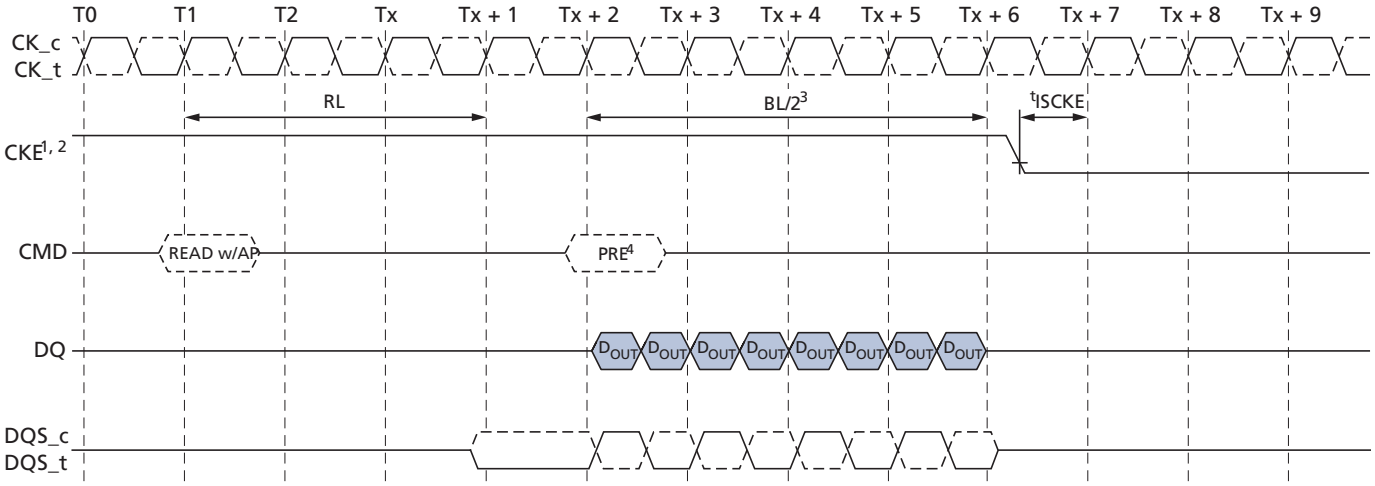
Figure 59: READ to Power-Down Entry



Notes: 1. CKE must be held HIGH until the end of the burst operation.
2. CKE can be registered LOW at {RL + RU[tDQSCK(MAX)/tCK] + BL/2 + 1} clock cycles after the clock on which the READ command is registered.

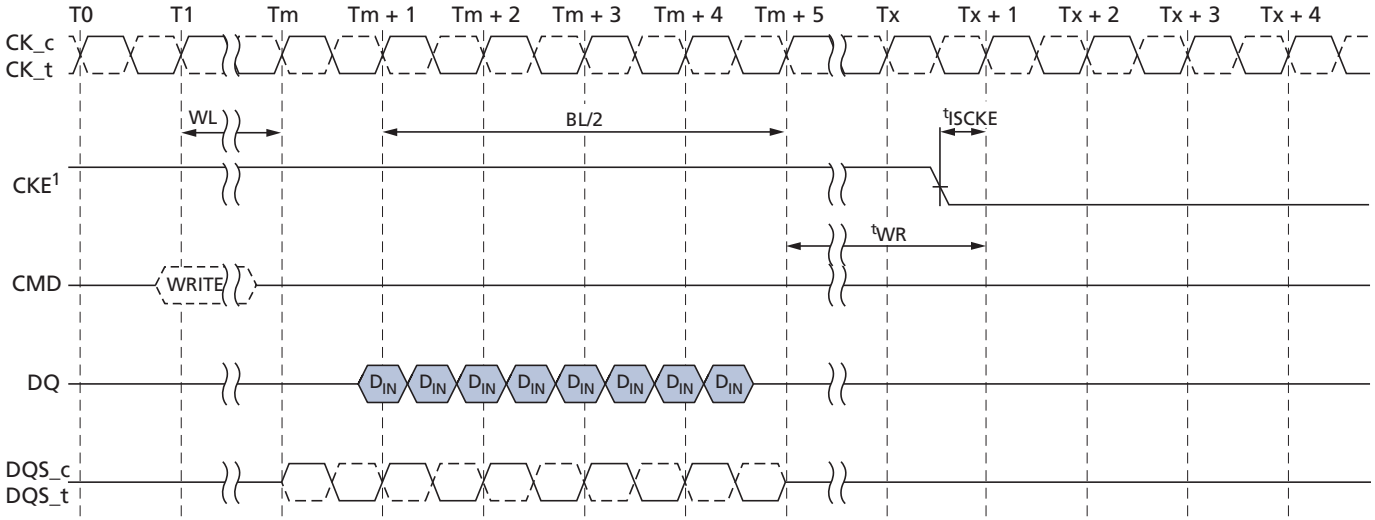
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Figure 60: READ with Auto Precharge to Power-Down Entry



Notes:
1. CKE must be held HIGH until the end of the burst operation.
2. CKE can be registered LOW at [RL + RU(^{t}DQSCK/^{t}CK) + BL/2 + 1] clock cycles after the clock on which the READ command is registered.
3. BL/2 with ^{t}RTP = 7.5ns and ^{t}RAS (MIN) is satisfied.
4. Start internal PRECHARGE.

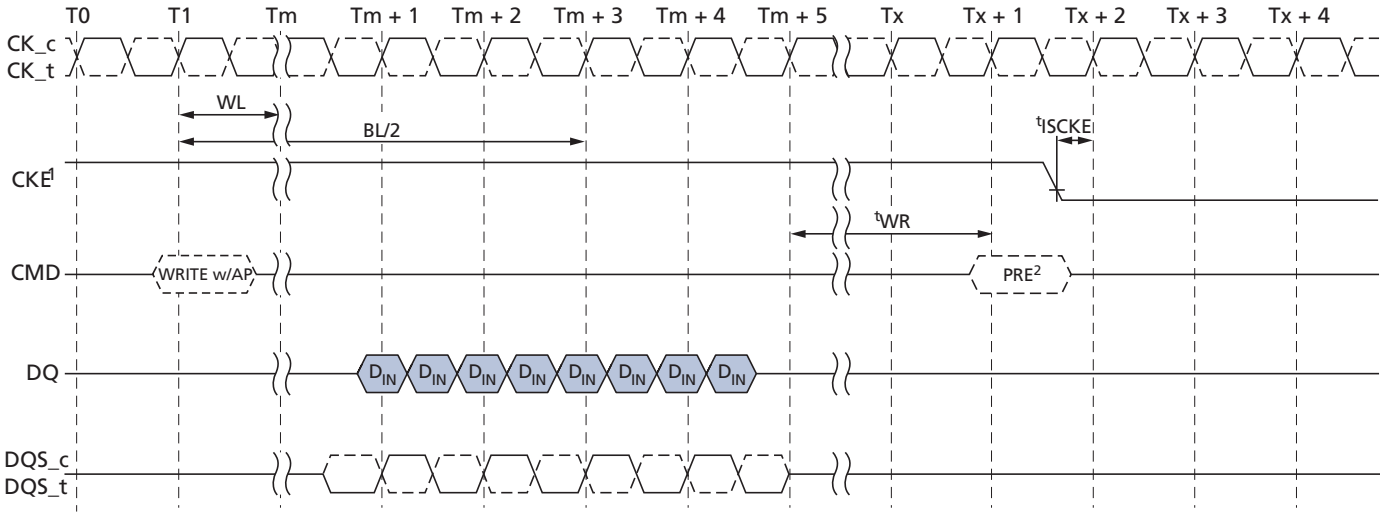
Figure 61: WRITE to Power-Down Entry



Note:
1. CKE can be registered LOW at [WL + 1 + BL/2 + RU(^{t}WR/^{t}CK)] clock cycles after the clock on which the WRITE command is registered.

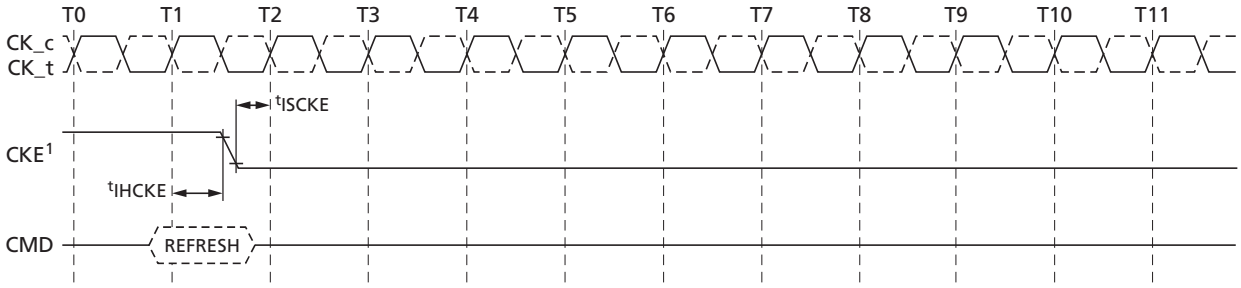
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Figure 62: WRITE with Auto Precharge to Power-Down Entry



Notes:
1. CKE can be registered LOW at [WL + 1 + BL/2 + RU(^{t}WR/^{t}CK) + 1] clock cycles after the WRITE command is registered.
2. Start internal PRECHARGE.

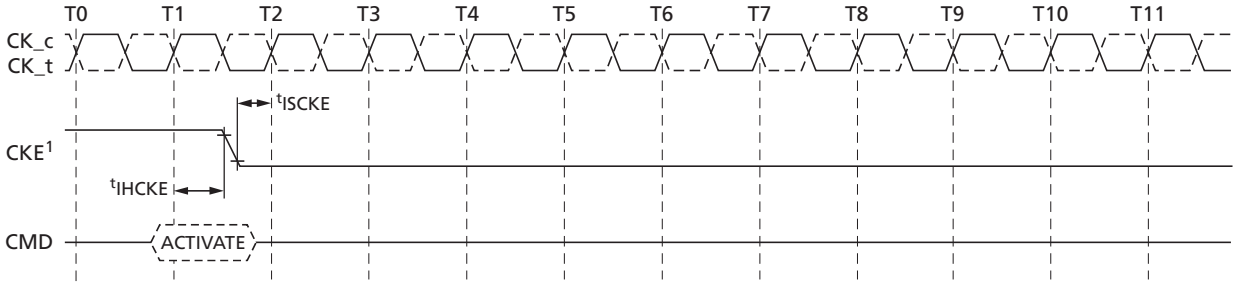
Figure 63: REFRESH Command to Power-Down Entry



Note:
1. CKE can go LOW ^{t}IHCKE after the clock on which the REFRESH command is registered.

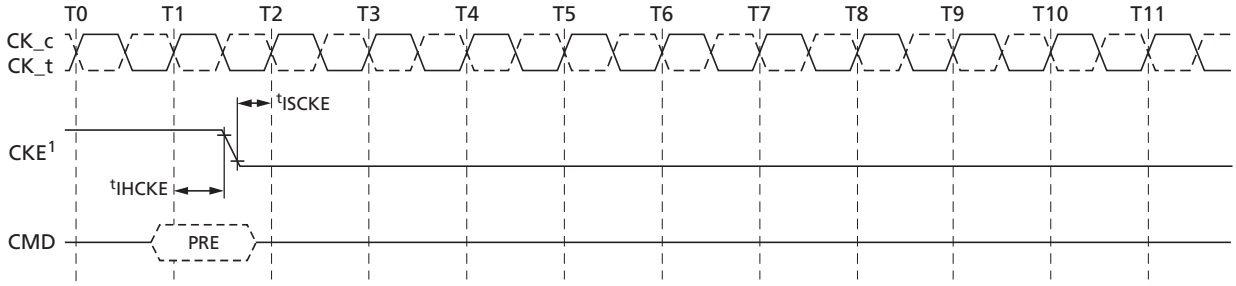
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Figure 64: ACTIVATE Command to Power-Down Entry



Note: 1. CKE can go LOW at ^{t}IHCKE after the clock on which the ACTIVATE command is registered.

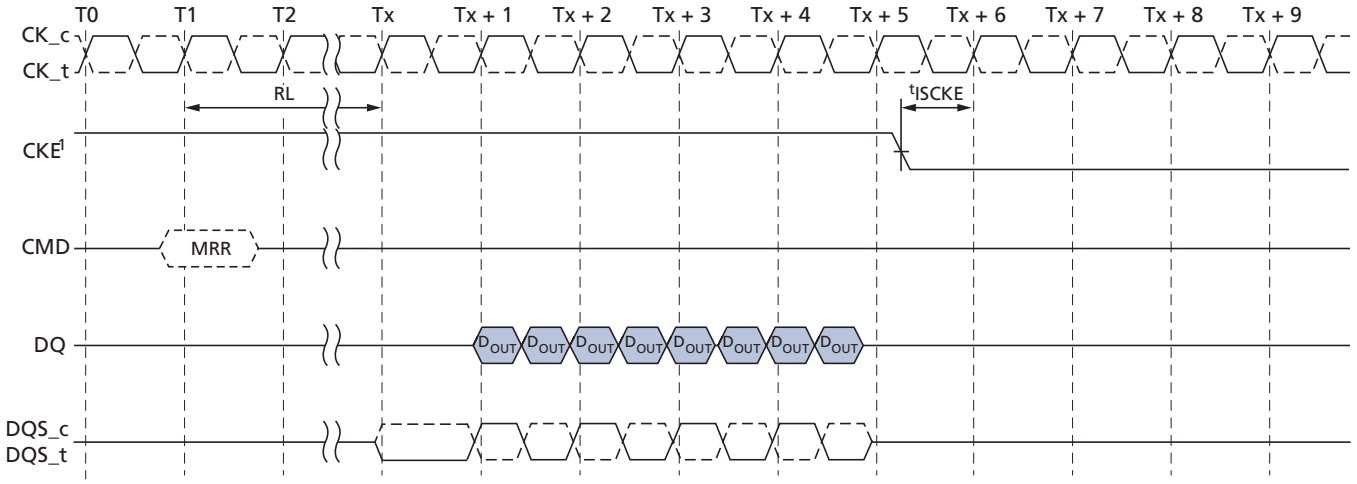
Figure 65: PRECHARGE Command to Power-Down Entry



Note: 1. CKE can go LOW ^{t}IHCKE after the clock on which the PRECHARGE command is registered.

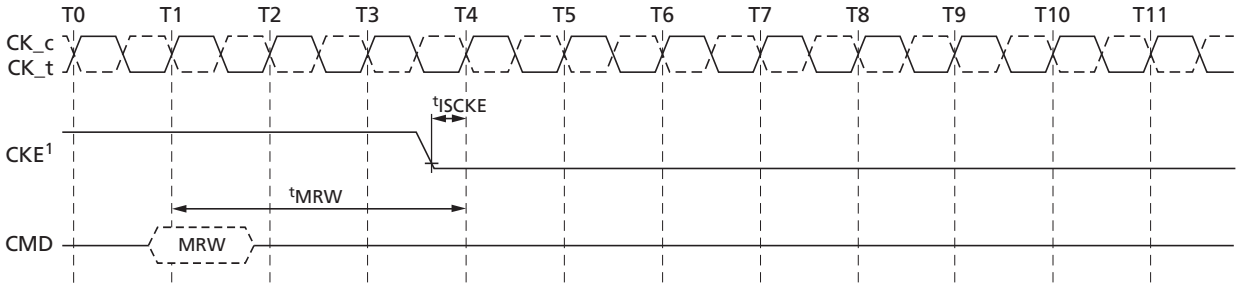
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Figure 66: MRR Power-Down Entry



Note: 1. CKE can be registered LOW at [RL + RU(^{t}DQSCK/^{t}CK)+ BL/2 + 1] clock cycles after the clock on which the MRR command is registered.

Figure 67: MRW Command to Power-Down Entry



Note: 1. CKE can be registered LOW ^{t}MRW after the clock on which the MRW command is registered.

Deep Power-Down

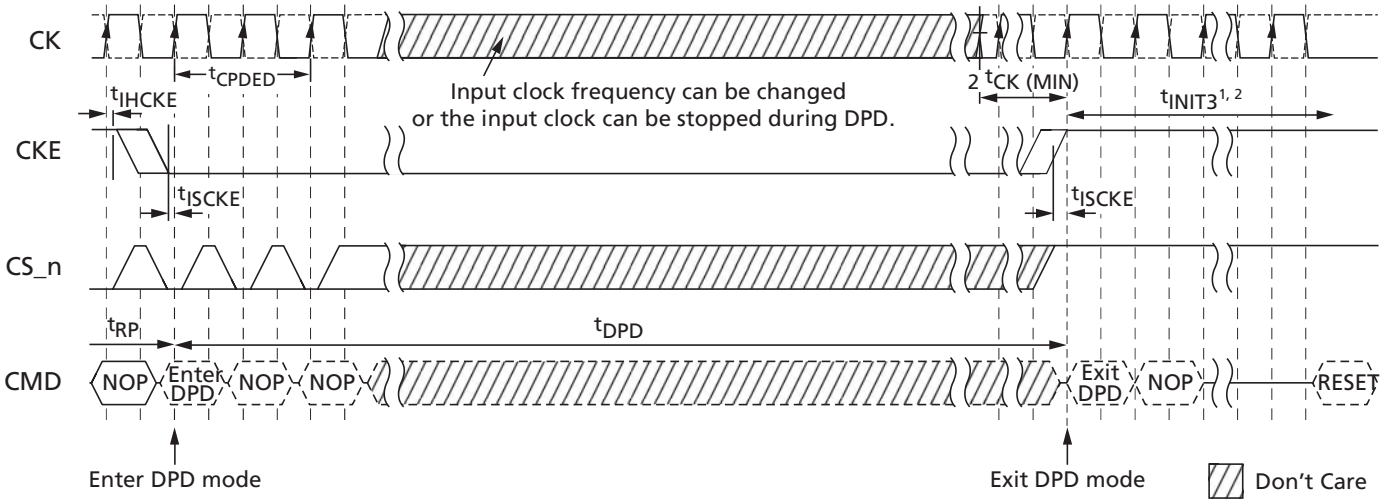
Deep power-down (DPD) is entered when CKE is registered LOW with CS_n LOW, CA0 HIGH, CA1 HIGH, and CA2 LOW at the rising edge of the clock. All banks must be in the idle state with no activity on the data bus prior to entering DPD mode. During DPD, CKE must be held LOW. The contents of the device will be lost upon entering DPD mode.

In DPD mode, all input buffers except CKE, all output buffers, and the power supply to internal circuitry are disabled within the device. To ensure that there is enough time to account for internal delay on the CKE signal path, two NOP commands are required after CKE is driven LOW; this timing period is defined as ^{t}CPDED. CKE LOW will result in deactivation of command and address receivers after ^{t}CPDED has expired. V_{REFDQ} can be at any level between 0 and V_{DDQ}, and V_{REFCA} can be at any level between 0 and V_{DDCA} during DPD. All power supplies, including V_{REF}, must be within the specified limits prior to exiting DPD (see AC and DC Operating Conditions).

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DPD mode is exited when CKE is registered HIGH while meeting tISCKE, and the clock must be stable. The device must be fully reinitialized using the power-up initialization sequence. For a description of ODT operation and specifications during DPD entry and exit, see the ODT During Deep Power-Down section.

Figure 68: Deep Power-Down Entry and Exit Timing



Notes:
1. The initialization sequence can start at any time after Tx + 1.
2. tINIT3 and Tx + 1 refer to timings in the initialization sequence. For details, see the Mode Register Definition section.

Input Clock Frequency Changes and Stop Events

Input Clock Frequency Changes and Clock Stop with CKE LOW

During CKE LOW, the device supports input clock frequency changes and clock stop under the following conditions:

- Refresh requirements are met
- Only REFab or REFpb commands can be in process
- Any ACTIVATE or PRECHARGE commands have completed prior to changing the frequency
- Related timing conditions, tRCD and tRP, have been met prior to changing the frequency
- The initial clock frequency must be maintained for a minimum of two clock cycles after CKE goes LOW
- The clock satisfies tCH(abs) and tCL(abs) for a minimum of two clock cycles prior to CKE going HIGH

For input clock frequency changes, tCK (MIN) and tCK (MAX) must be met for each clock cycle.

After the input clock frequency changes and CKE is held HIGH, additional MRW commands may be required to set the WR, RL, and so on. These settings may require adjustment to meet minimum timing requirements at the target clock frequency.

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For clock stop, CK_t is held LOW and CK_c is held HIGH.

Input Clock Frequency Changes and Clock Stop with CKE HIGH

During CKE HIGH, the device supports input clock frequency changes and clock stop under the following conditions:

- Refresh requirements are met
- Any ACTIVATE, READ, WRITE, PRECHARGE, MRW, or MRR commands have completed, including any associated data bursts, prior to changing the frequency
- Related timing conditions, ^{t}RCD, ^{t}WR, ^{t}WRA, ^{t}RP, ^{t}MRW, ^{t}MRR, and so on, are met
- CS_n must be held HIGH
- Only REFab or REFpb commands can be in process

The device is ready for normal operation after the clock satisfies ^{t}CH(abs) and ^{t}CL(abs) for a minimum of 2 × ^{t}CK + ^{t}XP.

After the input clock frequency changes, ^{t}CK (MIN) and ^{t}CK (MAX) must be met for each clock cycle.

After the input clock frequency changes, additional MRW commands may be required to set the WR, RL, and so on. These settings may require adjustment to meet minimum timing requirements at the target clock frequency.

For clock stop, CK_t is held LOW and CK_c is held HIGH.

NO OPERATION Command

The NO OPERATION (NOP) command prevents the device from registering any unwanted commands issued between operations. A NOP command can be issued only at clock cycle *n* when the CKE level is constant for clock cycle *n* - 1 and clock cycle *n*. A NOP command has two possible encodings:

1. CS_n HIGH at the clock rising edge *n*.

2. CS_n LOW with CA0, CA1, CA2 HIGH at the clock rising edge *n*.

The NOP command does not terminate a previous operation that is still in process, such as a READ burst or WRITE burst cycle.

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Truth Tables

Truth tables provide complementary information to the state diagram. They also clarify device behavior and applicable restrictions when considering the actual state of the banks.

Unspecified operations and timings are illegal. To ensure proper operation after an illegal event, the device must be powered down and then restarted using the specified initialization sequence before normal operation can continue.

Table 64: Command Truth Table

Notes 1–13 apply to entire table

Command	Command Pins			CA Pins										CK Edge
	CKE		CS_n	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9	
	CK(*n*-1)	CK(*n*)												
MRW	H	H	L	L	L	L	L	MA0	MA1	MA2	MA3	MA4	MA5	↑
			X	MA6	MA7	OP0	OP1	OP2	OP3	OP4	OP5	OP6	OP7	↓
MRR	H	H	L	L	L	L	H	MA0	MA1	MA2	MA3	MA4	MA5	↑
			X	MA6	MA7	X								↓
REFRESH (per bank)	H	H	L	L	L	H	L	X						↑
			X	X										↓
REFRESH (all banks)	H	H	L	L	L	H	H	X						↑
			X	X										↓
Enter self refresh	H	L	L	L	L	H	X							↑
	X		X	X										↓
ACTIVATE (bank)	H	H	L	L	H	R8	R9	R10	R11	R12	BA0	BA1	BA2	↑
			X	R0	R1	R2	R3	R4	R5	R6	R7	R13	R14	↓
WRITE (bank)	H	H	L	H	L	L	RFU	RFU	C1	C2	BA0	BA1	BA2	↑
			X	AP	C3	C4	C5	C6	C7	C8	C9	C10	C11	↓
READ (bank)	H	H	L	H	L	H	RFU	RFU	C1	C2	BA0	BA1	BA2	↑
			X	AP	C3	C4	C5	C6	C7	C8	C9	C10	C11	↓
PRECHARGE (per bank, all banks)	H	H	L	H	H	L	H	AB	X	X	BA0	BA1	BA2	↑
			X	X										↓
ENTER DPD	H	L	L	H	H	L	X							↑
	X		X	X										↓
NOP	H	H	L	H	H	H	X							↑
			X	X										↓
MAINTAIN PD, SREF, DPD (NOP)	L	L	L	H	H	H	X							↑
			X	X										↓
NOP	H	H	H	X										↑
			X	X										↓

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Table 64: Command Truth Table (Continued)

Notes 1–13 apply to entire table

Command	Command Pins			CA Pins										CK Edge
	CKE		CS_n	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9	
	CK(*n*-1)	CK(*n*)												
MAINTAIN PD, SREF, DPD	L	L	X	X										↑
			X	X										↓
ENTER POWER-DOWN	H	L	H	X										↑
	X		X	X										↓
Exit PD, SREF, DPD	L	H	H	X										↑
	X		X	X										↓

Notes:
1. All commands are defined by the current state of CS_n, CA0, CA1, CA2, CA3, and CKE at the rising edge of the clock.
2. Bank addresses (BA) determine which bank will be operated upon.
3. AP HIGH during a READ or WRITE command indicates that an auto precharge will occur to the bank associated with the READ or WRITE command.
4. X indicates a "Don't Care" state, with a defined logic level, either HIGH (H) or LOW (L). For PD, SREF and DPD, CS_n, CK can be floated after ^{t}CPDED has been met and until the required exit procedure is initiated as described in their respective entry/exit procedures.
5. Self refresh exit and DPD exit are asynchronous.
6. V_{REF} must be between 0 and V_{DDQ} during SREF and DPD operation.
7. CAxr refers to command/address bit "x" on the rising edge of clock.
8. CAxf refers to command/address bit "x" on the falling edge of clock.
9. CS_n and CKE are sampled on the rising edge of the clock.
10. The least significant column address C0 is not transmitted on the CA bus, and is inferred to be zero.
11. AB HIGH during a PRECHARGE command indicates that an all-bank precharge will occur. In this case, bank address is a "Don't Care."
12. RFU needs to input H or L (defined logic level).
13. When CS_n is HIGH, the CA bus can be floated.

Table 65: CKE Truth Table

Notes 1–5 apply to entire table; L = LOW; H = HIGH; X = "Don't Care"

Current State	CKE*n*-1	CKE*n*	CS_n	Command *n*	Operation *n*	Next State	Notes
Active power-down	L	L	X	X	Maintain active power-down	Active power-down	
	L	H	H	NOP	Exit active power-down	Active	6, 7
Idle power-down	L	L	X	X	Maintain idle power-down	Idle power-down	
	L	H	H	NOP	Exit idle power-down	Idle	6, 7
Resetting idle power-down	L	L	X	X	Maintain resetting power-down	Resetting power-down	
	L	H	H	NOP	Exit resetting power-down	Idle or resetting	6, 7, 8

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Table 65: CKE Truth Table (Continued)

Notes 1–5 apply to entire table; L = LOW; H = HIGH; X = "Don't Care"

Current State	CKE*n*-1	CKE*n*	CS_n	Command *n*	Operation *n*	Next State	Notes
Deep power-down	L	L	X	X	Maintain deep power-down	Deep power-down	
	L	H	H	NOP	Exit deep power-down	Power-on	9
Self refresh	L	L	X	X	Maintain self refresh	Self refresh	
	L	H	H	NOP	Exit self refresh	Idle	10, 11
Bank(s) active	H	L	H	NOP	Enter active power-down	Active power-down	
All banks idle	H	L	H	NOP	Enter idle power-down	Idle power-down	12
	H	L	L	ENTER SELF REFRESH	Enter self refresh	Self refresh	12
	H	L	L	DPD	Enter deep power-down	Deep power-down	12
Resetting	H	L	H	NOP	Enter resetting power-down	Resetting power-down	
Other states	H	H	Refer to the command truth table				

Notes:
1. Current state is the state of the device immediately prior to clock edge *n*.
2. All states and sequences not shown are illegal or reserved unless explicitly described elsewhere in this document.
3. CKE*n* is the logic state of CKE at clock rising edge *n*; CKE*n*-1 was the state of CKE at the previous clock edge.
4. CS_n is the logic state of CS_n at the clock rising edge *n*.
5. Command *n* is the command registered at clock edge *n*, and operation *n* is a result of command *n*.
6. Power-down exit time (^{t}XP) must elapse before any command other than NOP is issued.
7. The clock must toggle at least twice prior to the ^{t}XP period.
8. Upon exiting the resetting power-down state, the device will return to the idle state if ^{t}INIT5 has expired.
9. The DPD exit procedure must be followed as described in Deep Power-Down.
10. Self refresh exit time (^{t}XSR) must elapse before any command other than NOP is issued.
11. The clock must toggle at least twice prior to the ^{t}XSR time.
12. In the case of ODT disabled, all DQ output must be High-Z. In the case of ODT enabled, all DQ must be terminated to V_{DDQ}.

Table 66: Current State Bank *n* to Command to Bank *n* Truth Table

Notes 1–5 apply to entire table

Current State	Command	Operation	Next State	Notes
Any	NOP	Continue previous operation	Current state	

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Table 66: Current State Bank *n* to Command to Bank *n* Truth Table (Continued)

Notes 1–5 apply to entire table

Current State	Command	Operation	Next State	Notes
Idle	ACTIVATE	Select and activate row	Active	
	REFRESH (per bank)	Begin to refresh	Refreshing (per bank)	6
	REFRESH (all banks)	Begin to refresh	Refreshing (all banks)	7
	MRW	Load value to mode register	MR writing	7
	MRR	Read value from mode register	Idle, MR reading	
	RESET	Begin device auto initialization	Resetting	7, 8
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	9, 10
Row active	READ	Select column and start read burst	Reading	
	WRITE	Select column and start write burst	Writing	
	MRR	Read value from mode register	Active MR reading	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	9
Reading	READ	Select column and start new read burst	Reading	11, 12
	WRITE	Select column and start write burst	Writing	11, 12, 13
Writing	WRITE	Select column and start new write burst	Writing	11, 12
	READ	Select column and start read burst	Reading	11, 12, 14
Power-on	MRW RESET	Begin device auto initialization	Resetting	7, 9
Resetting	MRR	Read value from mode register	Resetting MR reading	

Notes:

1. Values in this table apply when both CKE*n* -1 and CKE*n* are HIGH, and after ^{t}XSR or ^{t}XP has been met, if the previous state was power-down.
2. All states and sequences not shown are illegal or reserved.
3. Current state definitions:

State	Definition
Idle	The bank or banks have been precharged, and ^{t}RP has been met.
Active	A row in the bank has been activated, and ^{t}RCD has been met. No data bursts or accesses, and no register accesses, are in progress.
Reading	A READ burst has been initiated with auto precharge disabled, and has not yet terminated.
Writing	A WRITE burst has been initiated with auto precharge disabled, and has not yet terminated.

4. The states listed below must not be interrupted by a command issued to the same bank. NOP commands or supported commands to the other bank should be issued on any clock edge occurring during these states. Supported commands to the other banks are determined by that bank's current state, and the definitions given in the table: Current State Bank *n* to Command to Bank *m*.

State	Starts with...	Ends when...	Notes
Precharging	Registration of a PRECHARGE command	^{t}RP is met	After ^{t}RP is met, the bank is in the idle state.
Row activating	Registration of an ACTIVATE command	^{t}RCD is met	After ^{t}RCD is met, the bank is in the active state.

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State	Starts with...	Ends when...	Notes
READ with AP enabled	Registration of a READ command with auto precharge enabled	^{t}RP is met	After ^{t}RP is met, the bank is in the idle state.
WRITE with AP enabled	Registration of a WRITE command with auto precharge enabled	^{t}RP is met	After ^{t}RP is met, the bank is in the idle state.

5. The states listed below must not be interrupted by any executable command. NOP commands must be applied to each positive clock edge during these states.

State	Starts with...	Ends when...	Notes
Refreshing (per bank)	Registration of a REFRESH (per bank) command	^{t}RFCpb is met	After ^{t}RFCpb is met, the bank is in the idle state.
Refreshing (all banks)	Registration of a REFRESH (all banks) command	^{t}RFCab is met	After ^{t}RFCab is met, the device is in the all banks idle state.
Idle MR reading	Registration of the MRR command	^{t}MRR is met	After ^{t}MRR is met, the device is in the all banks idle state.
Resetting MR reading	Registration of the MRR command	^{t}MRR is met	After ^{t}MRR is met, the device is in the all banks idle state.
Active MR reading	Registration of the MRR command	^{t}MRR is met	After ^{t}MRR is met, the bank is in the active state.
MR writing	Registration of the MRW command	^{t}MRW is met	After ^{t}MRW is met, the device is in the all banks idle state.
Precharging all	Registration of a PRECHARGE ALL command	^{t}RP is met	After ^{t}RP is met, the device is in the all banks idle state.

6. Bank-specific; requires that the bank is idle and no bursts are in progress.
7. Not bank-specific; requires that all banks are idle and no bursts are in progress.
8. Not bank-specific.
9. This command may or may not be bank-specific. If all banks are being precharged, they must be in a valid state for precharging.
10. If a PRECHARGE command is issued to a bank in the idle state, ^{t}RP still applies.
11. A command other than NOP should not be issued to the same bank while a READ or WRITE with auto precharge is enabled.
12. The new READ or WRITE command could be auto precharge enabled or auto precharge disabled.
13. A WRITE command can be issued only after the completion of the READ burst.
14. A READ command can be issued only after completion of the WRITE burst.

Table 67: Current State Bank *n* to Command to Bank *m* Truth Table

Notes 1–6 apply to entire table

Current State of Bank *n*	Command to Bank *m*	Operation	Next State for Bank *m*	Notes
Any	NOP	Continue previous operation	Current state of bank *m*	

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Table 67: Current State Bank *n* to Command to Bank *m* Truth Table (Continued)

Notes 1–6 apply to entire table

Current State of Bank *n*	Command to Bank *m*	Operation	Next State for Bank *m*	Notes
Idle	Any	Any command supported to bank *m*	–	
Row activating, active, or pre-charging	ACTIVATE	Select and activate row in bank *m*	Active	6
	READ	Select column and start READ burst from bank *m*	Reading	7
	WRITE	Select column and start WRITE burst to bank *m*	Writing	7
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	8
	MRR	READ value from mode register	Idle MR reading or active MR reading	9, 10, 11
Reading (auto precharge disabled)	READ	Select column and start READ burst from bank *m*	Reading	7
	WRITE	Select column and start WRITE burst to bank *m*	Writing	7, 12
	ACTIVATE	Select and activate row in bank *m*	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	8
Writing (auto precharge disabled)	READ	Select column and start READ burst from bank *m*	Reading	7, 13
	WRITE	Select column and start WRITE burst to bank *m*	Writing	7
	ACTIVATE	Select and activate row in bank *m*	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	8
Reading with auto precharge	READ	Select column and start READ burst from bank *m*	Reading	7, 14
	WRITE	Select column and start WRITE burst to bank *m*	Writing	7, 12, 14
	ACTIVATE	Select and activate row in bank *m*	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	8
Writing with auto precharge	READ	Select column and start READ burst from bank *m*	Reading	7, 13, 14
	WRITE	Select column and start WRITE burst to bank *m*	Writing	7, 14
	ACTIVATE	Select and activate row in bank *m*	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	8
Power-on	MRW RESET	Begin device auto initialization	Resetting	15, 16
Resetting	MRR	Read value from mode register	Resetting MR reading	

Notes: 1. This table applies when:

- The previous state was self refresh or power-down;
- After ^{t}XSR or ^{t}XP has been met; and

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- When both CKE*n* -1 and CKE*n* are HIGH.

2. All states and sequences not shown are illegal or reserved.
3. Current state definitions:

State	Condition	And...	And...
Idle	The bank has been pre-charged	^{t}RP is met	
Active	A row in the bank has been activated	^{t}RCD is met	No data bursts/accesses and no register accesses are in progress.
Reading	A READ burst has been initiated with auto precharge disabled	The READ has not yet terminated	
Writing	A WRITE burst has been initiated with auto precharge disabled	The WRITE has not yet terminated	

4. Refresh, self refresh, and MRW commands can only be issued when all banks are idle.
5. The states listed below must not be interrupted by any executable command. NOP commands must be applied during each clock cycle while in these states:

State	Starts with...	Ends when...	Notes
Idle MR reading	Registration of the MRR command	^{t}MRR is met	After ^{t}MRR is met, the device is in the all banks idle state.
Resetting MR reading	Registration of the MRR command	^{t}MRR is met	After ^{t}MRR is met, the device is in the all banks reset state.
Active MR reading	Registration of the MRR command	^{t}MRR is met	After ^{t}MRR is met, the bank is in the active state.
MR writing	Registration of the MRW command	^{t}MRW is met	After ^{t}MRW is met, the device is in the all banks idle state.

6. ^{t}RRD must be met between the ACTIVATE command to bank *n* and any subsequent ACTIVATE command to bank *m*.
7. READs or WRITEs listed in the command column include READs and WRITEs with or without auto precharge enabled.
8. This command may or may not be bank-specific. If all banks are being precharged, they must be in a valid state for precharging.
9. MRR is supported in the row-activating state.
10. MRR is supported in the precharging state.
11. The next state for bank *m* depends on the current state of bank *m* (idle, row-activating, precharging, or active).
12. A WRITE command can be issued only after the completion of the READ burst.
13. A READ command can be issued only after the completion of the WRITE burst.
14. A READ with auto precharge enabled or a WRITE with auto precharge enabled can be followed by any valid command to other banks, provided that the timing restrictions in the PRECHARGE and Auto Precharge Clarification table are met.
15. Not bank-specific; requires that all banks are idle and no bursts are in progress.
16. RESET command is achieved through the MODE REGISTER WRITE command.

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Table 68: DM Truth Table

Functional Name	DM	DQ	Notes
Write enable	L	Valid	1
Write inhibit	H	X	1

Note: 1. Used to mask write data; provided simultaneously with the corresponding input data.

Absolute Maximum Ratings

Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these conditions, or any other conditions outside those indicated in the operational sections of this document, is not implied. Exposure to absolute maximum rating conditions for extended periods may adversely affect reliability.

Table 69: Absolute Maximum DC Ratings

Parameter	Symbol	Min	Max	Unit	Notes
V_{DD1} supply voltage relative to V_{SS}	V_{DD1}	–0.4	2.3	V	1
V_{DD2} supply voltage relative to V_{SS}	V_{DD2}	–0.4	1.6	V	1
V_{DDCA} supply voltage relative to V_{SSCA}	V_{DDCA}	–0.4	1.6	V	1, 2
V_{DDQ} supply voltage relative to V_{SSQ}	V_{DDQ}	–0.4	1.6	V	1, 3
Voltage on any ball relative to V_{SS}	V_{IN}, V_{OUT}	–0.4	1.6	V	
Storage temperature	T_{STG}	–55	125	°C	4

Notes:
1. For information about relationships between power supplies, see the Power-Up and Initialization section.
2. $V_{REFCA} \leq 0.6 \times V_{DDCA}$; however, V_{REFCA} may be $\geq V_{DDCA}$, provided that $V_{REFCA} \leq 300$mV.
3. $V_{REFDQ} \leq 0.7 \times V_{DDQ}$; however, V_{REFDQ} may be $\geq V_{DDQ}$, provided that $V_{REFDQ} \leq 300$mV.
4. Storage temperature is the case surface temperature on the center/top side of the device. For measurement conditions, refer to the JESD51-2 standard.

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Electrical Specifications – I_{DD} Measurements and Conditions

The following definitions and conditions are used in the I_{DD} measurement tables unless stated otherwise:

- LOW: $V_{IN} \leq V_{IL(DC)max}$
- HIGH: $V_{IN} \geq V_{IH(DC)min}$
- STABLE: Inputs are stable at a HIGH or LOW level
- SWITCHING: See the following three tables

Table 70: Switching for CA Input Signals

	CK_t (Rising)/ CK_c (Falling)		CK_t (Falling)/ CK_c (Rising)		CK_t (Rising)/ CK_c (Falling)		CK_t (Falling)/ CK_c (Rising)	
Cycle	N		N + 1		N + 2		N + 3	
CS_n	HIGH		HIGH		HIGH		HIGH	
CA0	H	L	L	L	L	H	H	H
CA1	H	H	H	L	L	L	L	H
CA2	H	L	L	L	L	H	H	H
CA3	H	H	H	L	L	L	L	H
CA4	H	L	L	L	L	H	H	H
CA5	H	H	H	L	L	L	L	H
CA6	H	L	L	L	L	H	H	H
CA7	H	H	H	L	L	L	L	H
CA8	H	L	L	L	L	H	H	H
CA9	H	H	H	L	L	L	L	H

Notes:
1. CS_n must always be driven HIGH.
2. For each clock cycle, 50% of the CA bus is changing between HIGH and LOW.
3. The noted pattern (N, N + 1, N + 2, N + 3...) is used continuously during I_{DD} measurement for I_{DD} values that require switching on the CA bus.

Table 71: Switching for I_{DD4R}

Clock	CKE	CS_n	Clock Cycle Number	Command	CA[2:0]	CA[9:3]	All DQ
Rising	H	L	N	Read_Rising	HLH	LHLHLHL	L
Falling	H	L	N	Read_Falling	LLL	LLLLLLL	L
Rising	H	H	N + 1	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 1	NOP	LLL	LLLLLLL	L
Rising	H	H	N + 2	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 2	NOP	LLL	LLLLLLL	H
Rising	H	H	N + 3	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 3	NOP	HLH	LHLLHLH	L

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Table 71: Switching for I_{DD4R} (Continued)

Clock	CKE	CS_n	Clock Cycle Number	Command	CA[2:0]	CA[9:3]	All DQ
Rising	H	L	N + 4	Read_Rising	HLH	LHLLHLH	H
Falling	H	L	N + 4	Read_Falling	HHL	HHHHHHH	H
Rising	H	H	N + 5	NOP	HHH	HHHHHHH	H
Falling	H	H	N + 5	NOP	HHH	HHHHHHH	L
Rising	H	H	N + 6	NOP	HHH	HHHHHHH	L
Falling	H	H	N + 6	NOP	HHH	HHHHHHH	L
Rising	H	H	N + 7	NOP	HHH	HHHHHHH	H
Falling	H	H	N + 7	NOP	HLH	LHLHLHL	L

Notes:
1. Data strobe (DQS_t) is changing between HIGH and LOW with every clock cycle.
2. The noted pattern (N, N + 1...) is used continuously during I_{DD} measurement for I_{DD4R}.

Table 72: Switching for I_{DD4W}

Clock	CKE	CS_n	Clock Cycle Number	Command	CA[2:0]	CA[9:3]	All DQ
Rising	H	L	N	Write_Rising	LLH	LHLHLHL	L
Falling	H	L	N	Write_Falling	LLL	LLLLLLL	L
Rising	H	H	N + 1	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 1	NOP	LLL	LLLLLLL	L
Rising	H	H	N + 2	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 2	NOP	LLL	LLLLLLL	H
Rising	H	H	N + 3	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 3	NOP	LLH	LHLLHLH	L
Rising	H	L	N + 4	Write_Rising	LLH	LHLLHLH	H
Falling	H	L	N + 4	Write_Falling	HHL	HHHHHHH	H
Rising	H	H	N + 5	NOP	HHH	HHHHHHH	H
Falling	H	H	N + 5	NOP	HHH	HHHHHHH	L
Rising	H	H	N + 6	NOP	HHH	HHHHHHH	L
Falling	H	H	N + 6	NOP	HHH	HHHHHHH	L
Rising	H	H	N + 7	NOP	HHH	HHHHHHH	H
Falling	H	H	N + 7	NOP	LLH	LHLHLHL	L

Notes:
1. Data strobe (DQS_t) is changing between HIGH and LOW with every clock cycle.
2. Data masking (DM) must always be driven LOW.
3. The noted pattern (N, N + 1...) is used continuously during I_{DD} measurement for I_{DD4W}.

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I_{DD} Specifications

I_{DD} values are for the entire operating voltage range, and all of them are for the entire standard range, with the exception of I_{DD6ET}, which is for the entire extended temperature range.

Table 73: I_{DD} Specification Parameters and Operating Conditions

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V
Notes 1, 2, 3, and 5 apply to entire table; Note 4 applies to all "in" values

Parameter/Condition	Symbol	Power Supply	Notes
Operating one bank active-precharge current: $^{t}CK = {}^{t}CK$ (MIN); $^{t}RC = {}^{t}RC$ (MIN); CKE is HIGH; CS_n is HIGH between valid commands; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD01}	V_{DD1}	
	I_{DD02}	V_{DD2}	
	$I_{DD0,in}$	V_{DDCA}, V_{DDQ}	2
Idle power-down standby current: $^{t}CK = {}^{t}CK$ (MIN); CKE is LOW; CS_n is HIGH; All banks are idle; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD2P1}	V_{DD1}	
	I_{DD2P2}	V_{DD2}	
	$I_{DD2P,in}$	V_{DDCA}, V_{DDQ}	2
Idle power-down standby current with clock stop: CK_t = LOW, CK_c = HIGH; CKE is LOW; CS_n is HIGH; All banks are idle; CA bus inputs are stable; Data bus inputs are stable; ODT is disabled	I_{DD2PS1}	V_{DD1}	
	I_{DD2PS2}	V_{DD2}	
	$I_{DD2PS,in}$	V_{DDCA}, V_{DDQ}	2
Idle non-power-down standby current: $^{t}CK = {}^{t}CK$ (MIN); CKE is HIGH; CS_n is HIGH; All banks are idle; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD2N1}	V_{DD1}	
	I_{DD2N2}	V_{DD2}	
	$I_{DD2N,in}$	V_{DDCA}, V_{DDQ}	2
Idle non-power-down standby current with clock stopped: CK_t = LOW; CK_c = HIGH; CKE is HIGH; CS_n is HIGH; All banks are idle; CA bus inputs are stable; Data bus inputs are stable; ODT is disabled	I_{DD2NS1}	V_{DD1}	
	I_{DD2NS2}	V_{DD2}	
	$I_{DD2NS,in}$	V_{DDCA}, V_{DDQ}	2
Active power-down standby current: $^{t}CK = {}^{t}CK$ (MIN); CKE is LOW; CS_n is HIGH; One bank is active; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD3P1}	V_{DD1}	
	I_{DD3P2}	V_{DD2}	
	$I_{DD3P,in}$	V_{DDCA}, V_{DDQ}	2
Active power-down standby current with clock stop: CK_t = LOW, CK_c = HIGH; CKE is LOW; CS_n is HIGH; One bank is active; CA bus inputs are stable; Data bus inputs are stable; ODT is disabled	I_{DD3PS1}	V_{DD1}	
	$I_{DD3PS22}$	V_{DD2}	
	$I_{DD3PS,in}$	V_{DDCA}, V_{DDQ}	3
Active non-power-down standby current: $^{t}CK = {}^{t}CK$ (MIN); CKE is HIGH; CS_n is HIGH; One bank is active; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD3N1}	V_{DD1}	
	I_{DD3N2}	V_{DD2}	
	$I_{DD3N,in}$	V_{DDCA}, V_{DDQ}	3
Active non-power-down standby current with clock stopped: CK_t = LOW, CK_c = HIGH; CKE is HIGH; CS_n is HIGH; One bank is active; CA bus inputs are stable; Data bus inputs are stable; ODT is disabled	I_{DD3NS1}	V_{DD1}	
	I_{DD3NS2}	V_{DD2}	
	$I_{DD3NS,in}$	V_{DDCA}, V_{DDQ}	3

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Table 73: I_{DD} Specification Parameters and Operating Conditions (Continued)

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V
Notes 1, 2, 3, and 5 apply to entire table; Note 4 applies to all "in" values

Parameter/Condition	Symbol	Power Supply	Notes
Operating burst READ current: ^{t}CK = ^{t}CK (MIN); CS_n is HIGH between valid commands; One bank is active; BL = 8; RL = RL (MIN); CA bus inputs are switching; 50% data change each burst transfer; ODT is disabled	I_{DD4R1}	V_{DD1}	
	I_{DD4R2}	V_{DD2}	
	$I_{DD4R,in}$	V_{DDCA}	
Operating burst WRITE current: ^{t}CK = ^{t}CK (MIN); CS_n is HIGH between valid commands; One bank is active; BL = 8; WL = WL (MIN); CA bus inputs are switching; 50% data change each burst transfer; ODT is disabled	I_{DD4W1}	V_{DD1}	
	I_{DD4W2}	V_{DD2}	
	$I_{DD4W,in}$	V_{DDCA}, V_{DDQ}	3
All-bank REFRESH burst current: ^{t}CK = ^{t}CK (MIN); CKE is HIGH between valid commands; ^{t}RC = ^{t}RFCab (MIN); Burst refresh; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD51}	V_{DD1}	
	I_{DD52}	V_{DD2}	
	$I_{DD5,in}$	V_{DDCA}, V_{DDQ}	3
All-bank REFRESH average current: ^{t}CK = ^{t}CK (MIN); CKE is HIGH between valid commands; ^{t}RC = ^{t}REFI; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD5AB1}	V_{DD1}	
	I_{DD5AB2}	V_{DD2}	
	$I_{DD5AB,in}$	V_{DDCA}, V_{DDQ}	3
Per-bank REFRESH average current: ^{t}CK = ^{t}CK (MIN); CKE is HIGH between valid commands; ^{t}RC = ^{t}REFI/8; CA bus inputs are switching; Data bus inputs are stable; ODT is disabled	I_{DD5PB1}	V_{DD1}	
	I_{DD5PB2}	V_{DD2}	
	$I_{DD5PB,in}$	V_{DDCA}, V_{DDQ}	3
Self refresh current (–30˚C to +85˚C): CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are stable; Data bus inputs are stable; Maximum 1x self refresh rate; ODT is disabled	I_{DD61}	V_{DD1}	4, 5
	I_{DD62}	V_{DD2}	4, 5
	$I_{DD6,in}$	V_{DDCA}, V_{DDQ}	3, 4
Self refresh current (+85˚C to +105˚C): CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are stable; Data bus inputs are stable; ODT is disabled	I_{DD6ET1}	V_{DD1}	5, 6
	I_{DD6ET2}	V_{DD2}	5, 6
	$I_{DD6ET,in}$	V_{DDCA}, V_{DDQ}	3, 5, 6
Deep power-down current: CK_t = LOW, CK_c = HIGH; CKE is LOW; CA bus inputs are stable; Data bus inputs are stable; ODT is disabled	I_{DD81}	V_{DD1}	
	I_{DD82}	V_{DD2}	
	$I_{DD8,in}$	V_{DDCA}, V_{DDQ}	3

Notes:
1. ODT disabled: MR11[2:0] = 000b.
2. I_{DD} current specifications are tested after the device is properly initialized.
3. Measured currents are the summation of V_{DDQ} and V_{DDCA}.
4. The 1x self refresh rate is the rate at which the device is refreshed internally during self refresh before going into the elevated temperature range.
5. This is the general definition that applies to full-array self-refresh.
6. I_{DD6ET} is a typical value, is sampled only, and is not tested.
7. For all I_{DD} measurements, V_{IHCKE} = 0.8 × V_{DDCA}; V_{ILCKE} = 0.2 × V_{DDCA}.

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AC and DC Operating Conditions

Operation or timing that is not specified is illegal. To ensure proper operation, the device must be initialized properly.

Table 74: Recommended DC Operating Conditions

Note 1 applies to entire table

Symbol	Min	Typ	Max	DRAM	Unit	Notes
V_{DD1}	1.70	1.80	1.95	Core power 1	V	2
V_{DD2}	1.14	1.20	1.30	Core power 2	V	
V_{DDCA}	1.14	1.20	1.30	Input buffer power	V	
V_{DDQ}	1.14	1.20	1.30	I/O buffer power	V	

Notes:
1. The voltage range is for DC voltage only. DC is defined as the voltage supplied at the DRAM and is inclusive of all noise up to 1 MHz at the DRAM package ball.
2. V_{DD1} uses significantly less power than V_{DD2}.

Table 75: Input Leakage Current

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input leakage current: For CA, CKE, CS_n, CK; Any input 0V ≤ V_{IN} ≤ V_{DDCA}; (All other pins not under test = 0V)	I_I	–2	2	µA	1
V_{REF} supply leakage current: V_{REFDQ} = V_{DDQ}/2, or V_{REFCA} = V_{DDCA}/2; (All other pins not under test = 0V)	I_{VREF}	–1	1	µA	2

Notes:
1. Although DM is for input only, the DM leakage must match the DQ and DQS output leakage specification.
2. The minimum limit requirement is for testing purposes. The leakage current on V_{REFCA} and V_{REFDQ} pins should be minimal.

Table 76: Operating Temperature Range

Notes 1 and 2 apply to entire table

Parameter/Condition	Symbol	Min	Max	Unit
Standard (WT) temperature range	T_{CASE}[1]	–30	85	°C
Wide temperature range		–30	105	°C

Notes:
1. Operating temperature is the case surface temperature at the center of the top side of the device. For measurement conditions, refer to the JESD51-2 standard.
2. Either the device operating temperature or the temperature sensor can be used to set an appropriate refresh rate, determine the need for AC timing derating, and/or monitor the operating temperature (see Temperature Sensor). When using the temperature sensor, the actual device case temperature may be higher than the T_{CASE} rating that applies for the operating temperature range. For example, T_{CASE} could be above +85°C when the temperature sensor indicates a temperature of less than +85°C.

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AC and DC Logic Input Measurement Levels for Single-Ended Signals

Table 77: Single-Ended AC and DC Input Levels for CA and CS_n Inputs

Parameter	Symbol	1333/1600		1866/2133			
		Min	Max	Min	Max	Unit	Notes
AC input logic HIGH	$V_{IHCA(AC)}$	V_{REF} + 0.150	Note 2	V_{REF} + 0.135	Note 2	V	1, 2
AC input logic LOW	$V_{ILCA(AC)}$	Note 2	V_{REF} - 0.150	Note 2	V_{REF} - 0.135	V	1, 2
DC input logic HIGH	$V_{IHCA(DC)}$	V_{REF} + 0.100	V_{DDCA}	V_{REF} + 0.100	V_{DDCA}	V	1
DC input logic LOW	$V_{ILCA(DC)}$	V_{SSCA}	V_{REF} - 0.100	V_{SSCA}	V_{REF} - 0.100	V	1
Reference voltage for CA and CS_n inputs	$V_{REFCA(DC)}$	0.49 × V_{DDCA}	0.51 × V_{DDCA}	0.49 × V_{DDCA}	0.51 × V_{DDCA}	V	3, 4

Notes:
1. For CA and CS_n input-only pins. $V_{REF} = V_{REFCA(DC)}$.
2. See figure: Overshoot and Undershoot Definition.
3. The AC peak noise on V_{REFCA} could prevent V_{REFCA} from deviating more than ±1% V_{DDCA} from $V_{REFCA(DC)}$ (for reference, approximately ±12mV).
4. For reference, approximately $V_{DDCA}/2$ ±12mV.

Table 78: Single-Ended AC and DC Input Levels for CKE

Parameter	Symbol	Min	Max	Unit	Notes
CKE input HIGH level	V_{IHCKE}	0.65 × V_{DDCA}	Note 1	V	1
CKE input LOW level	V_{ILCKE}	Note 1	0.35 × V_{DDCA}	V	1

Note:
1. See figure: Overshoot and Undershoot Definition.

Table 79: Single-Ended AC and DC Input Levels for DQ and DM

Parameter	Symbol	1333/1600		1866/2133			
		Min	Max	Min	Max	Unit	Notes
AC input logic HIGH	$V_{IHDQ(AC)}$	V_{REF} + 0.150	Note 2	V_{REF} + 0.135	Note 2	V	1, 2, 5
AC input logic LOW	$V_{ILDQ(AC)}$	Note 2	V_{REF} - 0.150	Note 2	V_{REF} - 0.135	V	1, 2, 5
DC input logic HIGH	$V_{IHDQ(DC)}$	V_{REF} + 0.100	V_{DDQ}	V_{REF} + 0.100	V_{DDQ}	V	1
DC input logic LOW	$V_{ILDQ(DC)}$	V_{SSQ}	V_{REF} - 0.100	V_{SSQ}	V_{REF} - 0.100	V	1
Reference voltage for DQ and DM inputs	$V_{REFDQ(DC)}$	0.49 × V_{DDQ}	0.51 × V_{DDQ}	0.49 × V_{DDQ}	0.51 × V_{DDQ}	V	3, 4
Reference voltage for DQ and DM inputs (DQ ODT enabled)	$V_{REFDQ(DC)}$ DQODT,enabled	$V_{ODTR}/2$ - 0.01 × V_{DDQ}	$V_{ODTR}/2$ + 0.01 × V_{DDQ}	$V_{ODTR}/2$ - 0.01 × V_{DDQ}	$V_{ODTR}/2$ + 0.01 × V_{DDQ}	V	3, 5, 6

Notes:
1. For DQ input-only pins. $V_{REF} = V_{REFDQ(DC)}$.
2. See figure: Overshoot and Undershoot Definition.
3. The AC peak noise on V_{REFDQ} could prevent V_{REFDQ} from deviating more than ±1% V_{DDQ} from $V_{REFDQ(DC)}$ (for reference, approximately ±12mV).

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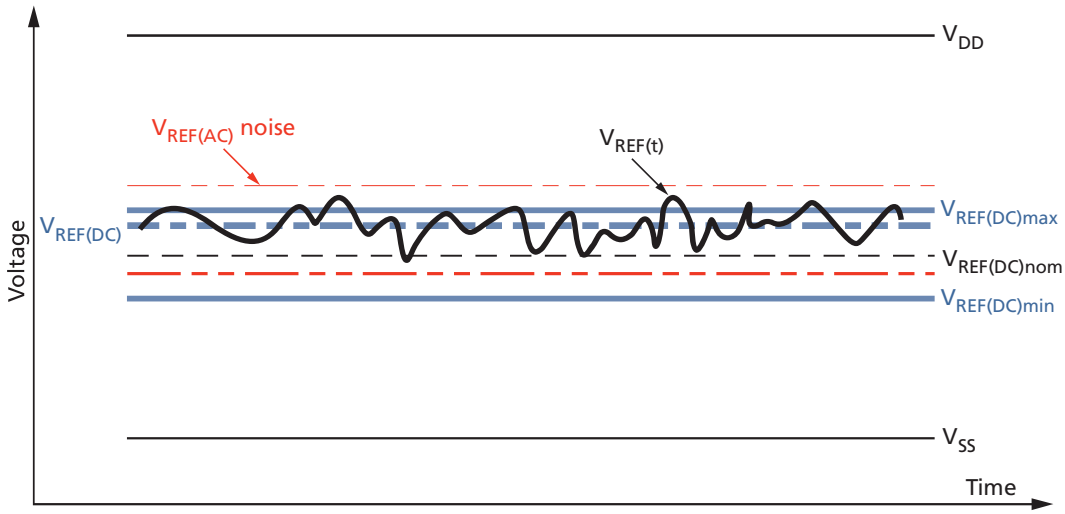
4. For reference, approximately $V_{DDQ}/2$ ±12mV.
5. For reference, approximately $V_{ODTR}/2$ ±12mV.
6. The nominal mode register programmed values for R_{ODT} and the nominal controller output impedance R_{ON} are used for the calculation of V_{ODTR}. For testing purposes, a controller R_{ON} value of 50Ω is used.

$$V_{ODTR} = \frac{2R_{ON} + R_{TT}}{R_{ON} + R_{TT}} \times V_{DDQ}$$

V_{REF} Tolerances

The DC tolerance limits and AC noise limits for the reference voltages V_{REFCA} and V_{REFDQ} are shown below. This figure shows a valid reference voltage $V_{REF}(t)$ as a function of time. V_{DD} is used in place of V_{DDCA} for V_{REFCA}, and V_{DDQ} for V_{REFDQ}. $V_{REF(DC)}$ is the linear average of $V_{REF}(t)$ over a very long period of time (for example, 1 second), and is specified as a fraction of the linear average of V_{DDQ} or V_{DDCA}, also over a very long period of time (for example, 1 second). This average must meet the MIN/MAX requirements in the table: Single-Ended AC and DC Input Levels for CA and CS_n Inputs. Additionally, $V_{REF}(t)$ can temporarily deviate from $V_{REF(DC)}$ by no more than ±1% V_{DD}. $V_{REF}(t)$ cannot track noise on V_{DDQ} or V_{DDCA} if doing so would force V_{REF} outside these specifications.

Figure 69: V_{REF} DC Tolerance and V_{REF} AC Noise Limits



The voltage levels for setup and hold time measurements $V_{IH(AC)}$, $V_{IH(DC)}$, $V_{IL(AC)}$, and $V_{IL(DC)}$ are dependent on V_{REF}. V_{REF} shall be understood as $V_{REF(DC)}$, as defined in the Single-Ended Requirements for Differential Signals figure.

V_{REF} DC variations affect the absolute voltage a signal must reach to achieve a valid HIGH or LOW, as well as the time from which setup and hold times are measured.

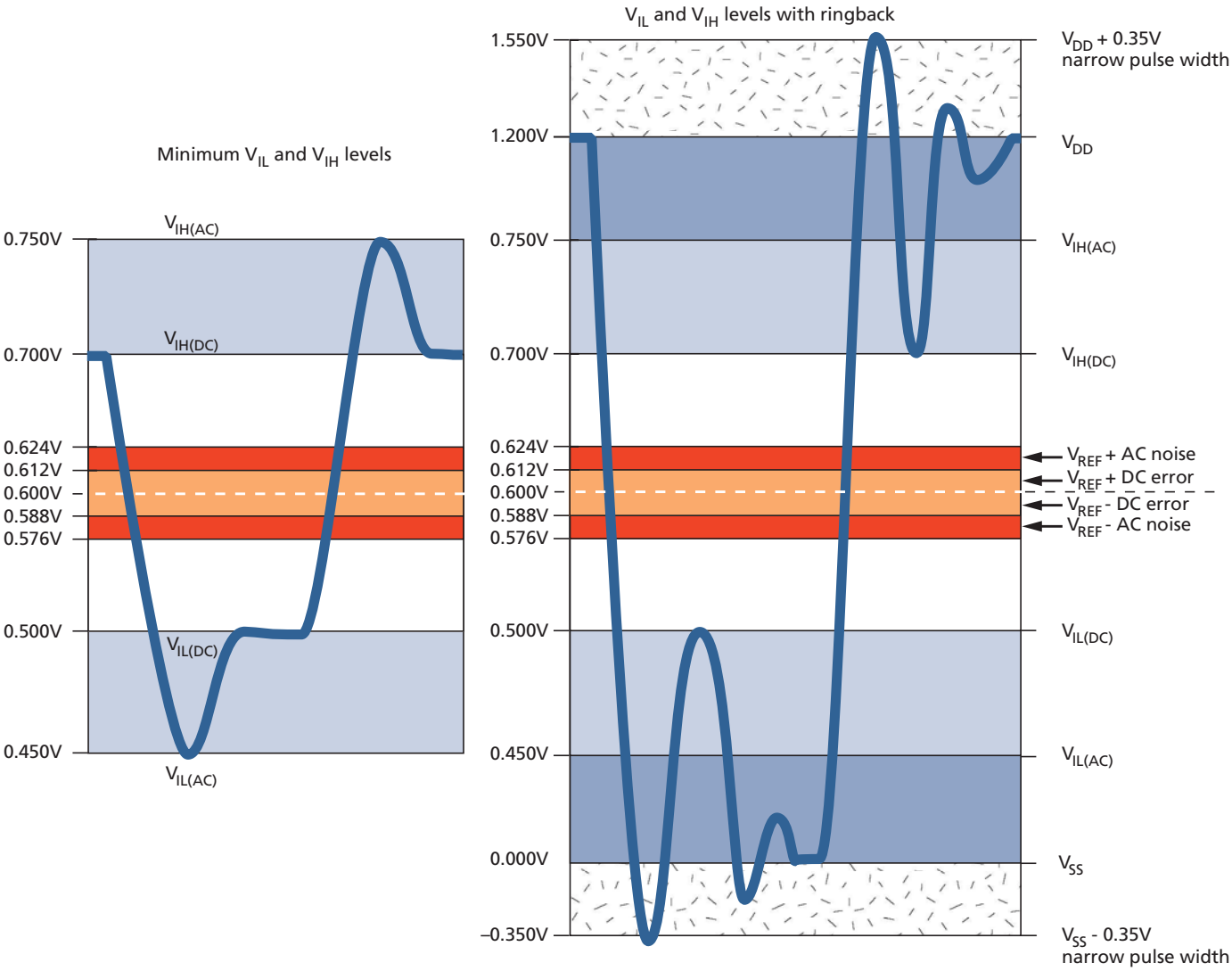
System timing and voltage budgets must account for V_{REF} deviations outside this range.

The setup/hold specification and derating values must include time and voltage associated with V_{REF} AC noise. Timing and voltage effects due to AC noise on V_{REF} up to the specified limit (±1% V_{DD}) are included in device timings and associated deratings.

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Input Signal

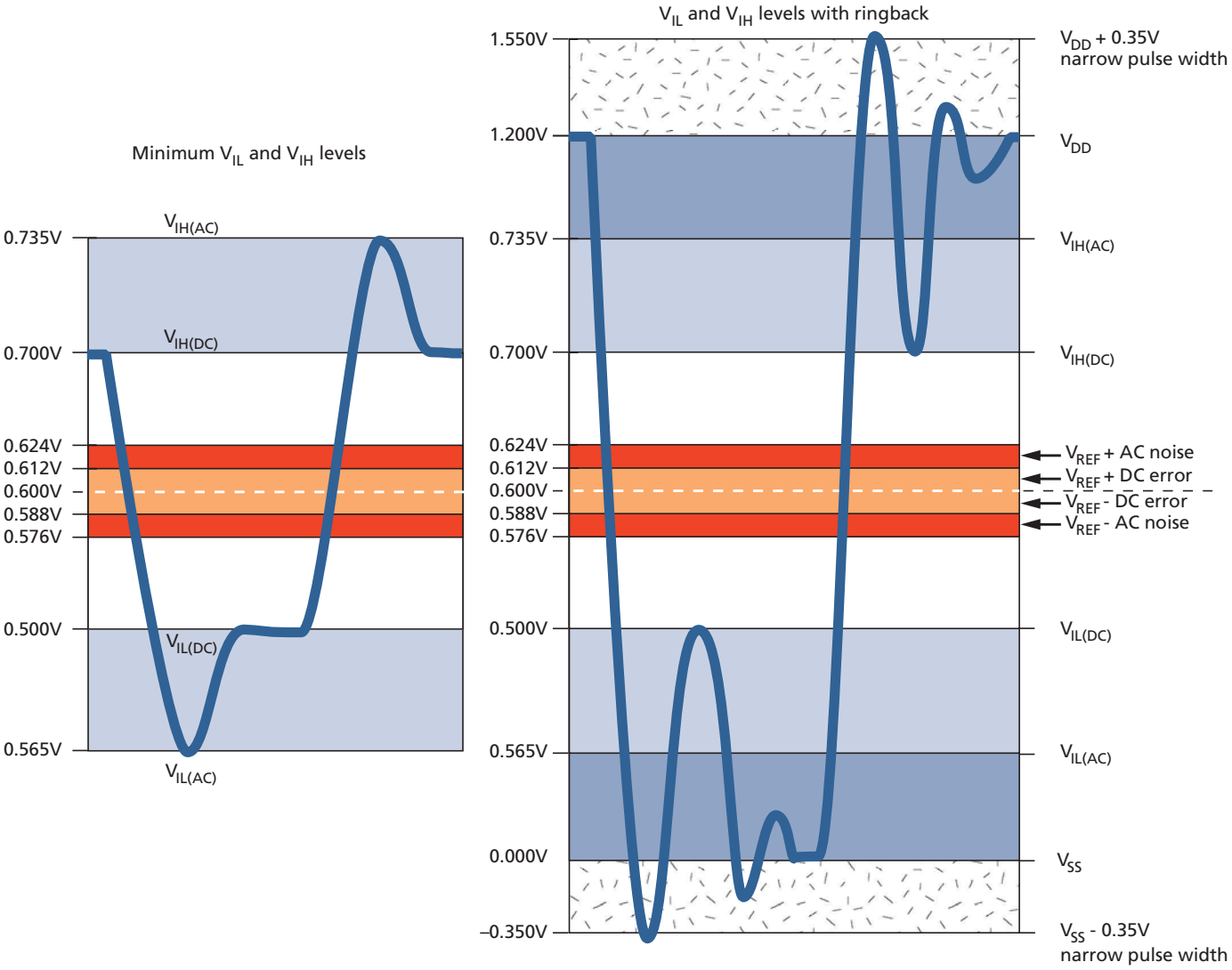
Figure 70: LPDDR3-1600 to LPDDR3-1333 Input Signal



Notes:
1. Numbers reflect typical values.
2. For CA[9:0], CK, and CS_n, V_{DD} stands for V_{DDCA}. For DQ, DM, DQS, and ODT, V_{DD} stands for V_{DDQ}.
3. For CA[9:0], CK, and CS_n, V_{SS} stands for V_{SSCA}. For DQ, DM, DQS, and ODT, V_{SS} stands for V_{SSQ}.

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Figure 71: LPDDR3-2133 to LPDDR3-1866 Input Signal



Notes:
1. Numbers reflect typical values.
2. For CA[9:0], CK, and CS_n, V_{DD} stands for V_{DDCA}. For DQ, DM, DQS, and ODT, V_{DD} stands for V_{DDQ}.
3. For CA[9:0], CK, and CS_n, V_{SS} stands for V_{SSCA}. For DQ, DM, DQS, and ODT, V_{SS} stands for V_{SSQ}.

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AC and DC Logic Input Measurement Levels for Differential Signals

Figure 72: Differential AC Swing Time and ^{t}DVAC

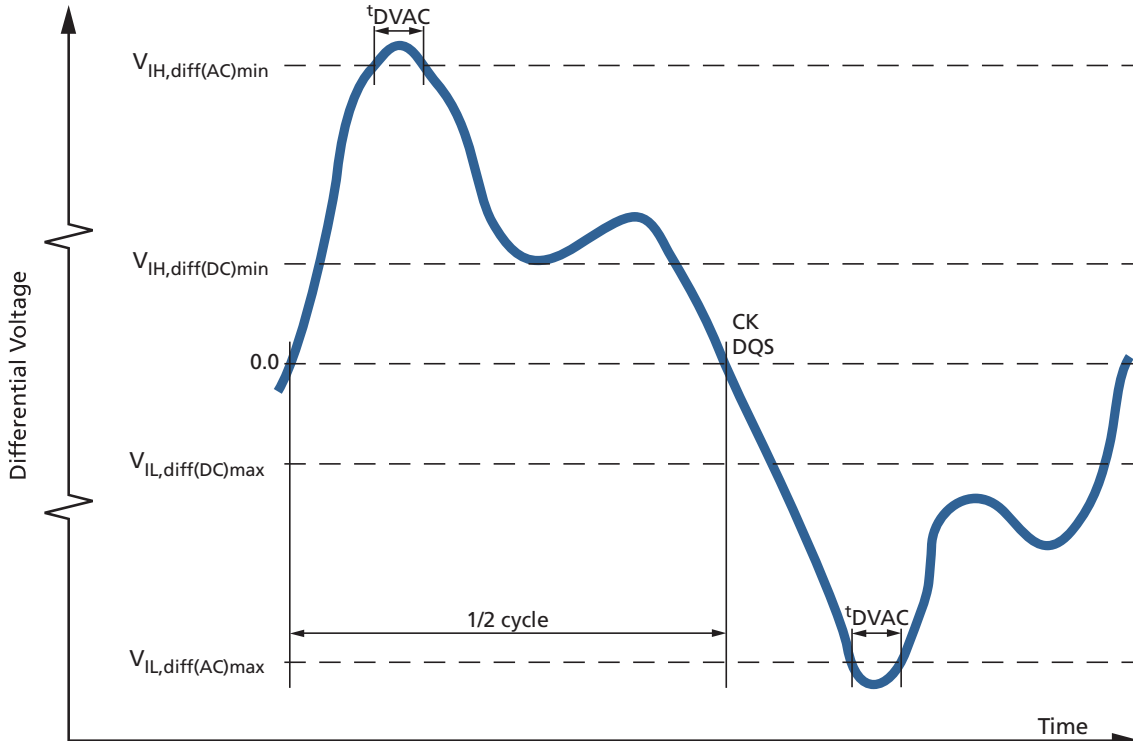


Table 80: Differential AC and DC Input Levels

For CK, $V_{REF} = V_{REFCA(DC)}$; For DQS, $V_{REF} = V_{REFDQ(DC)}$

Parameter	Symbol	LPDDR3		Unit	Notes
		Min	Max		
Differential input HIGH AC	$V_{IH,diff(AC)}$	2 × ($V_{IH(AC)}$ - V_{REF})	Note 1	V	2
Differential input LOW AC	$V_{IL,diff(AC)}$	Note 1	2 × ($V_{IL(AC)}$ - V_{REF})	V	2
Differential input HIGH DC	$V_{IH,diff(DC)}$	2 × ($V_{IH(DC)}$ - V_{REF})	Note 1	V	3
Differential input LOW DC	$V_{IL,diff(DC)}$	Note 1	2 × ($V_{IL(DC)}$ - V_{REF})	V	3

Notes:
1. These values are not defined; however, the single-ended signals CK and DQS must be within the respective limits ($V_{IH(DC)max}$, $V_{IL(DC)min}$) for single-ended signals, and must comply with the specified limitations for overshoot and undershoot (see figure: Overshoot and Undershoot Definition).
2. For CK, use $V_{IH}/V_{IL(AC)}$ of CA and V_{REFCA}; for DQS, use $V_{IH}/V_{IL(AC)}$ of DQ and V_{REFDQ}. If a reduced AC HIGH or AC LOW is used for a signal group, the reduced voltage level also applies.
3. Used to define a differential signal slew rate.

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Table 81: CK and DQS Time Requirements Before Ringback (^{t}DVAC)

Slew Rate (V/ns)	^{t}DVAC (ps) @ V_{IH}/$V_{IL,diff(AC)}$ = 300mV1333 Mb/s		^{t}DVAC (ps) @ V_{IH}/$V_{IL,diff(AC)}$ = 300mV1600 Mb/s		^{t}DVAC (ps) @ V_{IH}/$V_{IL,diff(AC)}$ = 270mV1866 Mb/s		^{t}DVAC (ps) @ V_{IH}/$V_{IL,diff(AC)}$ = 270mV2133 Mb/s	
	Min	Max	Min	Max	Min	Max	Min	Max
>8.0	58	–	48	–	40	–	34	–
8.0	58	–	48	–	40	–	34	–
7.0	56	–	46	–	39	–	33	–
6.0	53	–	43	–	36	–	30	–
5.0	50	–	40	–	33	–	27	–
4.0	45	–	35	–	29	–	23	–
3.0	37	–	27	–	21	–	15	–
<3.0	37	–	27	–	21	–	15	–

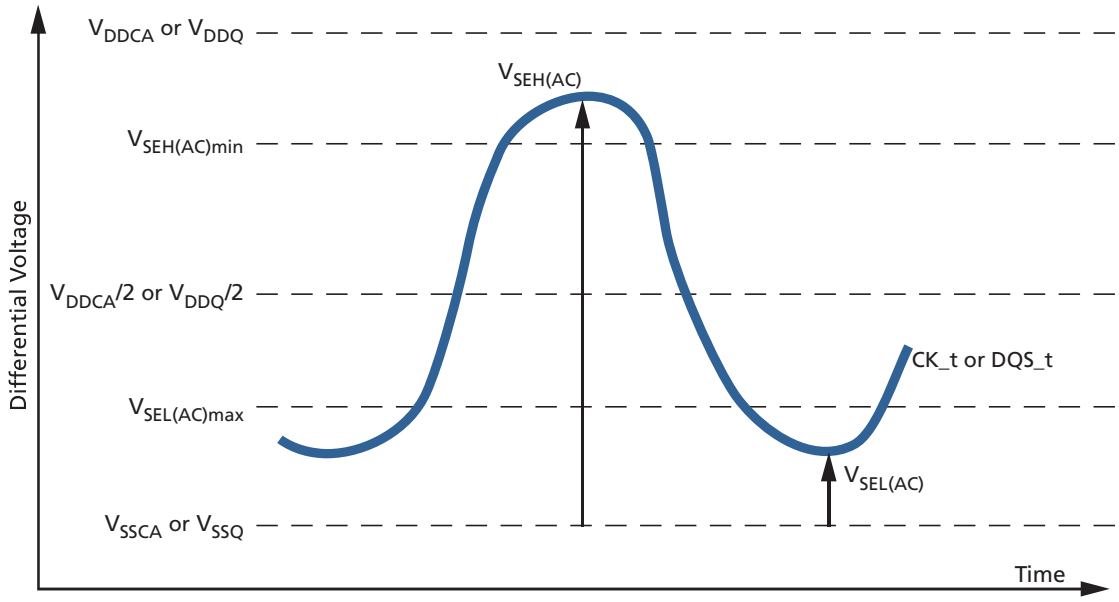
Single-Ended Requirements for Differential Signals

Each individual component of a differential signal (CK and DQS) must also comply with certain requirements for single-ended signals.

CK must meet $V_{SEH(AC)min}$/$V_{SEL(AC)max}$ in every half cycle. DQS must meet $V_{SEH(AC)min}$/$V_{SEL(AC)max}$ in every half cycle preceding and following a valid transition.

The applicable AC levels for CA and DQ differ by speed bin.

Figure 73: Single-Ended Requirements for Differential Signals



Note: While CA and DQ signal requirements are referenced to V_{REF}, the single-ended components of differential signals also have a requirement with respect to $V_{DDQ}/2$ for DQS, and $V_{DDCA}/2$ for CK.

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The transition of single-ended signals through the AC levels is used to measure setup time. For single-ended components of differential signals, the requirement to reach $V_{SEL(AC)max}$ or $V_{SEH(AC)min}$ has no bearing on timing; however, this requirement adds a restriction on the common mode characteristics of these signals (see tables: Single-Ended AC and DC Input Levels for CA and CS_n Inputs; Single-Ended AC and DC Input Levels for DQ and DM).

Table 82: Single-Ended Levels for CK and DQS

Parameter	Symbol	Value		Unit	Notes
		Min	Max		
Single-ended HIGH level for strobes	$V_{SEH(AC150)}$	$(V_{DDQ}/2) + 0.150$	Note 1	V	2, 3
Single-ended HIGH level for CK		$(V_{DDCA}/2) + 0.150$	Note 1	V	2, 3
Single-ended LOW level for strobes	$V_{SEL(AC150)}$	Note 1	$(V_{DDQ}/2) - 0.150$	V	2, 3
Single-ended LOW level for CK		Note 1	$(V_{DDCA}/2) - 0.150$	V	2, 3
Single-ended HIGH level for strobes	$V_{SEH(AC135)}$	$(V_{DDQ}/2) + 0.135$	Note 1	V	2, 3
Single-ended HIGH level for CK		$(V_{DDCA}/2) + 0.135$	Note 1	V	2, 3
Single-ended LOW level for strobes	$V_{SEL(AC135)}$	Note 1	$(V_{DDQ}/2) + 0.135$	V	2, 3
Single-ended LOW level for CK		Note 1	$(V_{DDCA}/2) + 0.135$	V	2, 3

Notes:
1. These values are not defined; however, the single-ended signals CK and DQS[3:0] must be within the respective limits ($V_{IH(DC)max}$, $V_{IL(DC)min}$) for single-ended signals, and must comply with the specified limitations for overshoot and undershoot (see figure: Overshoot and Undershoot Definition).
2. For CK, use $V_{SEH}/V_{SEL(AC)}$ of CA; for strobes (DQS[3:0]), use $V_{IH}/V_{IL(AC)}$ of DQ.
3. $V_{IH(AC)}$ and $V_{IL(AC)}$ for DQ are based on V_{REFDQ}; $V_{SEH(AC)}$ and $V_{SEL(AC)}$ for CA are based on V_{REFCA}. If a reduced AC HIGH or AC LOW is used for a signal group, the reduced level applies.

Differential Input Crosspoint Voltage

To ensure tight setup and hold times, as well as output skew parameters with respect to clock and strobe, each crosspoint voltage of differential input signals (CK, CK_c, DQS_t, and DQS_c) must meet the specifications in the table above. The differential input crosspoint voltage (V_{IX}) is measured from the actual crosspoint of the true signal and its and complement to the midlevel between V_{DD} and V_{SS}.

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Figure 74: V_{IX} Definition

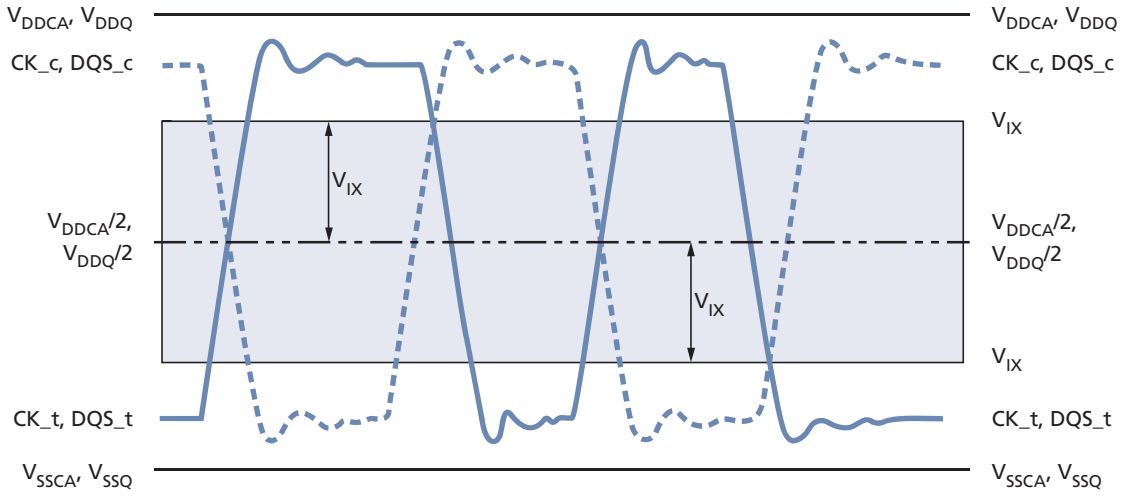


Table 83: Crosspoint Voltage for Differential Input Signals (CK, CK_c, DQS_t, DQS_c)

Parameter	Symbol	Min	Max	Unit	Notes
Differential input crosspoint voltage relative to $V_{DDCA}/2$ for CK	$V_{IXCA(AC)}$	–120	120	mV	1, 2
Differential input crosspoint voltage relative to $V_{DDQ}/2$ for DQS	$V_{IXDQ(AC)}$	–120	120	mV	1, 2

Notes:
1. The typical value of $V_{IX(AC)}$ is expected to be about 0.5 × V_{DD} of the transmitting device, and it is expected to track variations in V_{DD}. $V_{IX(AC)}$ indicates the voltage at which differential input signals must cross.
2. For CK, $V_{REF} = V_{REFCA(DC)}$. For DQS, $V_{REF} = V_{REFDQ(DC)}$.

Input Slew Rate

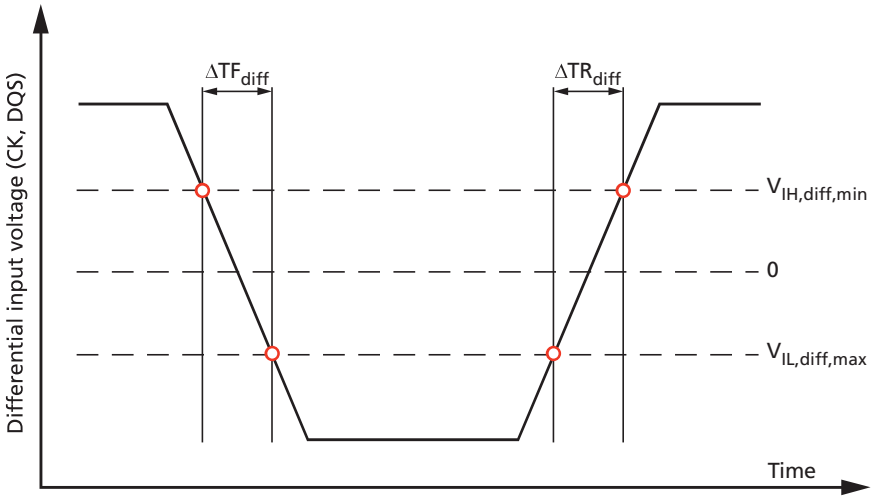
Table 84: Differential Input Slew Rate Definition

Description	Measured[1]		Defined By
	From	To	
Differential input slew rate for rising edge (CK and DQS)	$V_{IL,diff,max}$	$V_{IH,diff,min}$	$(V_{IH,diff,min} - V_{IL,diff,max}) / \Delta TR_{diff}$
Differential input slew rate for falling edge (CK and DQS)	$V_{IH,diff,min}$	$V_{IL,diff,max}$	$(V_{IH,diff,min} - V_{IL,diff,max}) / \Delta TF_{diff}$

Note:
1. The differential signals (CK and DQS) must be linear between these thresholds.

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Figure 75: Differential Input Slew Rate Definition for CK and DQS



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Output Characteristics and Operating Conditions

Table 85: Single-Ended AC and DC Output Levels

Parameter	Symbol	Value	Unit	Notes
AC output HIGH measurement level (for output slew rate)	$V_{OH(AC)}$	V_{REF} + 0.12	V	
AC output LOW measurement level (for output slew rate)	$V_{OL(AC)}$	V_{REF} - 0.12	V	
DC output HIGH measurement level (for I-V curve linearity)	$V_{OH(DC)}$	0.9 × V_{DDQ}	V	1
DC output LOW measurement level (for I-V curve linearity)	$V_{OL(DC)}$	0.1 × V_{DDQ}	V	2
DC output LOW measurement level (for I-V curve linearity); ODT enabled DQS_t	$V_{OL(DC)ODT,enabled}$	V_{DDQ} × {0.1 + 0.9 × [R_{ON} / (R_{TT} + R_{ON})]}	V	3
Output leakage current (DQ, DM, DQS); DQ, DQS are disabled; 0V ≤ V_{OUT} ≤ V_{DDQ}	I_{OZ}	–5 (MIN)	µA	
		5 (MAX)		
Delta output impedance between pull-up and pull-down for DQ/DM	MM_{PUPD}	–15 (MIN)	%	
		15 (MAX)		

Notes:
1. I_{OH} = –0.1mA.
2. I_{OL} = 0.1mA.
3. The minimum value is derived when using $R_{TT,min}$ and $R_{ON,max}$ (±30% uncalibrated, ±15% calibrated).

Table 86: Differential AC and DC Output Levels

Parameter	Symbol	Value	Unit	Notes
AC differential output HIGH measurement level (for output SR)	$V_{OH,diff(AC)}$	0.2 × V_{DDQ}	V	1
AC differential output LOW measurement level (for output SR)	$V_{OL,diff(AC)}$	–0.2 × V_{DDQ}	V	2

Notes:
1. I_{OH} = –0.1mA.
2. I_{OL} = 0.1mA.

Single-Ended Output Slew Rate

With the reference load for timing measurements, the output slew rate for falling and rising edges is defined and measured between $V_{OL(AC)}$ and $V_{OH(AC)}$ for single-ended signals.

Table 87: Single-Ended Output Slew Rate Definition

Description	Measured		Defined by
	From	To	
Single-ended output slew rate for rising edge	$V_{OL(AC)}$	$V_{OH(AC)}$	[$V_{OH(AC)}$ - $V_{OL(AC)}$] / ΔTR_{SE}
Single-ended output slew rate for falling edge	$V_{OH(AC)}$	$V_{OL(AC)}$	[$V_{OH(AC)}$ - $V_{OL(AC)}$] / ΔTF_{SE}

Note:
1. Output slew rate is verified by design and characterization and may not be subject to production testing.

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Figure 76: Single-Ended Output Slew Rate Definition

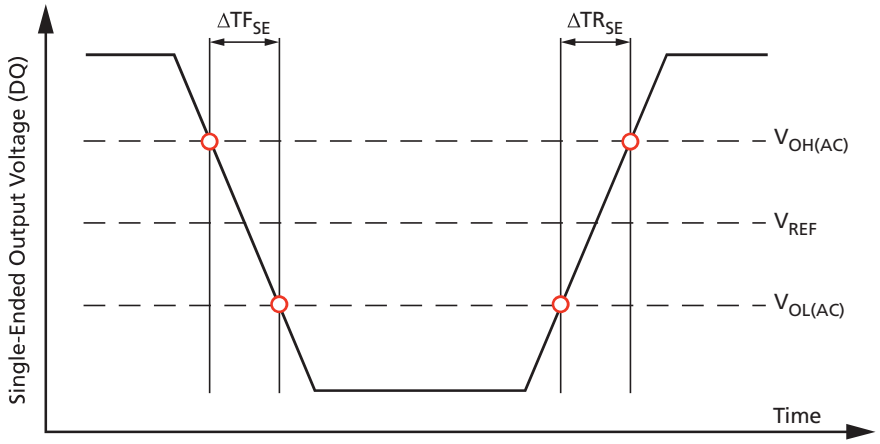


Table 88: Single-Ended Output Slew Rate

Notes 1–5 apply to entire table

Parameter	Symbol	Value		Unit
		Min	Max	
Single-ended output slew rate (output impedance = 40Ω ±30%)	SRQ_{SE}	1.5	4.0	V/ns
Output slew-rate-matching ratio (pull-up to pull-down)	–	0.7	1.4	–

Notes:
1. Definitions: SR = Slew rate; Q = Query output (similar to DQ = Data-in, query output); SE = Single-ended signals.
2. Measured with output reference load.
3. The ratio of pull-up to pull-down slew rate is specified for the same temperature and voltage over the entire temperature and voltage range. For a given output, the ratio represents the maximum difference between pull-up and pull-down drivers due to process variation.
4. The output slew rate for falling and rising edges is defined and measured between $V_{OL(AC)}$ and $V_{OH(AC)}$.
5. Slew rates are measured under typical simultaneous switching output (SSO) conditions, with one half of DQ signals per data byte driving HIGH and one half of DQ signals per data byte driving LOW.

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Differential Output Slew Rate

With the reference load for timing measurements, the output slew rate for falling and rising edges is defined and measured between $V_{OL,diff(AC)}$ and $V_{OH,diff(AC)}$ for differential signals.

Table 89: Differential Output Slew Rate Definition

Description	Measured		Defined by
	From	To	
Differential output slew rate for rising edge	$V_{OL,diff(AC)}$	$V_{OH,diff(AC)}$	$[V_{OH,diff(AC)} - V_{OL,diff(AC)}] / \Delta TR_{diff}$
Differential output slew rate for falling edge	$V_{OH,diff(AC)}$	$V_{OL,diff(AC)}$	$[V_{OH,diff(AC)} - V_{OL,diff(AC)}] / \Delta TF_{diff}$

Note: 1. Output slew rate is verified by design and characterization and may not be subject to production testing.

Figure 77: Differential Output Slew Rate Definition

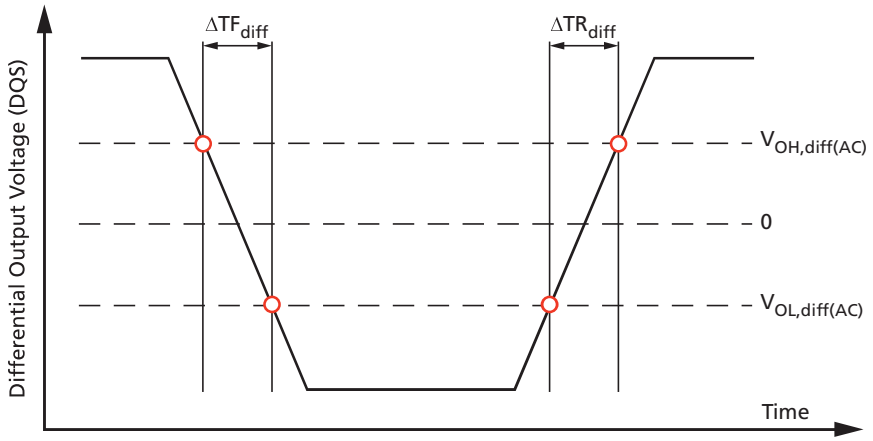


Table 90: Differential Output Slew Rate

Parameter	Symbol	Min	Max	Unit
Differential output slew rate (output impedance = 40Ω ±30%)	SRQ_{diff}	3.0	8.0	V/ns

Notes:
1. Definitions: SR = Slew rate; Q = Query output (similar to DQ = Data-in, query output); diff = Differential signals.
2. Measured with output reference load.
3. The output slew rate for falling and rising edges is defined and measured between $V_{OL(AC)}$ and $V_{OH(AC)}$.
4. Slew rates are measured under typical simultaneous switching output (SSO) conditions, with one half of the DQ signals per data byte driving HIGH and one half of the DQ signals per data byte driving LOW.

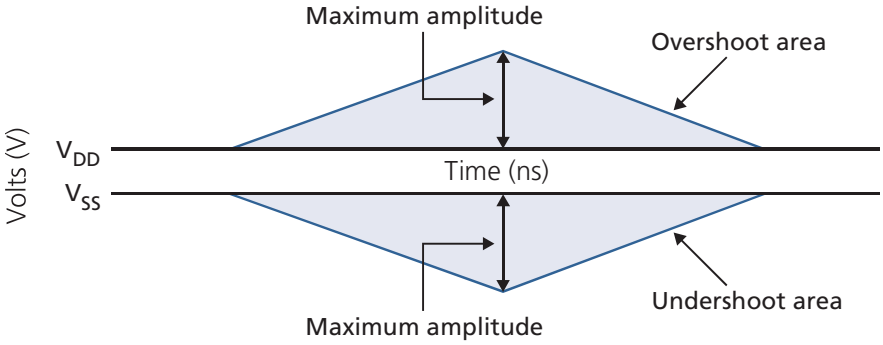
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Table 91: AC Overshoot/Undershoot Specification

Parameter	2133	1866	1600	1333	Unit	Notes
Maximum peak amplitude provided for overshoot area	0.35	0.35	0.35	0.35	V	
Maximum peak amplitude provided for undershoot area	0.35	0.35	0.35	0.35	V	
Maximum area above V_{DD}	0.10	0.10	0.10	0.12	V-ns	1
Maximum area below V_{SS}	0.10	0.10	0.10	0.12	V-ns	2

Notes:
1. $V_{DD} = V_{DDCA}$ for CA[9:0], CK, CS_n, and CKE. V_{DD} stands for V_{DDQ} for DQ, DM, DQS, and ODT.
2. $V_{SS} = V_{SSCA}$ for CA[9:0], CK, CS_n, and CKE. V_{SS} stands for V_{SSQ} for DQ, DM, DQS, and ODT.
3. Maximum peak amplitude values are referenced from actual V_{DD} and V_{SS} values.
4. Maximum area values are referenced from maximum operating V_{DD} and V_{SS} values.

Figure 78: Overshoot and Undershoot Definition



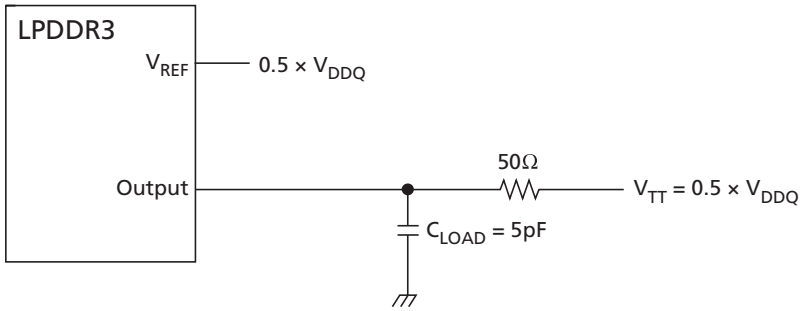
Notes:
1. $V_{DD} = V_{DDCA}$ for CA[9:0], CK, CS_n, and CKE. $V_{DD} = V_{DDQ}$ for DQ, DM, DQS, and ODT.
2. $V_{SS} = V_{SSCA}$ for CA[9:0], CK, CS_n, and CKE. $V_{SS} = V_{SSQ}$ for DQ, DM, DQS, and ODT.
3. Maximum peak amplitude values are referenced from actual V_{DD} and V_{SS} values.
4. Maximum area values are referenced from maximum operating V_{DD} and V_{SS} values.

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HSUL_12 Driver Output Timing Reference Load

The timing reference loads are not a precise representation of any particular system environment or a depiction of the actual load presented by a production tester. System designers should use IBIS or other simulation tools to correlate the timing reference load to a system environment. Manufacturers correlate to their production test conditions, generally with one or more coaxial transmission lines terminated at the tester electronics.

Figure 79: HSUL_12 Driver Output Reference Load for Timing and Slew Rate



Note: 1. All output timing parameter values (^{t}DQSCK, ^{t}DQSQ, ^{t}HZ, ^{t}RPRE, etc.) are reported with respect to this reference load. This reference load is also used to report slew rate.

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Output Driver Impedance

Output driver impedance is selected by a mode register during initialization. The selected value is able to maintain the tight tolerances specified if proper ZQ calibration is performed. Output specifications refer to the default output drive unless specifically stated otherwise. The output driver impedance R_{ON} is defined by the value of the external reference resistor R_{ZQ} as follows:

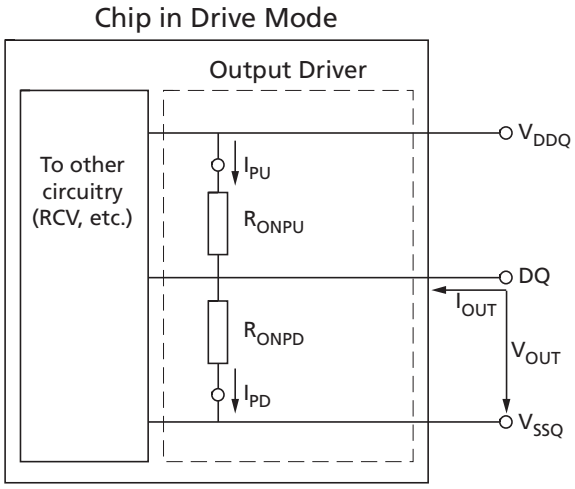
$$R_{ONPU} = \frac{V_{DDQ} - V_{OUT}}{ABS(I_{OUT})}$$

When R_{ONPD} is turned off.

$$R_{ONPD} = \frac{V_{OUT}}{ABS(I_{OUT})}$$

When R_{ONPU} is turned off.

Figure 80: Output Driver



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Output Driver Impedance Characteristics with ZQ Calibration

Output driver impedance is defined by the value of the external reference resistor R_{ZQ}. Typical R_{ZQ} is 240Ω.

Table 92: Output Driver DC Electrical Characteristics with ZQ Calibration

Notes 1–4 apply to entire table

R_{ONnom}	Resistor	V_{OUT}	Min	Typ	Max	Unit	Notes
34.3Ω	R_{ON34PD}	0.5 × V_{DDQ}	0.85	1.00	1.15	$R_{ZQ}/7$	
	R_{ON34PU}	0.5 × V_{DDQ}	0.85	1.00	1.15	$R_{ZQ}/7$	
40.0Ω	R_{ON40PD}	0.5 × V_{DDQ}	0.85	1.00	1.15	$R_{ZQ}/6$	
	R_{ON40PU}	0.5 × V_{DDQ}	0.85	1.00	1.15	$R_{ZQ}/6$	
48.0Ω	R_{ON48PD}	0.5 × V_{DDQ}	0.85	1.00	1.15	$R_{ZQ}/5$	
	R_{ON48PU}	0.5 × V_{DDQ}	0.85	1.00	1.15	$R_{ZQ}/5$	
Mismatch between pull-up and pull-down	MM_{PUPD}	–	–15.00	–	15.00	%	5

Notes:
1. Applies across entire operating temperature range after calibration.
2. R_{ZQ} = 240Ω.
3. The tolerance limits are specified after calibration, with fixed voltage and temperature. For behavior of the tolerance limits if temperature or voltage changes after calibration, see Output Driver Temperature and Voltage Sensitivity.
4. Pull-down and pull-up output driver impedances should be calibrated at 0.5 x V_{DDQ}.
5. Measurement definition for mismatch between pull-up and pull-down, MM_{PUPD}: Measure R_{ONPU} and R_{ONPD}, both at 0.5 × V_{DDQ}:

$$MM_{PUPD} = \frac{R_{ONPU} - R_{ONPD}}{R_{ON,nom}} \times 100$$

For example, with MM_{PUPD} (MAX) = 15% and R_{ONPD} = 0.85, R_{ONPU} must be less than 1.0.

Output Driver Temperature and Voltage Sensitivity

If temperature and/or voltage change after calibration, the tolerance limits widen.

Table 93: Output Driver Sensitivity Definition

Notes 1 and 2 apply to entire table

Resistor	V_{OUT}	Min	Max	Unit
R_{ONPD}	0.5 × V_{DDQ}	85 - ($dR_{ON}dT$ × |ΔT|) - ($dR_{ON}dV$ × |ΔV|)	115 + ($dR_{ON}dT$ × |ΔT|) + ($dR_{ON}dV$ × |ΔV|)	%
R_{ONPU}				
R_{TT}	0.5 × V_{DDQ}	85 - ($dR_{TT}dT$ × |ΔT|) - ($dR_{TT}dV$ × |ΔV|)	115 + ($dR_{TT}dT$ × |ΔT|) + ($dR_{TT}dV$ × |ΔV|)	%

Notes:
1. ΔT = T - T (at calibration). ΔV = V - V (at calibration).
2. $dR_{ON}dT$ and $dR_{ON}dV$, and $dR_{TT}dT$ and $dR_{TT}dV$ are not subject to production testing; they are verified by design and characterization.

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Table 94: Output Driver Temperature and Voltage Sensitivity

Symbol	Parameter	Min	Max	Unit
dR_{ONdT}	R_{ON} temperature sensitivity	0	0.75	%/°C
dR_{ONdV}	R_{ON} voltage sensitivity	0	0.20	%/mV
dR_{TTdT}	R_{TT} temperature sensitivity	0	0.75	%/°C
dR_{TTdV}	R_{TT} voltage sensitivity	0	0.20	%/mV

Output Impedance Characteristics Without ZQ Calibration

Output driver impedance is defined by design and characterization as the default setting.

Table 95: Output Driver DC Electrical Characteristics Without ZQ Calibration

Notes 1 and 2 apply to entire table

$R_{ON,nom}$	Resistor	V_{OUT}	Min	Typ	Max	Unit
34.3Ω	R_{ON34PD}	$0.5 \times V_{DDQ}$	0.70	1.00	1.30	$R_{ZQ}/7$
	R_{ON34PU}	$0.5 \times V_{DDQ}$	0.70	1.00	1.30	$R_{ZQ}/7$
40.0Ω	R_{ON40PD}	$0.5 \times V_{DDQ}$	0.70	1.00	1.30	$R_{ZQ}/6$
	R_{ON40PU}	$0.5 \times V_{DDQ}$	0.70	1.00	1.30	$R_{ZQ}/6$
48.0Ω	R_{ON48PD}	$0.5 \times V_{DDQ}$	0.70	1.00	1.30	$R_{ZQ}/5$
	R_{ON48PU}	$0.5 \times V_{DDQ}$	0.70	1.00	1.30	$R_{ZQ}/5$

Notes:
1. Applies across entire operating temperature range without calibration.
2. $R_{ZQ} = 240\Omega$.

Table 96: I-V Curves

	$R_{ON} = 240\Omega$ (R_{ZQ})							
	Pull-Down				Pull-Up			
	Current (mA) / R_{ON} (Ω)				Current (mA) / R_{ON} (Ω)			
	Default Value after ZQRESET		With Calibration		Default Value after ZQRESET		With Calibration	
Voltage (V)	Min (mA)	Max (mA)	Min (mA)	Max (mA)	Min (mA)	Max (mA)	Min (mA)	Max (mA)
0.00	0.00	0.00	N/A	N/A	0.00	0.00	N/A	N/A
0.05	0.17	0.35	N/A	N/A	–0.17	–0.35	N/A	N/A
0.10	0.34	0.70	N/A	N/A	–0.34	–0.70	N/A	N/A
0.15	0.50	1.03	N/A	N/A	–0.50	–1.03	N/A	N/A
0.20	0.67	1.39	N/A	N/A	–0.67	–1.39	N/A	N/A
0.25	0.83	1.73	N/A	N/A	–0.83	–1.73	N/A	N/A
0.30	0.97	2.05	N/A	N/A	–0.97	–2.05	N/A	N/A
0.35	1.13	2.39	N/A	N/A	–1.13	–2.39	N/A	N/A
0.40	1.26	2.71	N/A	N/A	–1.26	–2.71	N/A	N/A

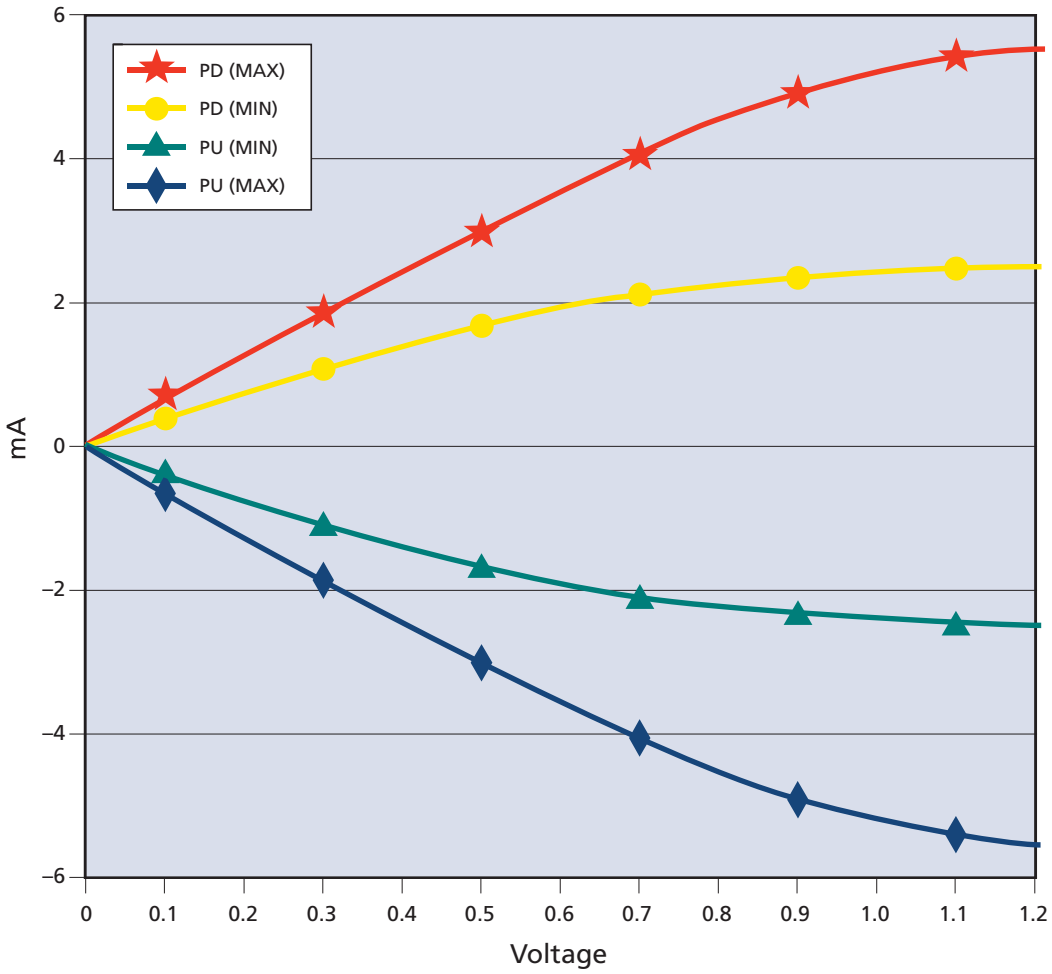
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Table 96: I-V Curves (Continued)

	$R_{ON} = 240\Omega$ (R_{ZQ})							
	Pull-Down				Pull-Up			
	Current (mA) / R_{ON} (Ω)				Current (mA) / R_{ON} (Ω)			
	Default Value after ZQRESET		With Calibration		Default Value after ZQRESET		With Calibration	
Voltage (V)	Min (mA)	Max (mA)	Min (mA)	Max (mA)	Min (mA)	Max (mA)	Min (mA)	Max (mA)
0.45	1.39	3.01	N/A	N/A	–1.39	–3.01	N/A	N/A
0.50	1.51	3.32	N/A	N/A	–1.51	–3.32	N/A	N/A
0.55	1.63	3.63	N/A	N/A	–1.63	–3.63	N/A	N/A
0.60	1.73	3.93	2.17	2.94	–1.73	–3.93	–2.17	–2.94
0.65	1.82	4.21	N/A	N/A	–1.82	–4.21	N/A	N/A
0.70	1.90	4.49	N/A	N/A	–1.90	–4.49	N/A	N/A
0.75	1.97	4.74	N/A	N/A	–1.97	–4.74	N/A	N/A
0.80	2.03	4.99	N/A	N/A	–2.03	–4.99	N/A	N/A
0.85	2.07	5.21	N/A	N/A	–2.07	–5.21	N/A	N/A
0.90	2.11	5.41	N/A	N/A	–2.11	–5.41	N/A	N/A
0.95	2.13	5.59	N/A	N/A	–2.13	–5.59	N/A	N/A
1.00	2.17	5.72	N/A	N/A	–2.17	–5.72	N/A	N/A
1.05	2.19	5.84	N/A	N/A	–2.19	–5.84	N/A	N/A
1.10	2.21	5.95	N/A	N/A	–2.21	–5.95	N/A	N/A
1.15	2.23	6.03	N/A	N/A	–2.23	–6.03	N/A	N/A
1.20	2.25	6.11	N/A	N/A	–2.25	–6.11	N/A	N/A

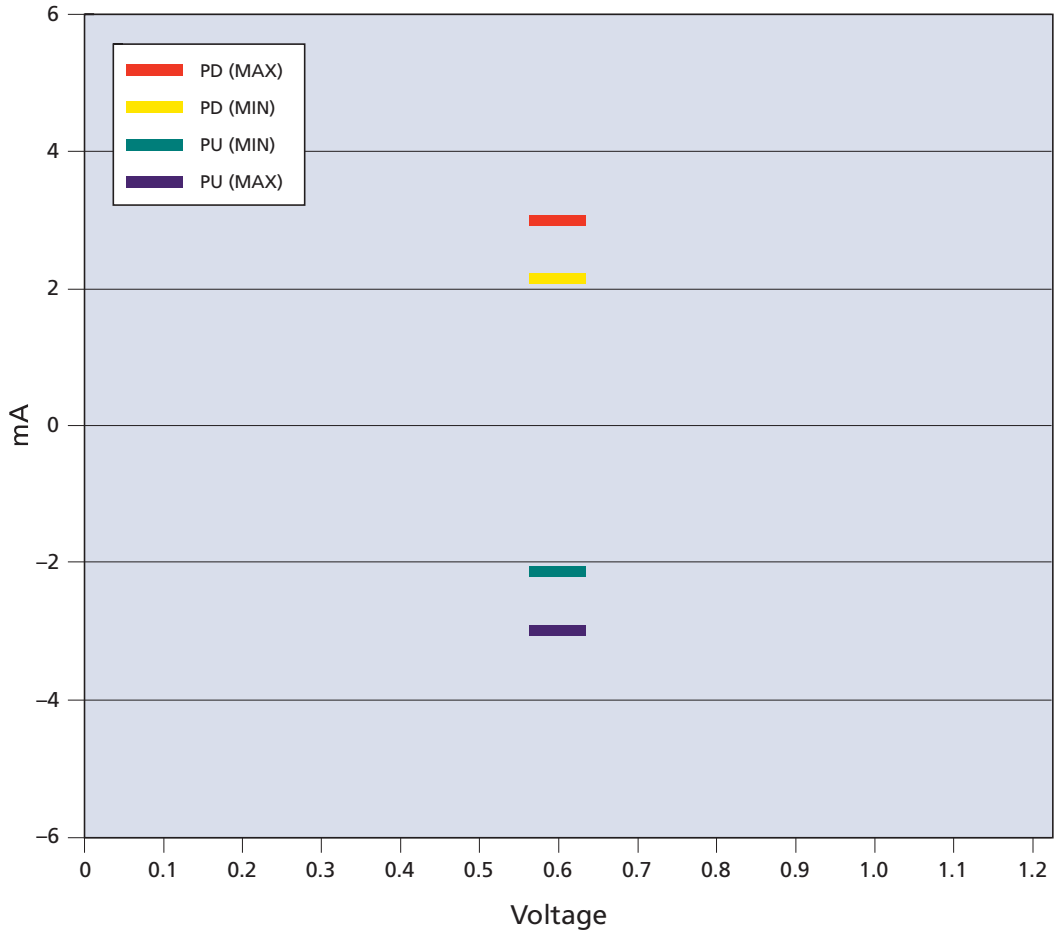
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Figure 81: Output Impedance = 240Ω, I-V Curves After ZQRESET



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Figure 82: Output Impedance = 240Ω, I-V Curves After Calibration



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ODT Levels and I-V Characteristics

ODT effective resistance, R_{TT}, is defined by mode register MR11[1:0]. ODT is applied to the DQ, DM, and DQS pins. A functional block diagram of the on-die termination is shown in the figure below. R_{TT} is defined by the following formula: $R_{TTPU} = (V_{DDQ} - V_{OUT}) / |I_{OUT}|$

Figure 83: ODT Functional Block Diagram

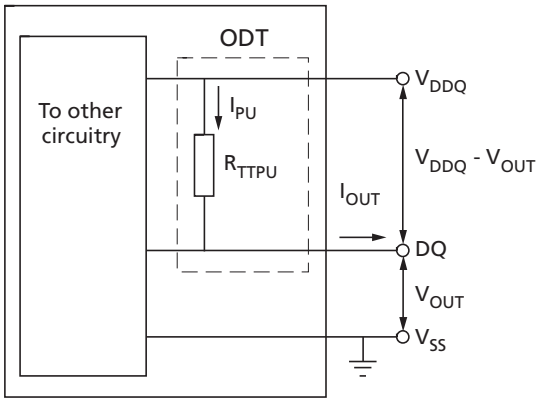


Table 97: ODT DC Electrical Characteristics (R_{ZQ} = 240Ω After Proper ZQ Calibration)

R_{TT} (Ω)	V_{OUT}	I_{OUT}	
		Min (mA)	Max (mA)
$R_{ZQ}/1$	0.6	–2.17	–2.94
$R_{ZQ}/2$	0.6	–4.34	–5.88
$R_{ZQ}/4$	0.6	–8.68	–11.76

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Clock Specification

The specified clock jitter is a random jitter with Gaussian distribution. Input clocks violating minimum or maximum values may result in device malfunction.

Table 98: Definitions and Calculations

Symbol	Description	Calculation	Notes
$^{t}CK(avg)$ and *n*CK	The average clock period across any consecutive 200-cycle window. Each clock period is calculated from rising clock edge to rising clock edge. Unit $^{t}CK(avg)$ represents the actual clock average $^{t}CK(avg)$ of the input clock under operation. Unit *n*CK represents one clock cycle of the input clock, counting from actual clock edge to actual clock edge. $^{t}CK(avg)$can change no more than ±1% within a 100-clock-cycle window, provided that all jitter and timing specifications are met.	$^{t}CK(avg) = \left(\sum_{j=1}^{N} {}^{t}CK_{j}\right)/N$ Where N = 200	
$^{t}CK(abs)$	The absolute clock period, as measured from one rising clock edge to the next consecutive rising clock edge.		1
$^{t}CH(avg)$	The average HIGH pulse width, as calculated across any 200 consecutive HIGH pulses.	$^{t}CH(avg) = \left(\sum_{j=1}^{N} {}^{t}CH_{j}\right)/(N \times {}^{t}CK(avg))$ Where N = 200	
$^{t}CL(avg)$	The average LOW pulse width, as calculated across any 200 consecutive LOW pulses.	$^{t}CL(avg) = \left(\sum_{j=1}^{N} {}^{t}CL_{j}\right)/(N \times {}^{t}CK(avg))$ Where N = 200	
$^{t}JIT(per)$	The single-period jitter defined as the largest deviation of any signal ^{t}CK from $^{t}CK(avg)$.	$^{t}JIT(per) = \text{min/max of } \left({}^{t}CK_{i} - {}^{t}CK(avg)\right)$ Where i = 1 to 200	1
$^{t}JIT(per),act$	The actual clock jitter for a given system.		
$^{t}JIT(per),$ allowed	The specified clock period jitter allowance.		
$^{t}JIT(cc)$	The absolute difference in clock periods between two consecutive clock cycles. $^{t}JIT(cc)$ defines the cycle-to-cycle jitter.	$^{t}JIT(cc) = \text{max of } \left({}^{t}CK_{i+1} - {}^{t}CK_{i}\right)$	1
$^{t}ERR(nper)$	The cumulative error across *n* multiple consecutive cycles from $^{t}CK(avg)$.	$^{t}ERR(nper) = \left(\sum_{j=i}^{i+n-1} {}^{t}CK_{j}\right) - (n \times {}^{t}CK(avg))$	1
$^{t}ERR(nper),act$	The actual cumulative error over *n* cycles for a given system.		
$^{t}ERR(nper),$ allowed	The specified cumulative error allowance over *n* cycles.		
$^{t}ERR(nper),min$	The minimum $^{t}ERR(nper)$.	$^{t}ERR(nper),min = (1 + 0.68LN(n)) \times {}^{t}JIT(per),min$	2

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Table 98: Definitions and Calculations (Continued)

Symbol	Description	Calculation	Notes
^{t}ERR(nper),max	The maximum ^{t}ERR(nper).	^{t}ERR(nper),max = (1 + 0.68LN(n)) × ^{t}JIT(per),max	2
^{t}JIT(duty)	Defined with absolute and average specifications for ^{t}CH and ^{t}CL, respectively.	^{t}JIT(duty),min = MIN((^{t}CH(abs),min – ^{t}CH(avg),min), (^{t}CL(abs),min – ^{t}CL(avg),min)) × ^{t}CK(avg) ^{t}JIT(duty),max = MAX((^{t}CH(abs),max – ^{t}CH(avg),max), (^{t}CL(abs),max – ^{t}CL(avg),max)) × ^{t}CK(avg)	

Notes:
1. Not subject to production testing.
2. Using these equations, ^{t}ERR(nper) tables can be generated for each ^{t}JIT(per),act value.

^{t}CK(abs), ^{t}CH(abs), and ^{t}CL(abs)

These parameters are specified with their average values; however, the relationship between the average timing and the absolute instantaneous timing (defined in the following table) is applicable at all times.

Table 99: ^{t}CK(abs), ^{t}CH(abs), and ^{t}CL(abs) Definitions

Parameter	Symbol	Minimum	Unit
Absolute clock period	^{t}CK(abs)	^{t}CK(avg),min + ^{t}JIT(per),min	ps[1]
Absolute clock HIGH pulse width	^{t}CH(abs)	^{t}CH(avg),min + ^{t}JIT(duty),min[2]/^{t}CK(avg)min	^{t}CK(avg)
Absolute clock LOW pulse width	^{t}CL(abs)	^{t}CL(avg),min + ^{t}JIT(duty),min[2]/^{t}CK(avg)min	^{t}CK(avg)

Notes:
1. ^{t}CK(avg),min is expressed in ps for this table.
2. ^{t}JIT(duty),min is a negative value.

Clock Period Jitter

LPDDR3 devices can tolerate some clock period jitter without core timing parameter derating. This section describes device timing requirements with clock period jitter (^{t}JIT(per)) in excess of the values found in the AC Timing table. Calculating cycle time derating and clock cycle derating are also described.

Clock Period Jitter Effects on Core Timing Parameters

Core timing parameters (^{t}RCD, ^{t}RP, ^{t}RTP, ^{t}WR, ^{t}WRA, ^{t}WTR, ^{t}RC, ^{t}RAS, ^{t}RRD, ^{t}FAW) extend across multiple clock cycles. Clock period jitter impacts these parameters when measured in numbers of clock cycles. Within the specification limits, the device is characterized and verified to support ^{t}nPARAM = RU[^{t}PARAM/^{t}CK(avg)]. During device operation where clock jitter is outside specification limits, the number of clocks, or ^{t}CK(avg), may need to be increased based on the values for each core timing parameter.

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Cycle Time Derating for Core Timing Parameters

For a given number of clocks (^{t}nPARAM), when ^{t}CK(avg) and ^{t}ERR(^{t}nPARAM),act exceed ^{t}ERR(^{t}nPARAM),allowed, cycle time derating may be required for core timing parameters.

$$\text{CycleTimeDerating} = \max\left\{\left(\frac{^{t}\text{PARAM} + ^{t}\text{ERR}(^{t}\text{nPARAM}),\text{act} - ^{t}\text{ERR}(^{t}\text{nPARAM}),\text{allowed}}{^{t}\text{nPARAM}} - ^{t}\text{CK(avg)}\right), 0\right\}$$

Cycle time derating analysis should be conducted for each core timing parameter. The amount of cycle time derating required is the maximum of the cycle time deratings determined for each individual core timing parameter.

Clock Cycle Derating for Core Timing Parameters

For each core timing parameter and a given number of clocks (^{t}nPARAM), clock cycle derating should be specified with ^{t}JIT(per).

For a given number of clocks (^{t}nPARAM), when ^{t}CK(avg) plus (^{t}ERR(^{t}nPARAM),act) exceed the supported cumulative ^{t}ERR(^{t}nPARAM),allowed, derating is required. If the equation below results in a positive value for a core timing parameter (^{t}CORE), the required clock cycle derating will be that positive value (in clocks).

$$\text{ClockCycleDerating} = \text{RU}\left\{\frac{^{t}\text{PARAM} + ^{t}\text{ERR}(^{t}\text{nPARAM}),\text{act} - ^{t}\text{ERR}(^{t}\text{nPARAM}),\text{allowed}}{^{t}\text{CK(avg)}}\right\} - ^{t}\text{nPARAM}$$

Cycle-time derating analysis should be conducted for each core timing parameter.

Clock Jitter Effects on Command/Address Timing Parameters

Command/address timing parameters (^{t}IS, ^{t}IH, ^{t}ISCKE, ^{t}IHCKE, ^{t}ISb, ^{t}IHb, ^{t}ISCKEb, ^{t}IHCKEb) are measured from a command/address signal (CKE, CS, or CA[9:0]) transition edge to its respective clock signal (CK_t/CK_c) crossing. The specification values are not affected by the ^{t}JIT(per) applied, because the setup and hold times are relative to the clock signal crossing that latches the command/address. Regardless of clock jitter values, these values must be met.

Clock Jitter Effects on Read Timing Parameters

^{t}RPRE Parameter

When the device is operated with input clock jitter, ^{t}RPRE must be derated by the ^{t}JIT(per),act,max of the input clock that exceeds ^{t}JIT(per),allowed,max. Output deratings are relative to the input clock:

$$^{t}\text{RPRE(min,derated)} = 0.9 - \left(\frac{^{t}\text{JIT(per)},\text{act,max} - ^{t}\text{JIT(per)},\text{allowed,max}}{^{t}\text{CK(avg)}}\right)$$

For example, if the measured jitter into a LPDDR3-1600 device has ^{t}CK(avg) = 1250ps, ^{t}JIT(per),act,min = –92ps, and ^{t}JIT(per),act,max = +134ps, then ^{t}RPRE,min,derated = 0.9 - (^{t}JIT(per),act,max - ^{t}JIT(per),allowed,max)/^{t}CK(avg) = 0.9 - (134 - 100)/1250 = 0.8728 ^{t}CK(avg).

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^{t}LZ(DQ), ^{t}HZ(DQ), ^{t}DQSCK, ^{t}LZ(DQS), ^{t}HZ(DQS) Parameters

These parameters are measured from a specific clock edge to a data signal transition (DM*n* or DQ*m*, where: *n* = 0, 1, 2, or 3; and *m* = DQ[31:0]), and specified timings must be met with respect to that clock edge. Therefore, they are not affected by ^{t}JIT(per).

^{t}QSH, ^{t}QSL Parameters

These parameters are affected by duty cycle jitter, represented by ^{t}CH(abs)min and ^{t}CL(abs)min. These parameters determine the absolute data-valid window at the device pin. The absolute minimum data-valid window at the device pin = min [(^{t}QSH(abs)min × ^{t}CK(avg)min - ^{t}DQSQmax - ^{t}QHSmax), (^{t}QSL(abs)min × ^{t}CK(avg)min - ^{t}DQSQmax - ^{t}QHSmax)]. This minimum data valid window must be met at the target frequency regardless of clock jitter.

^{t}RPST Parameter

^{t}RPST is affected by duty cycle jitter, represented by ^{t}CL(abs). Therefore, ^{t}RPST(abs)min can be specified by ^{t}CL(abs)min. ^{t}RPST(abs)min = ^{t}CL(abs)min - 0.05 = ^{t}QSL(abs)min.

Clock Jitter Effects on Write Timing Parameters

^{t}DS, ^{t}DH Parameters

These parameters are measured from a data signal (DM*n* *or* DQ*m*, where *n* = 0, 1, 2, 3; and *m* = DQ[31:0]) transition edge to its respective data strobe signal crossing (DQS*n*_t, DQS*n*_c: *n* = 0,1,2,3). The specification values are not affected by the amount of ^{t}JIT(per) applied, because the setup and hold times are relative to the clock signal crossing that latches the command/address. Regardless of clock jitter values, these values must be met.

^{t}DSS, ^{t}DSH Parameters

These parameters are measured from a data strobe signal crossing (DQS*x*_t, DQS*x*_c) to its clock signal crossing (CK_t/CK_c). The specification values are not affected by the amount of ^{t}JIT(per)) applied, because the setup and hold times are relative to the clock signal crossing that latches the command/address. Regardless of clock jitter values, these values must be met.

^{t}DQSS Parameter

^{t}DQSS is measured from the clock signal crossing (CK_t/CK_c) to the first latching data strobe signal crossing (DQS*x*_t, DQS*x*_c). When the device is operated with input clock jitter, this parameter must be derated by the actual ^{t}JIT(per),act of the input clock in excess of ^{t}JIT(per),allowed.

$$^{t}\text{DQSS(min,derated)} = 0.75 - \left(\frac{^{t}\text{JIT(per),act,min} - {}^{t}\text{JIT(per),allowed, min}}{^{t}\text{CK(avg)}}\right)$$

$$^{t}\text{DQSS(max,derated)} = 1.25 - \left(\frac{^{t}\text{JIT(per),act,max} - {}^{t}\text{JIT(per),allowed, max}}{^{t}\text{CK(avg)}}\right)$$

For example, if the measured jitter into an LPDDR3-1600 device has ^{t}CK(avg) = 1250ps, ^{t}JIT(per),act,min = -93ps, and ^{t}JIT(per),act,max = +134ps, then:

^{t}DQSS,(min,derated) = 0.75 - (^{t}JIT(per),act,min - ^{t}JIT(per),allowed,min)/^{t}CK(avg) = 0.75 - (-93 + 100)/1250 = 0.7444 ^{t}CK(avg), *and*

^{t}DQSS,(max,derated) = 1.25 - (^{t}JIT(per),act,max - ^{t}JIT(per),allowed,max)/^{t}CK(avg) =

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1.25 - (134 - 100) / 1250 = 1.2228 ^{t}CK(avg).

Refresh Requirements

Table 100: Refresh Requirement Parameters (Per Density)

Parameter		Symbol	4Gb	6Gb	8Gb	16Gb	32Gb	Unit
Number of banks		–	8				TBD	
Refresh window: T_{CASE} ≤ 85°		^{t}REFW	32				TBD	ms
Refresh window: 1/2 rate		^{t}REFW	16				TBD	ms
Refresh window: 1/4 rate		^{t}REFW	8				TBD	ms
Required number of REFRESH commands (MIN)		R	8192				TBD	
Average time between REFRESH commands (for reference only) T_{CASE} ≤ 85°C	REFab	^{t}REFI	3.9				TBD	µs
	REFpb	^{t}REFIpb	0.4875				TBD	µs
Refresh cycle time		^{t}RFCab	130	210		TBD	TBD	ns
Per-bank REFRESH cycle time		^{t}RFCpb	60	90		TBD	TBD	ns

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AC Timing

Table 101: AC Timing

Notes 1–3 apply to all parameters and conditions

Parameter	Symbol	Min/Max	Data Rate				Unit	Notes
			1333	1600	1866	2133		
Maximum frequency	–	–	667	800	933	1066	MHz	
Clock Timing								
Average clock period	tCK(avg)	MIN	1.5	1.25	1.071	0.938	ns	
		MAX	100					
Average HIGH pulse width	tCH(avg)	MIN	0.45				tCK(avg)	
		MAX	0.55					
Average LOW pulse width	tCL(avg)	MIN	0.45				tCK(avg)	
		MAX	0.55					
Absolute clock period	tCK(abs)	MIN	tCK(avg) MIN + tJIT(per) MIN				ns	
Absolute clock HIGH pulse width	tCH(abs)	MIN	0.43				tCK(avg)	
		MAX	0.57					
Absolute clock LOW pulse width	tCL(abs)	MIN	0.43				tCK(avg)	
		MAX	0.57					
Clock period jitter (with supported jitter)	tJIT(per), allowed	MIN	–80	–70	-60	-50	ps	
		MAX	80	70	60	50		
Maximum clock jitter between two consecutive clock cycles (with allowed jitter)	tJIT(cc), allowed	MAX	160	140	120	100	ps	
Duty cycle jitter (with supported jitter)	tJIT(duty), allowed	MIN	min((tCH(abs),min - tCH(avg),min), (tCL(abs),min - tCL(avg),min)) × tCK(avg)				ps	
		MAX	max((tCH(abs),max - tCH(avg),max), (tCL(abs),max - tCL(avg),max)) × tCK(avg)					
Cumulative errors across 2 cycles	tERR(2per), allowed	MIN	–118	–103	-88	-74	ps	
		MAX	118	103	88	74		
Cumulative errors across 3 cycles	tERR(3per), allowed	MIN	–140	–122	-105	-87	ps	
		MAX	140	122	105	87		
Cumulative errors across 4 cycles	tERR(4per), allowed	MIN	–155	–136	-117	-97	ps	
		MAX	155	136	117	97		
Cumulative errors across 5 cycles	tERR(5per), allowed	MIN	–168	–147	-126	-105	ps	
		MAX	168	147	126	105		
Cumulative errors across 6 cycles	tERR(6per), allowed	MIN	–177	–155	-133	-111	ps	
		MAX	177	155	133	111		
Cumulative errors across 7 cycles	tERR(7per), allowed	MIN	–186	–163	-139	-116	ps	
		MAX	186	163	139	116		
Cumulative errors across 8 cycles	tERR(8per), allowed	MIN	–193	–169	-145	-121	ps	
		MAX	193	169	145	121		

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Table 101: AC Timing (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter	Symbol	Min/Max	Data Rate				Unit	Notes
			1333	1600	1866	2133		
Cumulative errors across 9 cycles	tERR(9per), allowed	MIN	–200	–175	-150	-125	ps	
		MAX	200	175	150	125		
Cumulative errors across 10 cycles	tERR(10per), allowed	MIN	–205	–180	-154	-128	ps	
		MAX	205	180	154	128		
Cumulative errors across 11 cycles	tERR(11per), allowed	MIN	–210	–184	-158	-132	ps	
		MAX	210	184	158	132		
Cumulative errors across 12 cycles	tERR(12per), allowed	MIN	–215	–188	-161	-134	ps	
		MAX	215	188	161	134		
Cumulative errors across n = 13, 14, 15..., 19, 20 cycles	tERR(nper), allowed	MIN	tERR(nper),allowed MIN = (1 + 0.68ln(n)) × tJIT(per), allowed MIN				ps	
		MAX	tERR (nper), allowed MAX = (1 + 0.68ln(n)) × tJIT(per), allowed MAX					
ZQ Calibration Parameters								
Initialization calibration time	tZQINIT	MIN	1				µs	
Long calibration time	tZQCL	MIN	360				ns	
Short calibration time	tZQCS	MIN	90				ns	
Calibration RESET time	tZQRESET	MIN	MAX (50ns, 3nCK)				ns	
READ Parameters[4]								
DQS output access time from CK	tDQSCK	MIN	2500				ps	
		MAX	5500					
DQSCK delta short	tDQSCKDS	MAX	265	220	190	165	ps	5
DQSCK delta medium	tDQSCKDM	MAX	593	511	435	380	ps	6
DQSCK delta long	tDQSCKDL	MAX	733	614	525	460	ps	7
DQS-DQ skew	tDQSQ	MAX	165	135	115	100	ps	
DQS output HIGH pulse width	tQSH	MIN	tCH(abs) - 0.05				tCK(avg)	
DQS output LOW pulse width	tQSL	MIN	tCL(abs) - 0.05				tCK(avg)	
DQ/DQS output hold time from DQS	tQH	MIN	MIN (tQSH, tQSL)				ps	
READ preamble	tRPRE	MIN	0.9				tCK(avg)	8, 9
READ postamble	tRPST	MIN	0.3				tCK(avg)	8, 10
DQS Low-Z from clock	tLZ(DQS)	MIN	tDQSCK (MIN) - 300				ps	8
DQ Low-Z from clock	tLZ(DQ)	MIN	tDQSCK (MIN) - 300				ps	8
DQS High-Z from clock	tHZ(DQS)	MAX	tDQSCK (MAX) - 100				ps	8
DQ High-Z from clock	tHZ(DQ)	MAX	tDQSCK (MAX) + (1.4 × tDQSQ (MAX))				ps	8
WRITE Parameters[4]								

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Table 101: AC Timing (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter	Symbol	Min/Max	Data Rate				Unit	Notes
			1333	1600	1866	2133		
DQ and DM input hold time (V_{REF} based)	tDH	MIN	175	150	130	115	ps	
DQ and DM input setup time (V_{REF} based)	tDS	MIN	175	150	130	115	ps	
DQ and DM input pulse width	tDIPW	MIN	0.35				tCK(avg)	
Write command to first DQS latching transition	tDQSS	MIN	0.75				tCK(avg)	
		MAX	1.25					
DQS input high-level width	tDQSH	MIN	0.4				tCK(avg)	
DQS input low-level width	tDQSL	MIN	0.4				tCK(avg)	
DQS rising edge to CK falling edge and DQS falling edge to CK rising edge setup time	tDSS	MIN	0.2				tCK(avg)	
CK rising edge to DQS falling edge and CK falling edge to DQS rising edge hold time	tDSH	MIN	0.2				tCK(avg)	
Write postamble	tWPST	MIN	0.4				tCK(avg)	
Write preamble	tWPRE	MIN	0.8				tCK(avg)	
CKE Input Parameters								
CKE minimum pulse width (HIGH and LOW pulse width)	tCKE	MIN	MAX (7.5ns, 3nCK)				tCK(avg)	
CKE input setup time	tISCKE	MIN	0.25				tCK(avg)	11
CKE input hold time	tIHCKE	MIN	0.25				tCK(avg)	12
Command path disable delay	tCPDED	MIN	2				tCK(avg)	
Command Address Input Parameters[4]								
Address and control input setup time	tISCA	MIN	175	150	130	115	ps	13
Address and control input hold time	tIHCA	MIN	175	150	130	115	ps	13
CS_n input setup time	tISCS	MIN	290	270	230	205	ps	13
CS_n input hold time	tIHCS	MIN	290	270	230	205	ps	13
Address and control input pulse width	tIPWCA	MIN	0.35				tCK(avg)	
CS_n input pulse width	tIPWCS	MIN	0.7				tCK(avg)	
Boot Parameters (10–55 MHz)[14, 15, 16]								
Clock cycle time	tCKb	MAX	100				ns	
		MIN	18					
CKE input setup time	tISCKEb	MIN	2.5				ns	
CKE input hold time	tIHCKEb	MIN	2.5				ns	

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Table 101: AC Timing (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter	Symbol	Min/Max	Data Rate				Unit	Notes
			1333	1600	1866	2133		
Address and control input setup time	tISb	MIN	1150				ps	
Address and control input hold time	tIHb	MIN	1150				ps	
DQS output data access time from CK	tDQSCKb	MIN	2				ns	
		MAX	10					
Data strobe edge to output data edge	tDQSQb	MAX	1.2				ns	
Mode Register Parameters								
MODE REGISTER WRITE command period (MRW command to MRW command interval)	tMRW	MIN	10				tCK(avg)	
MODE REGISTER SET command delay (MRW command to non-MRW command interval)	tMRD	MIN	MAX (14nx, 10nCK)				ns	
MODE REGISTER READ command period	tMRR	MIN	4				tCK(avg)	
Additional time after tXP has expired until MRR command may be issued	tMRRI	MIN	tRCD (MIN)				ns	
Core Parameters[17]								
READ latency	RL	MIN	10	12	14	16	tCK(avg)	
WRITE latency (set A)	WL	MIN	6	6	8	8	tCK(avg)	
WRITE latency (set B)	WL	MIN	8	9	11	13	tCK(avg)	
ACTIVATE-to- ACTIVATE command period	tRC	MIN	tRAS + tRPab (with all-bank precharge) tRAS + tRPpb (with per-bank precharge)				ns	
CKE minimum pulse width during SELF REFRESH (low pulse width during SELF REFRESH)	tCKESR	MIN	MAX (15ns, 3nCK)				ns	
SELF REFRESH exit to next valid command delay	tXSR	MIN	MAX (tRFCab + 10ns, 2nCK)				ns	
Exit power-down to next valid command delay	tXP	MIN	MAX (7.5ns, 2nCK)				ns	
CAS-to-CAS delay	tCCD	MIN	4				tCK(avg)	
Internal READ to PRECHARGE command delay	tRTP	MIN	MAX (7.5ns, 4nCK)				ns	
RAS-to-CAS delay	tRCD	MIN	MAX (18ns, 3nCK)				ns	

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Table 101: AC Timing (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter	Symbol	Min/Max	Data Rate				Unit	Notes
			1333	1600	1866	2133		
Row precharge time (single bank)	tRPpb	MIN	MAX (18ns, 3nCK)				ns	
Row precharge time (all banks)	tRPpab	MIN	MAX (21ns, 3nCK)				ns	
Row active time	tRAS	MIN	MAX (42ns, 3nCK)				ns	
		MAX	70				µs	
WRITE recovery time	tWR	MIN	MAX (15ns, 3nCK)				ns	
Internal WRITE-to- READ command delay	tWTR	MIN	MAX (7.5ns, 4nCK)				ns	
Active bank A to active bank B	tRRD	MIN	MAX (10ns, 2nCK)				ns	
Four-bank ACTIVATE window	tFAW	MIN	MAX (50ns, 8nCK)				ns	
Minimum deep power-down time	tDPD	MIN	500				µs	
ODT Parameters								
Asynchronous R_{TT} turn-on delay from ODT input	tODTon	MIN	1.75				ns	
		MAX	3.5					
Asynchronous R_{TT} turn-off delay from ODT input	tODToff	MIN	1.75				ns	
		MAX	3.5					
Automatic R_{TT} turn-on delay after READ data	tAODTon	MAX	tDQSCK + 1.4 × tDQSQmax + tCK(avg,min)				ps	
Automatic R_{TT} turn-off delay after READ data	tAODToff	MIN	tDQSCKmin - 300				ps	
R_{TT} disable delay from power-down, self refresh, and deep power-down entry	tODTd	MAX	12				ns	
R_{TT} enable delay from power-down and self refresh exit	tODTe	MAX	12				ns	
CA Training Parameters								
First CA calibration command following CA training entry	tCAMRD	MIN	20				tCK(avg)	
First CA calibration command following CKE LOW	tCAENT	MIN	10				tCK(avg)	
CA calibration exit command following CKE HIGH	tCAEXT	MIN	10				tCK(avg)	
CKE LOW following CA calibration mode entry	tCACKEL	MIN	10				tCK(avg)	
CKE HIGH following last CA calibration results	tCACKEH	MIN	10				tCK(avg)	

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Table 101: AC Timing (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter	Symbol	Min/Max	Data Rate				Unit	Notes
			1333	1600	1866	2133		
Data out delay after CA training calibration command entry	tADR	MAX	20				ns	
MRW CA exit command to DQ tri-state	tMRZ	MIN	3				ns	
CA calibration command to CA calibration command delay	tCACD	MIN	RU(tADR/tCK) + 2				tCK(avg)	
Write Leveling Parameters								
DQS delay after write leveling mode is programmed	tWLDQSEN	MIN	25				ns	
		MAX	–					
First DQS edge after write leveling mode is programmed	tWLMRD	MIN	40				ns	
		MAX	–					
Write leveling output delay	tWLO	MIN	0				ns	
		MAX	20					
Write leveling hold time	tWLH	MIN	205	175	150	135	ps	
Write leveling setup time	tWLS	MIN	205	175	150	135	ps	
Temperature Derating Parameters								
DQS output access time from CK (derated)	tDQSCK	MAX	5620				ps	
RAS-to-CAS delay (derated)	tRCD	MIN	tRCD + 1.875				ns	
ACTIVATE-to- ACTIVATE command period (derated)	tRC	MIN	tRC + 1.875				ns	
Row active time (derated)	tRAS	MIN	tRAS + 1.875				ns	
Row precharge time (derated)	tRP	MIN	tRP + 1.875				ns	
Active bank A to active bank B (derated)	tRRD	MIN	tRRD + 1.875				ns	

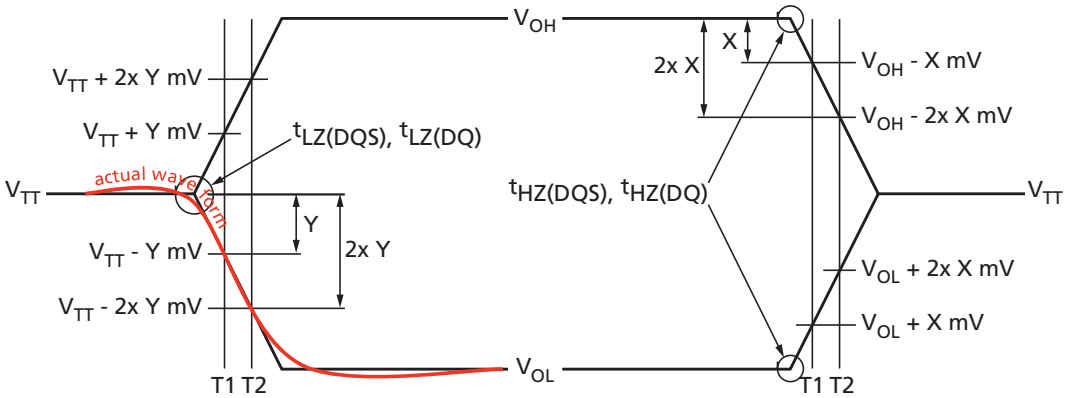
Notes:
1. Frequency values are for reference only. Clock cycle time (tCK) is used to determine device capabilities.
2. All AC timings assume an input slew rate of 2 V/ns.
3. Measured with 4 V/ns differential CK_t/CK_c slew rate and nominal VIX.
4. READ, WRITE, and input setup and hold values are referenced to V_{REF}.
5. tDQSCKDS is the absolute value of the difference between any two tDQSCK measurements (in a byte lane) within a contiguous sequence of bursts in a 160ns rolling window. tDQSCKDS is not tested and is guaranteed by design. Temperature drift in the system is <10°C/s. Values do not include clock jitter.
6. tDQSCKDM is the absolute value of the difference between any two tDQSCK measurements (in a byte lane) within a 1.6µs rolling window. tDQSCKDM is not tested and is

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guaranteed by design. Temperature drift in the system is <10°C/s. Values do not include clock jitter.

7. tDQSCKDL is the absolute value of the difference between any two tDQSCK measurements (in a byte lane) within a 32ms rolling window. tDQSCKDL is not tested and is guaranteed by design. Temperature drift in the system is <10°C/s. Values do not include clock jitter.
8. For LOW-to-HIGH and HIGH-to-LOW transitions, the timing reference is at the point when the signal crosses the transition threshold (V_{TT}). tHZ and tLZ transitions occur in the same access time (with respect to clock) as valid data transitions. These parameters are not referenced to a specific voltage level but to the time when the device output is no longer driving (for tRPST, tHZ(DQS) and tHZ(DQ)), or begins driving (for tRPRE, tLZ(DQS) and tLZ(DQ)). The figure below shows a method to calculate the point when the device is no longer driving tHZ(DQS) and tHZ(DQ) or begins driving tLZ(DQS) and tLZ(DQ) by measuring the signal at two different voltages. The actual voltage measurement points are not critical as long as the calculation is consistent. The parameters tLZ(DQS), tLZ(DQ), tHZ(DQS), and tHZ(DQ) are defined as single-ended. The timing parameters tRPRE and tRPST are determined from the differential signal DQS.

Output Transition Timing



9. Measured from the point when DQS begins driving the signal, to the point when DQS begins driving the first rising strobe edge.
10. Measured from the last falling strobe edge of DQS to the point when DQS finishes driving the signal.
11. CKE input setup time is measured from CKE reaching a HIGH/LOW voltage level to CK crossing.
12. CKE input hold time is measured from CK crossing to CKE reaching a HIGH/LOW voltage level.
13. Input setup/hold time for signal (CA[9:0], CS_n).
14. To ensure device operation before the device is configured, a number of AC boot timing parameters are defined in this table. Boot parameter symbols have the letter b appended (for example, tCK during boot is tCKb).
15. Mobile LPDDR3 devices set some mode register default values upon receiving a RESET (MRW) command, as specified in Mode Register Definition.
16. The output skew parameters are measured with default output impedance settings using the reference load.
17. The minimum tCK column applies only when tCK is greater than 6ns.

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CA and CS_n Setup, Hold, and Derating

For all input signals (CA and CS_n), the total required setup time (^{t}IS) and hold time (^{t}IH) is calculated by adding the data sheet ^{t}IS (base) and ^{t}IH (base) values to the Δ^{t}IS and Δ^{t}IH derating values, respectively. Example: ^{t}IS (total setup time) = ^{t}IS(base) + Δ^{t}IS. (See the series of tables following this section.)

The typical setup slew rate (^{t}IS) for a rising signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IH(AC)min}$. The typical setup slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IL(AC)max}$. If the actual signal is consistently earlier than the typical slew rate line between the shaded $V_{REF(DC)}$-to-(AC) region, use the typical slew rate for the derating value (see the Typical Slew Rate and ^{t}VAC – ^{t}IS for CA and CS_n Relative to Clock figure). If the actual signal is later than the typical slew rate line anywhere between the shaded $V_{REF(DC)}$-to-AC region, the slew rate of a tangent line to the actual signal from the AC level to the DC level is used for the derating value (see the Tangent Line – ^{t}IS for CA and CS_n Relative to Clock figure).

The hold (^{t}IH) typical slew rate for a rising signal is defined as the slew rate between the last crossing of $V_{IL(DC)max}$ and the first crossing of $V_{REF(DC)}$. The hold (^{t}IH) typical slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{IH(DC)min}$ and the first crossing of $V_{REF(DC)}$. If the actual signal is consistently later than the typical slew rate line between the shaded DC-to-$V_{REF(DC)}$ region, use the typical slew rate for the derating value (see the Typical Slew Rate – ^{t}IH for CA and CS_n Relative to Clock figure). If the actual signal is earlier than the typical slew rate line anywhere between the shaded DC-to-$V_{REF(DC)}$ region, the slew rate of a tangent line to the actual signal from the DC level to $V_{REF(DC)}$ level is used for the derating value (see the Tangent Line – ^{t}IH for CA and CS_n Relative to Clock figure).

For a valid transition, the input signal must remain above or below $V_{IH}/V_{IL(AC)}$ for a specified time, ^{t}VAC (see the Required Time for Valid Transition – ^{t}VAC > $V_{IH(AC)}$ and < $V_{IL(AC)}$ table).

For slow slew rates, the total setup time could be a negative value (that is, a valid input signal will not have reached $V_{IH}/V_{IL(AC)}$ at the time of the rising clock transition). A valid input signal is still required to complete the transition and reach $V_{IH}/V_{IL(AC)}$.

For slew rates between the values listed in the Derating Values for AC/DC-Based ^{t}IS/^{t}IH (AC150) table, the derating values are obtained using linear interpolation. Slew rate values are not typically subject to production testing. They are verified by design and characterization.

Table 102: CA Setup and Hold Base Values

Parameter	Data Rate				Reference
	1333	1600	1866	2133	
^{t}ISCA (base)	100	75	–	–	$V_{IH}/V_{IL(AC)} = V_{REF(DC)}$ ±150mV
^{t}ISCA (base)	–	–	62.5	47.5	$V_{IH}/V_{IL(AC)} = V_{REF(DC)}$ ±135mV
^{t}IHCA (base)	125	100	80	65	$V_{IH}/V_{IL(DC)} = V_{REF(DC)}$ ±100mV

Note: 1. AC/DC referenced for 2 V/ns CA slew rate and 4 V/ns differential CK slew rate.

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Table 103: CS_n Setup and Hold Base Values

Parameter	Data Rate				Reference
	1333	1600	1866	2133	
^{t}ISCS (base)	215	195	–	–	$V_{IH}/V_{IL(AC)} = V_{REF(DC)}$ ±150mV
^{t}ISCS (base)	–	–	162.5	137.5	$V_{IH}/V_{IL(AC)} = V_{REF(DC)}$ ±135mV
^{t}IHCS (base)	240	220	180	155	$V_{IH}/V_{IL(DC)} = V_{REF(DC)}$ ±100mV

Note: 1. AC/DC referenced for 2 V/ns CS_n slew rate, and 4 V/ns differential CK slew rate.

Table 104: Derating Values for AC/DC-Based ^{t}IS/^{t}IH (AC150)

Δ^{t}IS, Δ^{t}IH derating in ps

		Δ^{t}IS, Δ^{t}IH Derating in [ps] AC/DC-based AC150 Threshold -> $V_{IH(ac)} = V_{REF(dc)}$+150mV, $V_{IL(ac)} = V_{REF(dc)}$ - 150mV DC100 Threshold -> $V_{IH(dc)} = V_{REF(dc)}$ + 100mV, $V_{IL(dc)} = V_{REF(dc)}$ - 100mV											
		CK_t, CK_c Differential Slew Rate											
		8.0 V/ns		7.0 V/ns		6.0 V/ns		5.0 V/ns		4.0 V/ns		3.0 V/ns	
		Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH
CA, CS_n slew rate V/ns	4.0	38	25	38	25	38	25	38	25	38	25		
	3.0			25	17	25	17	25	17	25	17	38	29
	2.0					0	0	0	0	**0**	**0**	13	13
	1.5							–25	–17	–25	–17	–12	–4

Note: 1. Shaded cells are not supported.

Table 105: Derating Values for AC/DC-Based ^{t}IS/^{t}IH (AC135)

Δ^{t}IS, Δ^{t}IH derating in ps

		Δ^{t}IS, Δ^{t}IH Derating in [ps] AC/DC-based AC135 Threshold -> $V_{IH(ac)} = V_{REF(dc)}$+135mV, $V_{IL(ac)} = V_{REF(dc)}$ - 135mV DC100 Threshold -> $V_{IH(dc)} = V_{REF(dc)}$ + 100mV, $V_{IL(dc)} = V_{REF(dc)}$ - 100mV											
		CK_t, CK_c Differential Slew Rate											
		8.0 V/ns		7.0 V/ns		6.0 V/ns		5.0 V/ns		4.0 V/ns		3.0 V/ns	
		Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH
CA, CS_n slew rate V/ns	4.0	34	25	34	25	34	25	34	25	34	25		
	3.0			23	17	23	17	23	17	23	17	34	29
	2.0					0	0	0	0	**0**	**0**	11	13
	1.5							–23	–17	–23	–17	–12	–4

Note: 1. Shaded cells are not supported.

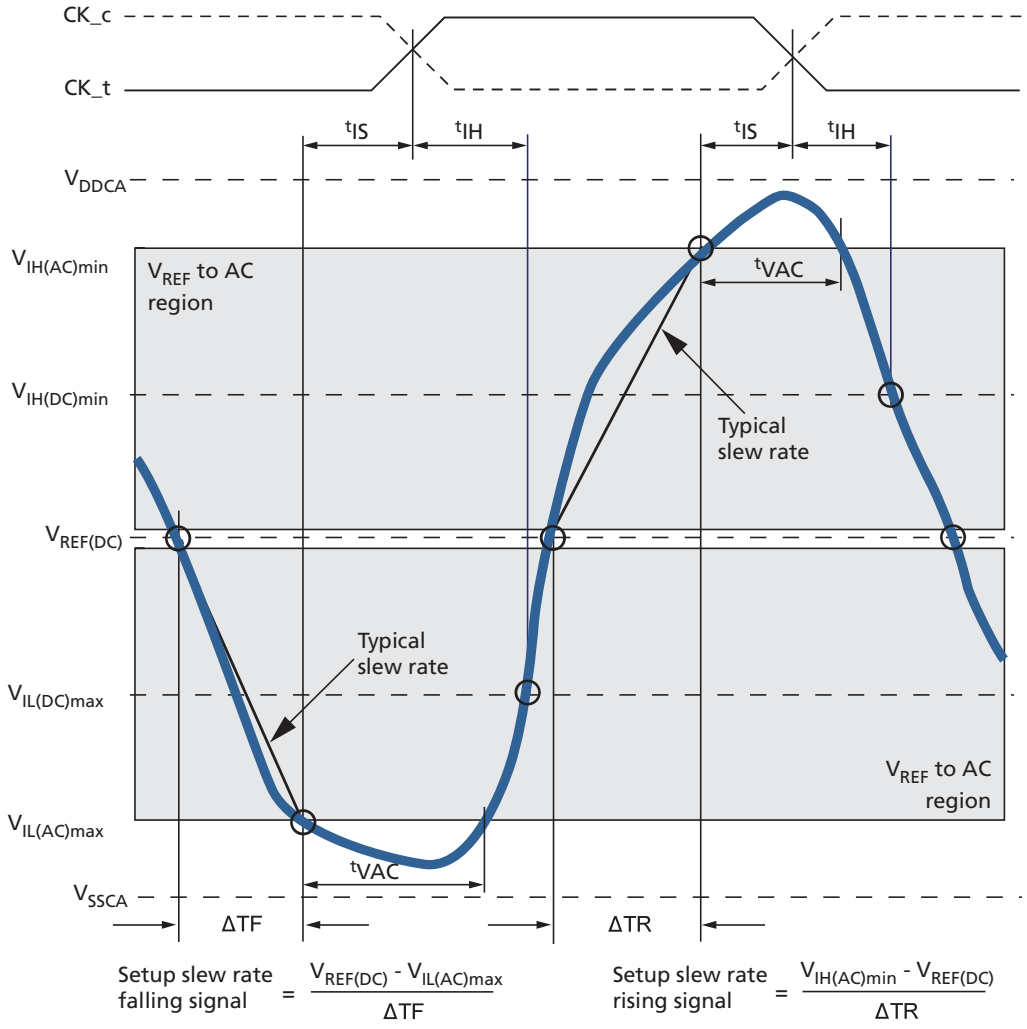
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Table 106: Required Time for Valid Transition – $^{t}VAC > V_{IH(AC)}$ and $< V_{IL(AC)}$

Slew Rate (V/ns)	^{t}VAC at 150mV (ps) 1333 Mb/s		^{t}VAC at 150mV (ps) 1600 Mb/s		^{t}VAC at 135mV (ps) 1866 Mb/s		^{t}VAC at 135mV (ps) 2133 Mb/s	
	Min	Max	Min	Max	Min	Max	Min	Max
>4.0	58	–	48	–	40	–	34	–
4.0	58	–	48	–	40	–	34	–
3.5	56	–	46	–	39	–	33	–
3.0	53	–	43	–	36	–	30	–
2.5	50	–	40	–	33	–	27	–
2.0	45	–	35	–	29	–	23	–
1.5	37	–	27	–	21	–	15	–
<1.5	37	–	27	–	21	–	15	–

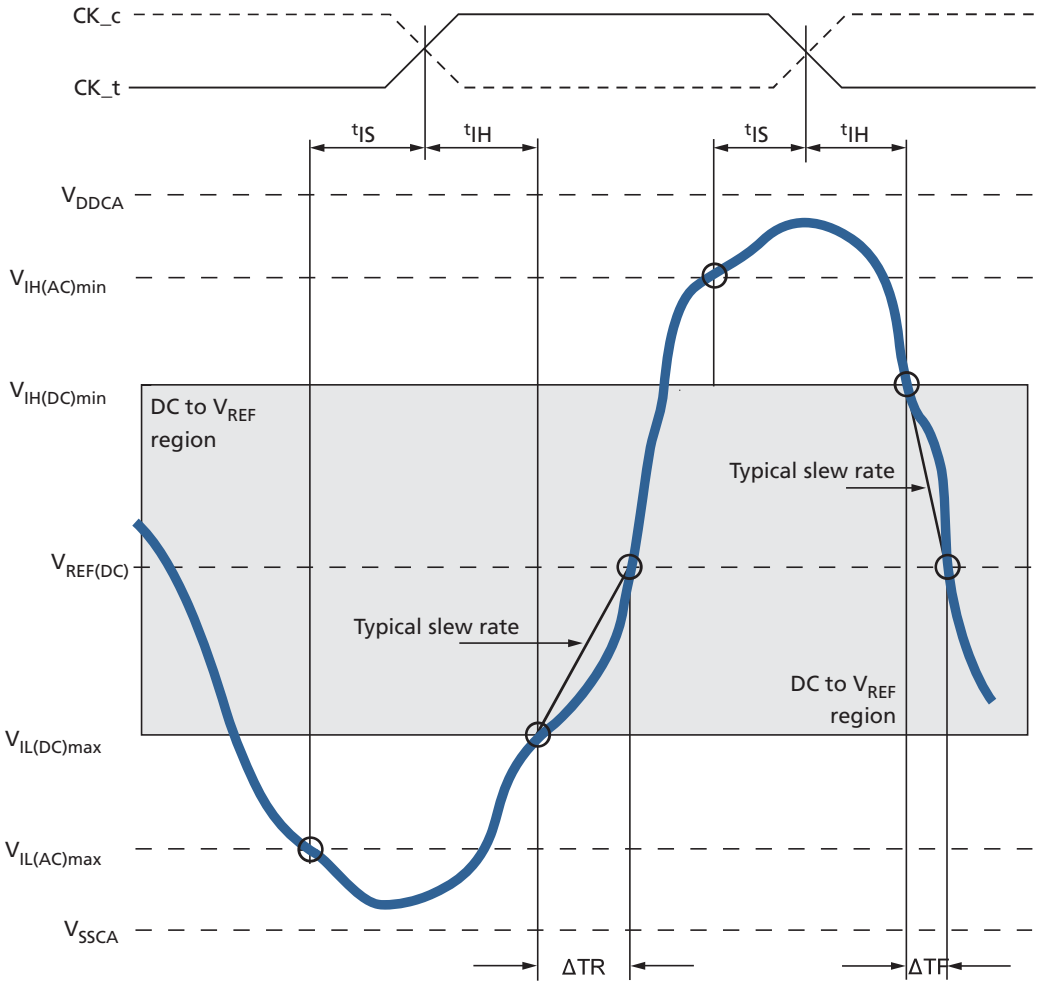
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Figure 84: Typical Slew Rate and ^{t}VAC – ^{t}IS for CA and CS_n Relative to Clock



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Figure 85: Typical Slew Rate – ^{t}IH for CA and CS_n Relative to Clock

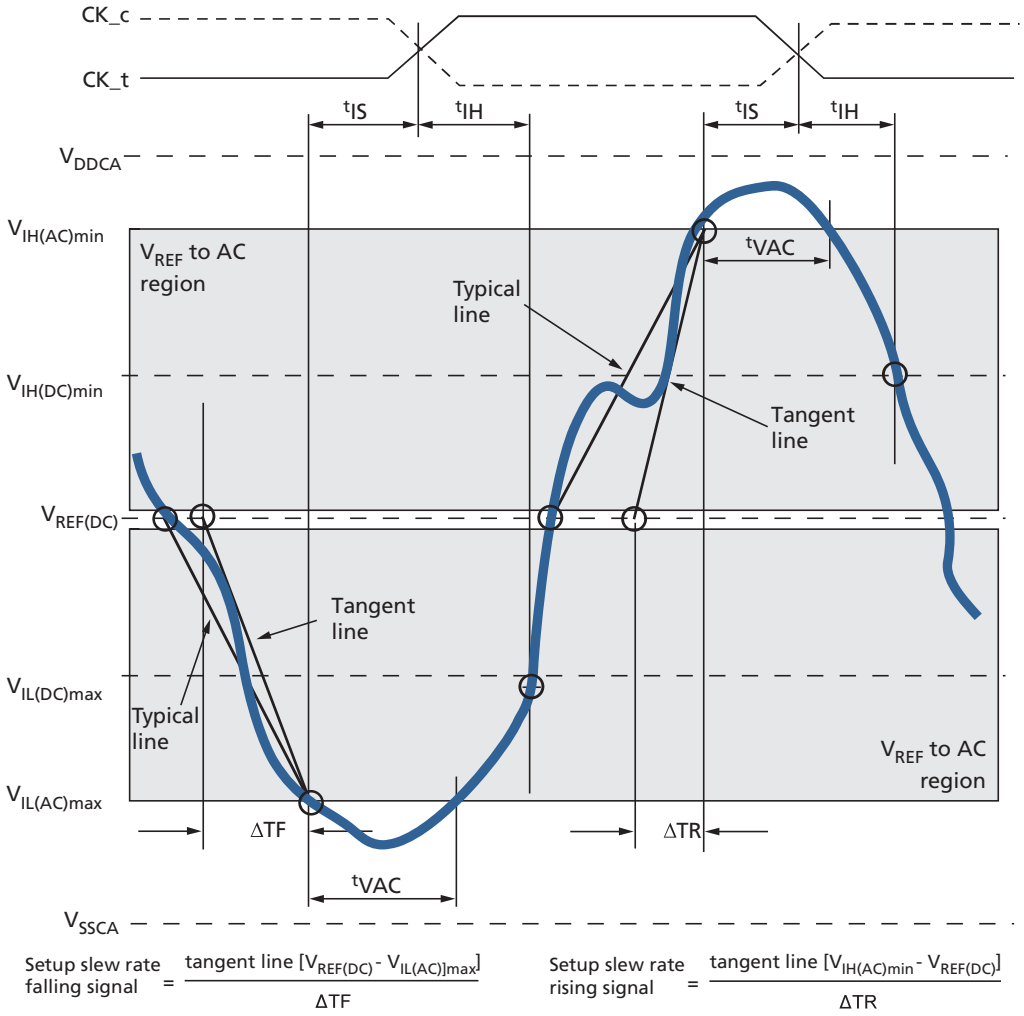


$$\text{Hold slew rate falling signal} = \frac{V_{IH(DC)min} - V_{REF(DC)}}{\Delta TF}$$

$$\text{Hold slew rate rising signal} = \frac{V_{REF(DC)} - V_{IL(DC)max}}{\Delta TR}$$

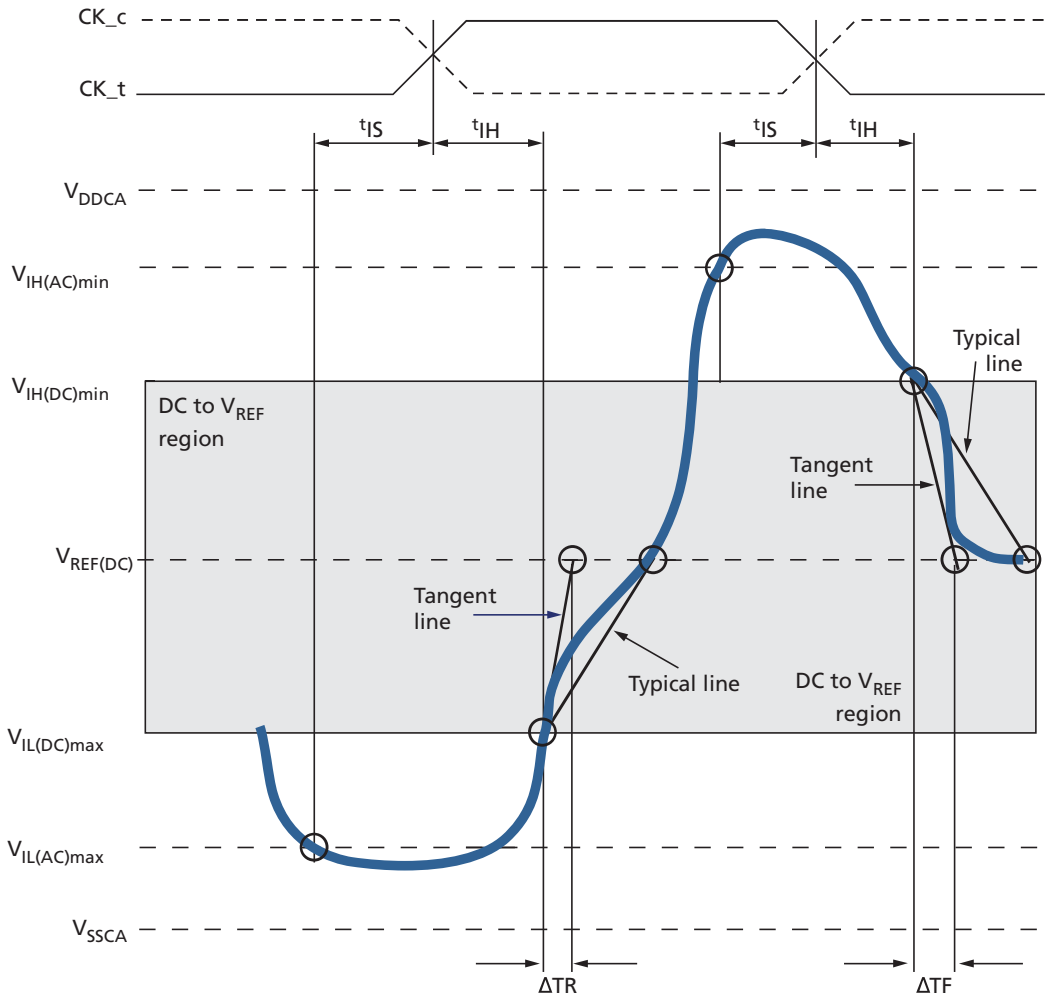
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Figure 86: Tangent Line – ^{t}IS for CA and CS_n Relative to Clock



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Figure 87: Tangent Line – ^{t}IH for CA and CS_n Relative to Clock



$$\text{Hold slew rate falling signal} = \frac{\text{tangent line } [V_{IH(DC)min} - V_{REF(DC)}]}{\Delta TF}$$

$$\text{Hold slew rate rising signal} = \frac{\text{tangent line } [V_{REF(DC)} - V_{IL(DC)max}]}{\Delta TR}$$

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Data Setup, Hold, and Slew Rate Derating

For all input signals (DQ, DM) calculate the total required setup time (^{t}DS) and hold time (^{t}DH) by adding the data sheet ^{t}DS(base) and ^{t}DH(base) values (see the Data Setup and Hold Base Values table) to the Δ^{t}DS and Δ^{t}DH derating values, respectively (see the Derating Values for AC/DC-Based ^{t}DS/^{t}DH (AC150) table). Example: ^{t}DS = ^{t}DS(base) + Δ^{t}DS.

The typical ^{t}DS slew rate for a rising signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IH(AC)min}$. The typical ^{t}DS slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IL(AC)max}$ (see the Typical Slew Rate and ^{t}VAC – ^{t}DS for DQ Relative to Strobe figure).

If the actual signal is consistently earlier than the typical slew rate line in the Typical Slew Rate and ^{t}VAC – ^{t}IS for CA and CS_n Relative to Clock figure in the area shaded gray between the $V_{REF(DC)}$ region and the AC region, use the typical slew rate for the derating value. If the actual signal is later than the typical slew rate line anywhere between the shaded $V_{REF(DC)}$ region and the AC region, the slew rate of a tangent line to the actual signal from the AC level to the DC level is used for the derating value (see the Tangent Line – ^{t}IS for CA and CS_n Relative to Clock figure).

The typical ^{t}DH slew rate for a rising signal is defined as the slew rate between the last crossing of $V_{IL(DC)max}$ and the first crossing of $V_{REF(DC)}$. The typical ^{t}DH slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{IH(DC)min}$ and the first crossing of $V_{REF(DC)}$ (see the Typical Slew Rate – ^{t}DH for DQ Relative to Strobe figure).

If the actual signal is consistently later than the typical slew rate line between the shaded DC-level-to-$V_{REF(DC)}$ region, use the typical slew rate for the derating value. If the actual signal is earlier than the typical slew rate line anywhere between shaded DC-to-$V_{REF(DC)}$ region, the slew rate of a tangent line to the actual signal from the DC level to the $V_{REF(DC)}$ level is used for the derating value (see the Tangent Line – ^{t}DH for DQ with Respect to Strobe figure).

For a valid transition, the input signal must remain above or below $V_{IH}/V_{IL(AC)}$ for the specified time, ^{t}VAC (see the Required Time for Valid Transition – ^{t}VAC > $V_{IH(AC)}$ or < $V_{IL(AC)}$ table).

The total setup time for slow slew rates could be negative (that is, a valid input signal may not have reached $V_{IH}/V_{IL(AC)}$ at the time of the rising clock transition). A valid input signal is still required to complete the transition and reach $V_{IH}/V_{IL(AC)}$.

For slew rates between the values listed in the following table, the derating values can be obtained using linear interpolation. Slew rate values are not typically subject to production testing. They are verified by design and characterization.

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Table 107: Data Setup and Hold Base Values

Parameter	Data Rate				Reference
	1333	1600	1866	2133	
^{t}DS (base)	100	75	–	–	$V_{IH}/V_{IL(AC)} = V_{REF(DC)}$ ±150mV
^{t}DS (base)	–	–	62.5	47.5	$V_{IH}/V_{IL(AC)} = V_{REF(DC)}$ ±135mV
^{t}DH (base)	125	100	80	65	$V_{IH}/V_{IL(DC)} = V_{REF(DC)}$ ±100mV

Note: 1. AC/DC referenced for 2 V/ns DQ, DM slew rate, and 4 V/ns differential DQS slew rate and nominal V_{IX}.

Table 108: Derating Values for AC/DC-Based ^{t}DS/^{t}DH (AC150)

Δ^{t}DS, Δ^{t}DH derating in ps

		Δ^{t}DS, Δ^{t}DH Derating in [ps] AC/DC-based AC150 Threshold -> $V_{IH(ac)} = V_{REF(dc)}$ + 150mV, $V_{IL(ac)} = V_{REF(dc)}$ - 150mV DC100 Threshold -> $V_{IH(dc)} = V_{REF(dc)}$ + 100mV, $V_{IL(dc)} = V_{REF(dc)}$ - 100mV											
		DQS_t, DQS_c Differential Slew Rate											
		8.0 V/ns		7.0 V/ns		6.0 V/ns		5.0 V/ns		4.0 V/ns		3.0 V/ns	
		Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH
DQ, DM slew rate V/ns	4.0	38	25	38	25	38	25	38	25	38	25		
	3.0			25	17	25	17	25	17	25	17	38	29
	2.0					0	0	0	0	**0**	**0**	13	13
	1.5							–25	–17	–25	–17	–12	–4

Note: 1. Shaded cells are not supported.

Table 109: Derating Values for AC/DC-Based ^{t}DS/^{t}DH (AC135)

Δ^{t}DS, Δ^{t}DH derating in ps

		Δ^{t}DS, Δ^{t}DH Derating in [ps] AC/DC-based AC135 Threshold -> $V_{IH(ac)} = V_{REF(dc)}$ + 135mV, $V_{IL(ac)} = V_{REF(dc)}$ - 135mV DC100 Threshold -> $V_{IH(dc)} = V_{REF(dc)}$ + 100mV, $V_{IL(dc)} = V_{REF(dc)}$ - 100mV											
		DQS_t, DQS_c Differential Slew Rate											
		8.0 V/ns		7.0 V/ns		6.0 V/ns		5.0 V/ns		4.0 V/ns		3.0 V/ns	
		Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH	Δ^{t}IS	Δ^{t}IH
DQ, DM slew rate V/ns	4.0	34	25	34	25	34	25	34	25	34	25		
	3.0			23	17	23	17	23	17	23	17	34	29
	2.0					0	0	0	0	**0**	**0**	11	13
	1.5							–23	–17	–23	–17	–12	–4

Note: 1. Shaded cells are not supported.

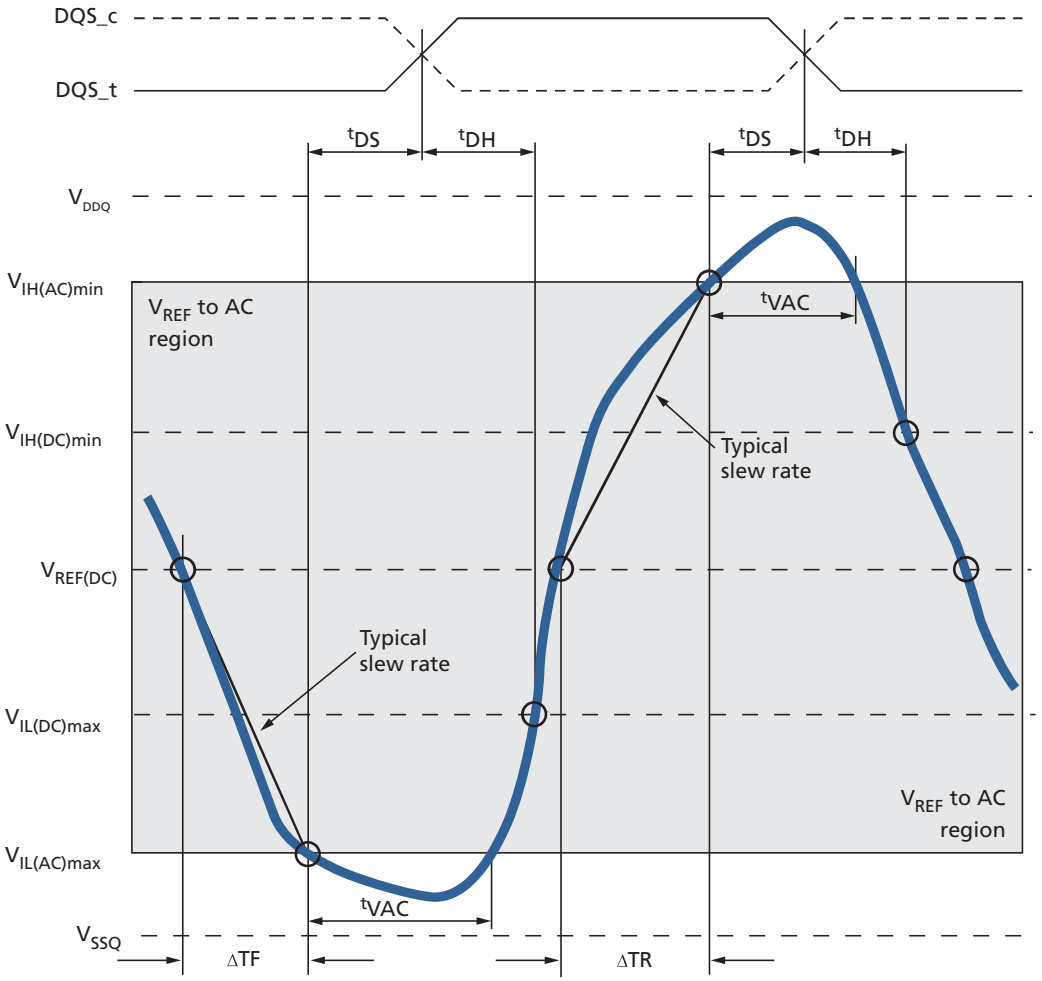
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Table 110: Required Time for Valid Transition – $^{t}VAC > V_{IH(AC)}$ or $< V_{IL(AC)}$

Slew Rate (V/ns)	^{t}VAC at 150mV (ps) 1333 Mb/s		^{t}VAC at 150mV (ps) 1600 Mb/s		^{t}VAC at 135mV (ps) 1866 Mb/s		^{t}VAC at 135mV (ps) 2133 Mb/s	
	Min	Max	Min	Max	Min	Max	Min	Max
>4.0	58	–	48	–	40	–	34	–
4.0	58	–	48	–	40	–	34	–
3.5	56	–	46	–	39	–	33	–
3.0	53	–	43	–	36	–	30	–
2.5	50	–	40	–	33	–	27	–
2.0	45	–	35	–	29	–	23	–
1.5	37	–	27	–	21	–	15	–
<1.5	37	–	27	–	21	–	15	–

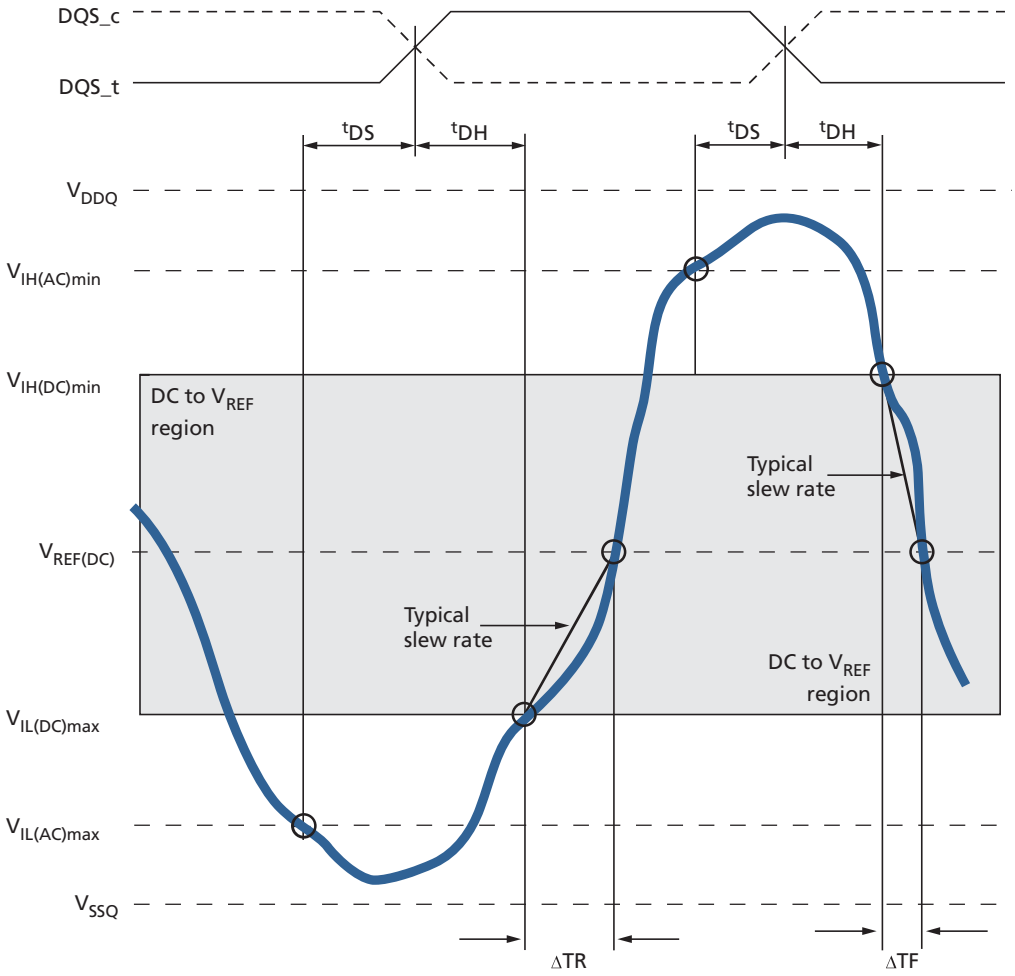
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Figure 88: Typical Slew Rate and ^{t}VAC – ^{t}DS for DQ Relative to Strobe



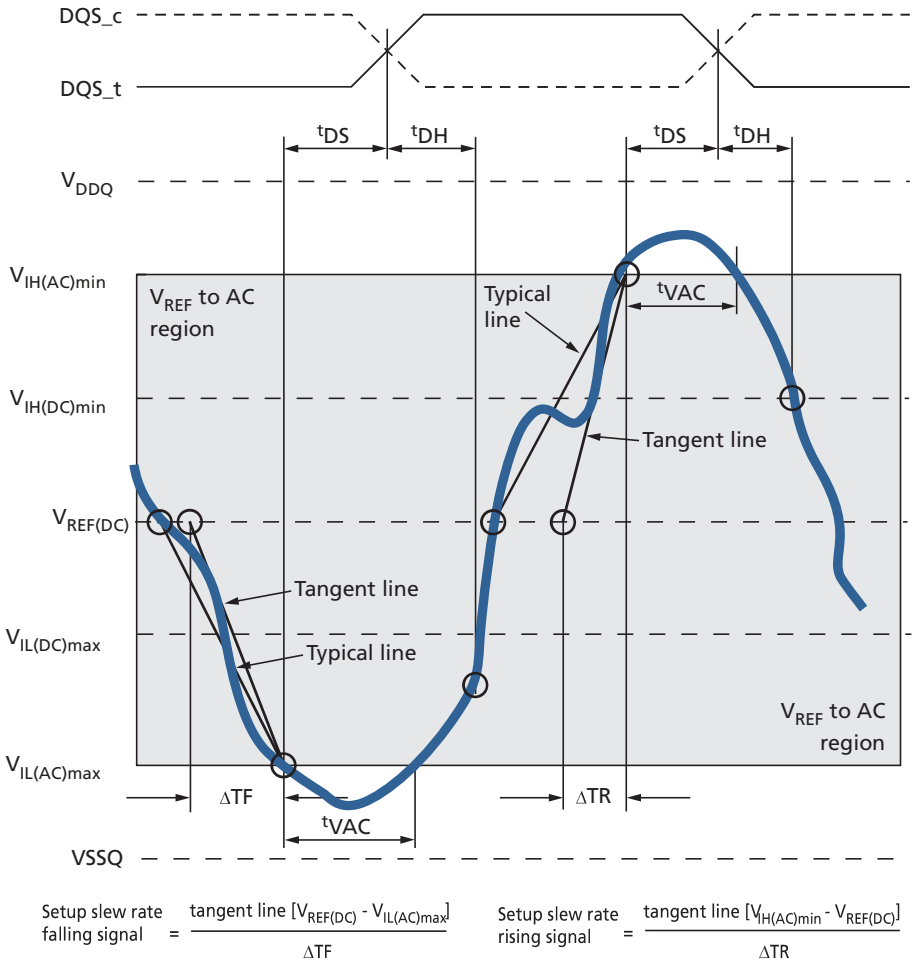
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Figure 89: Typical Slew Rate – ^{t}DH for DQ Relative to Strobe



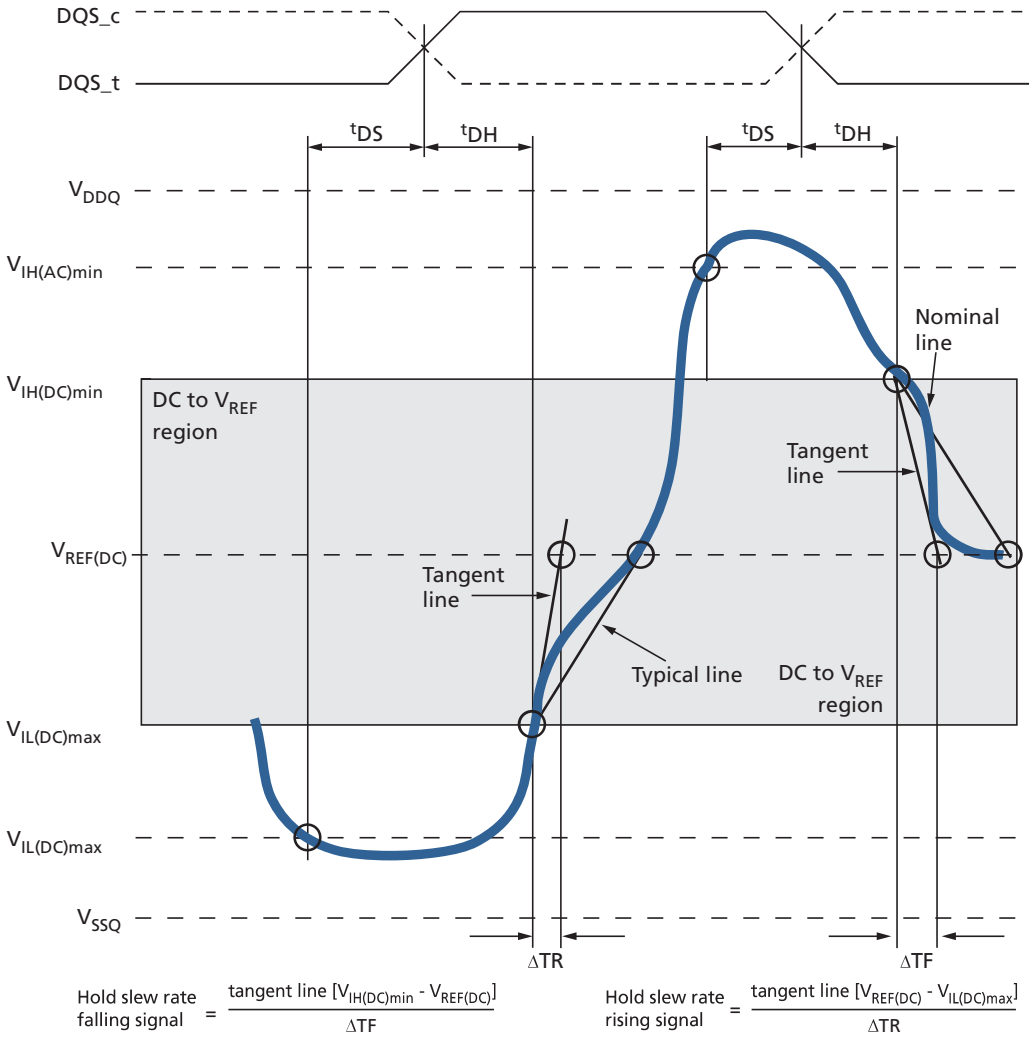
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Figure 90: Tangent Line – ^{t}DS for DQ with Respect to Strobe



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Figure 91: Tangent Line – ^{t}DH for DQ with Respect to Strobe



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Revision History

Rev. A – 10/15

- Initial release to support product options not supported int he Mobile datasheet. It is based on starting document 216b_12x12_2ch_8-16gb_2e0f_mobile-lpddr3.pdf – Rev. B 10/14 EN

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This data sheet contains initial characterization limits that are subject to change upon full characterization of production devices.

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